
DDR Setup Assistant

User's Guide

Notices

© Keysight Technologies 2013-2014, 2017, 2022

No part of this manual may be reproduced in any form or by any means (including electronic storage and retrieval or translation into a foreign language) without prior agreement and written consent from Keysight Technologies as governed by United States and international copyright laws.

Edition

November 2022

Available in electronic format only

Keysight Technologies
1900 Garden of the Gods Road
Colorado Springs, CO 80907 USA

Warranty

THE MATERIAL CONTAINED IN THIS DOCUMENT IS PROVIDED "AS IS," AND IS SUBJECT TO BEING CHANGED, WITHOUT NOTICE, IN FUTURE EDITIONS. FURTHER, TO THE MAXIMUM EXTENT PERMITTED BY APPLICABLE LAW, KEYSIGHT DISCLAIMS ALL WARRANTIES, EITHER EXPRESS OR IMPLIED WITH REGARD TO THIS MANUAL AND ANY INFORMATION CONTAINED HEREIN, INCLUDING BUT NOT LIMITED TO THE IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE. KEYSIGHT SHALL NOT BE LIABLE FOR ERRORS OR FOR INCIDENTAL OR CONSEQUENTIAL DAMAGES IN CONNECTION WITH THE FURNISHING, USE, OR PERFORMANCE OF THIS DOCUMENT OR ANY INFORMATION CONTAINED HEREIN. SHOULD KEYSIGHT AND THE USER HAVE A SEPARATE WRITTEN AGREEMENT WITH WARRANTY TERMS COVERING THE MATERIAL IN THIS DOCUMENT THAT CONFLICT WITH THESE TERMS, THE WARRANTY TERMS IN THE SEPARATE AGREEMENT WILL CONTROL.

Technology Licenses

The hardware and/or software described in this document are furnished under a license and may be used or copied only in accordance with the terms of such license.

Restricted Rights Legend

If software is for use in the performance of a U.S. Government prime contract or subcontract, Software is delivered and licensed as "Commercial computer software" as defined in DFAR 252.227-7014 (June 1995), or as a "commercial item" as defined in FAR 2.101(a) or as "Restricted computer software" as defined in FAR 52.227-19 (June 1987) or any equivalent agency regulation or contract clause. Use, duplication or disclosure of Software is subject to Keysight Technologies' standard commercial license terms, and non-DOD Departments and Agencies of the U.S. Government will receive no greater than Restricted Rights as defined in FAR 52.227-19(c)(1-2) (June 1987). U.S. Government users will receive no greater than Limited Rights as defined in FAR

52.227-14 (June 1987) or DFAR 252.227-7015 (b)(2) (November 1995), as applicable in any technical data.

Safety Notices

CAUTION

A CAUTION notice denotes a hazard. It calls attention to an operating procedure, practice, or the like that, if not correctly performed or adhered to, could result in damage to the product or loss of important data. Do not proceed beyond a CAUTION notice until the indicated conditions are fully understood and met.

WARNING

A WARNING notice denotes a hazard. It calls attention to an operating procedure, practice, or the like that, if not correctly performed or adhered to, could result in personal injury or death. Do not proceed beyond a WARNING notice until the indicated conditions are fully understood and met.

Safety Summary

The following general safety precautions must be observed during all phases of operation of this instrument. Failure to comply with these precautions or with specific warnings or operating instructions in the product manuals violates safety standards of design, manufacture, and intended use of the instrument. Keysight Technologies assumes no liability for the customer's failure to comply with these requirements. Product manuals are provided with your instrument on CD-ROM and/or in printed form. Printed manuals are an option for many products. Manuals may also be available on the Web. Go to www.keysight.com and type in your product number in the Search field at the top of the page.

General	Do not use this product in any manner not specified by the manufacturer. The protective features of this product may be impaired if it is used in a manner not specified in the operation instructions.
Before Applying Power	Verify that all safety precautions are taken. Make all connections to the unit before applying power. Note the instrument's external markings described in "Safety Symbols".
Ground the Instrument	If your product is provided with a grounding type power plug, the instrument chassis and cover must be connected to an electrical ground to minimize shock hazard. The ground pin must be firmly connected to an electrical ground (safety ground) terminal at the power outlet. Any interruption of the protective (grounding) conductor or disconnection of the protective earth terminal will cause a potential shock hazard that could result in personal injury.
Fuses	See the user's guide or operator's manual for information about line-fuse replacement. Some instruments contain an internal fuse, which is not user accessible.
Do Not Operate in an Explosive Atmosphere	Do not operate the instrument in the presence of flammable gases or fumes.
Do Not Remove the Instrument Cover	Only qualified, service-trained personnel who are aware of the hazards involved should remove instrument covers. Always disconnect the power cable and any external circuits before removing the instrument cover.
Cleaning	Clean the outside of the instrument with a soft, lint-free, slightly dampened cloth. Do not use detergent or chemical solvents.
Do Not Modify the Instrument	Do not install substitute parts or perform any unauthorized modification to the product. Return the product to an Keysight Sales and Service Office for service and repair to ensure that safety features are maintained.
In Case of Damage	Instruments that appear damaged or defective should be made inoperative and secured against unintended operation until they can be repaired by qualified service personnel.

CAUTION















A CAUTION notice denotes a hazard. It calls attention to an operating procedure, practice, or the like that, if not correctly performed or adhered to, could result in damage to the product or loss of important data. Do not proceed beyond a CAUTION notice until the indicated conditions are fully understood and met.

WARNING

A WARNING notice denotes a hazard. It calls attention to an operating procedure, practice, or the like that, if not correctly performed or adhered to, could result in personal injury or death. Do not proceed beyond a WARNING notice until the indicated conditions are fully understood and met.

Safety Symbols




Table 1 Safety Symbol

Symbol	Description
	Direct current
	Alternating current
	Both direct and alternating current
	Three phase alternating current
	Three phase alternating current
	Earth ground terminal
	Protective earth ground terminal
	Frame or chassis ground terminal
	Terminal is at earth potential
	Equipotentiality
N	Neutral conductor on permanently installed equipment
L	Line conductor on permanently installed equipment
	On (mains supply)
	Off (mains supply)
	Standby (mains supply). The instrument is not completely disconnected from the mains supply when the power switch is in the standby position
	In position of a bi-stable push switch

Symbol	Description
	Out position of a bi-stable push switch
	Equipment protected throughout by DOUBLE INSULATION or REINFORCED INSULATION
	Caution, refer to accompanying documentation
	Caution, risk of electric shock
	Do not apply around or remove from HAZARDOUS LIVE conductors
	Application around and removal from HAZARDOUS LIVE conductors is permitted
	Caution, hot surface
	Ionizing radiation
CAT I	IEC Measurement Category I
CAT II	Measurement Category II
CAT III	Measurement Category III
CAT IV	Measurement Category IV

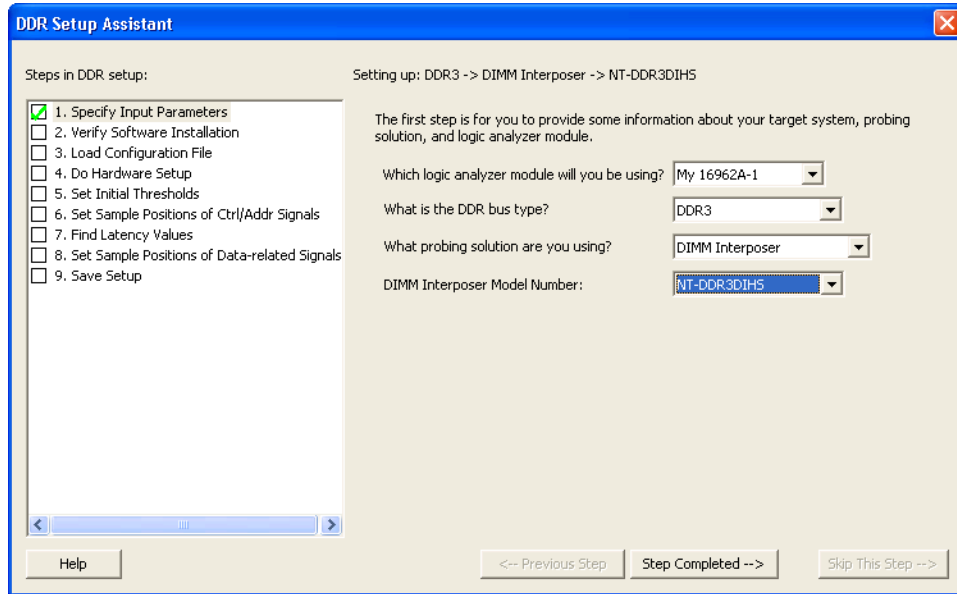
Compliance and Environmental Information

Table 2 Compliance and Environmental Information

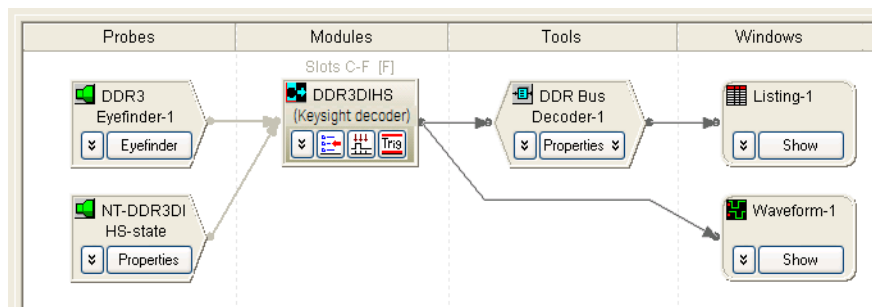
Safety Symbol	Description
	CSA is the Canadian certification mark to demonstrate compliance with the Safety requirements.
	The C-tick mark is a registered trademark of the Spectrum Management Agency of Australia. This signifies compliance with the Australia EMC Framework regulations under the terms of the Radio Communication Act of 1992.
	CE compliance marking to the EU Safety and EMC Directives. ISM GRP-1A classification according to the international EMC standard. ICES/NMB-001 compliance marking to the Canadian EMC standard.

DDR Setup Assistant—At a Glance

The DDR Setup Assistant is a wizard-like application that helps you set up your logic analyzer properly for DDR/LPDDR data capture and analysis.



Once you have completed the set up steps using the DDR Setup Assistant, the *Keysight Logic and Protocol Analyzer* application will have the appropriate Probes, Modules, Tools, and Windows set up, similar to those shown in the example Overview tab below.



Typically, the resulting Overview tab will contain:

- DDR3 Eyefinder – used to set up the appropriate sample positions for capturing DDR data.
- General purpose probe tool – shows how to connect the probe to logic analyzer pods.
- Four-card logic analyzer module (16962A or 16960A) or U4154A/B Logic Analyzer module.
- DDR Bus Decoder – decodes the captured data.
- Listing window – to display decoded data.
- Optional Waveform window – to display state or timing waveforms.
- It is best to add Waveform windows immediately after the logic analyzer module because, when displaying large amounts of waveform data, decoding can slow down the waveform display.

See Also ["In This Guide"](#) on page 8

In This Guide

For an overview and list of features, see: ["DDR Setup Assistant—At a Glance"](#) on page 7

First, this guide describes the options for probing DDR devices and the logic analysis system hardware and software required before you can use the DDR Setup Assistant.

- ["Options for Probing DDR Devices"](#) on page 13
- ["Before Using the DDR Setup Assistant"](#) on page 33

Next, this guide provides more in-depth information about the steps taken when using the DDR Setup Assistant:

To use the automated test application, see:

- ["Step - Specify Input Parameters"](#) on page 39
- ["Step - Verify Software Installation"](#) on page 40
- ["Step - Load Configuration File"](#) on page 42
- ["Step - Do Hardware Setup"](#) on page 45
- ["Step - Set Initial Thresholds"](#) on page 48
- ["Step - Set Sample Positions of Clk/CS Signals \(only applicable to U4154A/B Logic Analyzer\)"](#) on page 49
- ["Step - Set Sample Positions of Command/Addr Signals \(only applicable to U4154A/B Logic Analyzer\)"](#) on page 51
- ["Step - Set Sample Positions of Ctrl/Addr Signals \(not applicable to U4154A/B Logic Analyzer\)"](#) on page 53
- ["Step - Find Latency Values"](#) on page 55
- ["Step - Set Sample Positions of Data-related Signals \(not applicable to U4154A/B logic analyzer\)"](#) on page 66
- ["Step - Set Sample Positions of Data Read/Write \(only applicable to U4154A/B Logic Analyzer\)"](#) on page 67
- ["Step - Save Setup"](#) on page 70
- ["Setup Complete"](#) on page 71

Then, there is more in-depth information on using the logic analyzer's automated Thresholds and Sample Positions set up (also known as normal logic analyzer *eye finder*), using DDR3 Eyefinder, and validating DDR setups once you have completed the sampling position set up.

- ["Setting Up Thresholds and Sample Positions on DDR Address/Control Signals"](#) on page 73
- ["Using DDR3 Eyefinder"](#) on page 85
- ["Using Eyescan \(for U4154A/B Logic Analyzer Module\)"](#) on page 115
- ["Validating the DDR Setup"](#) on page 117

Finally, this guide introduces you to the other tools used for capturing and analyzing data from DDR systems and provides pointers to additional documentation.

- ["Capturing Data \(Triggering\)"](#) on page 119
- ["Decoding Captured Data"](#) on page 123

For a printable version of this online help, see: [🔗 "DDR Setup Assistant Online Help"](#).

See Also

- DDR probe manuals.
- DDR Bus Decoder Online Help
- DDR Compliance Tool online help.

Contents

Safety Summary	3
Compliance and Environmental Information	6
DDR Setup Assistant—At a Glance	7
In This Guide	8

1 Options for Probing DDR Devices

DDR4 BGA Probes	14
W4631A DDR4 x16 BGA Interposer	14
W4633A DDR4 x4/x8 BGA Interposer	15
W4636A DDR4 x16 KOV BGA 2-Wings Command and Reduced Data Interposer	15
W4641A DDR4 x16 BGA 2-Wings Interposer	16
W4643A DDR4 x4/x8 BGA 2-Wings Interposer	16
DDR3 DIMM Interposers	17
FS2352 1867 DDR3 DIMM Probe from FuturePlus	18
Nexus DDR3 DIMM Interposer	19
N4835A (FS2351) DDR3 DIMM Interposer (Discontinued)	20
N4821B (FS2350) DDR3 DIMM Interposer (Discontinued)	21
DDR3 SODIMM Interposers	22
FS2354 DDR3 SODIMM Interposer	22
Nexus DDR3 SODIMM Interposer	23
DDR3 BGA Probes	24
W3633A DDR3 BGA x8 Probe	24
W3631A DDR3 BGA x16 Probe	25
DDR3 Midbus Probes	26
N4834A DDR3 Midbus Probe (Discontinued)	26
DDR2 BGA Probes	27
W2633A/B, W2634A DDR2 BGA x8 Probe	27
W2631A/B, W2632A DDR2 BGA x16 Probe	27
LPDDR4 BGA Probes	29
W6601A LPDDR4 BGA Interposer, 200-ball, 2-wings	29
W6602A LPDDR4 RC BGA Interposer, 200-ball, Rigid	29
LPDDR3 BGA Probes	30
W3301A LPDDR3 BGA Interposers	30

- LPDDR BGA Probes** 31
 - W2638A LPDDR BGA x32 Probe 31
 - W2637A LPDDR BGA x16 Probe 31
- Custom Midbus Probing** 32
 - Soft Touch / Soft Touch Pro Embedded Custom Midbus Probing 32

2 Before Using the DDR Setup Assistant

- Installing Required and Optional Software** 34
- Tuning Your DDR DUT to Make the Best Measurements** 35
- Setting Up Read and Write Traffic in the DUT** 36

3 Using the DDR Setup Assistant

- Starting the DDR Setup Assistant** 38
- Step - Specify Input Parameters** 39
- Step - Verify Software Installation** 40
- Step - Load Configuration File** 42
- Step - Do Hardware Setup** 45
- Step - Set Initial Thresholds** 48
- Step - Set Sample Positions of Clk/CS Signals (only applicable to U4154A/B Logic Analyzer)** 49
- Step - Set Sample Positions of Command/Addr Signals (only applicable to U4154A/B Logic Analyzer)** 51
- Step - Set Sample Positions of Ctrl/Addr Signals (not applicable to U4154A/B Logic Analyzer)** 53
 - If there are problems with finding Ctrl/Addr sample positions 54
- Step - Find Latency Values** 55
 - Taking a Mode Register Settings (MRS) Trace 56
 - Setting Latency Values in DDR Bus Decoder 59
 - Setting Latency Values in DDR3 Eyefinder 61
 - Setting Latency Values in Eyescan 62
- Step - Set Sample Positions of Data-related Signals (not applicable to U4154A/B logic analyzer)** 66
- Step - Set Sample Positions of Data Read/Write (only applicable to U4154A/B Logic Analyzer)** 67
 - To find and set sample positions for DDR4 Data related signals 68
- Step - Save Setup** 70

Setup Complete	71
4 Setting Up Thresholds and Sample Positions on DDR Address/Control Signals	
Setting Up Thresholds and Sample Positions	74
Solving Problems with Thresholds and Sample Positions Set Up	78
Clock edges "too close together" error message on Run	78
Determining Correct Sample Position on Eyes that are Closing	80
Determining Read and Write latencies using Timing Zoom	82
5 Using DDR3 Eyefinder	
Getting Started with DDR3 Eyefinder (for 16962A/16960A)	86
Before Running DDR3 Eyefinder	86
Your First DDR3 Eyefinder Scan (16962A logic analyzers only)	86
Setting Scan Options	97
Setting DDR Bus Specifications	97
Setting Scan Mode	98
Setting Scan Options	99
Performing Scans	103
Setting Sample Positions	104
Adjusting the Display Scale	104
Changing the Time Bucket Scaling and Colors	105
Adjusting the Eye Sensitivity	106
Adjusting Sample Positions	107
Viewing Signal Swing vs. Time	109
Solving DDR3 Eyefinder Problems	110
If scans stick on Runs in DDR3 Eyefinder	110
If there are no transitions in DDR3 Eyefinder	110
If eyes show tri-stating	110
If eyes are closed	111
If there are multiple eyes	112
If eye scan results are noisy	112
6 Using Eyescan (for U4154A/B Logic Analyzer Module)	
7 Validating the DDR Setup	
Validating Data in the Trace	118
8 Capturing Data (Triggering)	
Recalling DDR Favorite Triggers	120

Triggering on Valid Commands	121
Burst Triggering	122
9 Decoding Captured Data	
DDR Bus Decoder	124
A Setting Data Sample Positions with the 1695x Logic Analyzers	
B DDR Glossary	
Index	

1 Options for Probing DDR Devices

There are several different Keysight and third-party options for probing a DDR device under test (DUT).

- DDR4**
 - “DDR4 BGA Probes” on page 14:
 - “W4631A DDR4 x16 BGA Interposer” on page 14
 - “W4633A DDR4 x4/x8 BGA Interposer” on page 15
 - “W4636A DDR4 x16 KOV BGA 2-Wings Command and Reduced Data Interposer” on page 15
 - “W4641A DDR4 x16 BGA 2-Wings Interposer” on page 16
 - “W4643A DDR4 x4/x8 BGA 2-Wings Interposer” on page 16
- DDR3**
 - “DDR3 DIMM Interposers” on page 17
 - “FS2352 1867 DDR3 DIMM Probe from FuturePlus” on page 18
 - “Nexus DDR3 DIMM Interposer” on page 19
 - “N4835A (FS2351) DDR3 DIMM Interposer (Discontinued)” on page 20
 - “N4821B (FS2350) DDR3 DIMM Interposer (Discontinued)” on page 21
 - “DDR3 SODIMM Interposers” on page 22:
 - “FS2354 DDR3 SODIMM Interposer” on page 22
 - “Nexus DDR3 SODIMM Interposer” on page 23
 - “DDR3 BGA Probes” on page 24:
 - “W3633A DDR3 BGA x8 Probe” on page 24
 - “W3631A DDR3 BGA x16 Probe” on page 25
 - “DDR3 Midbus Probes” on page 26:
 - “N4834A DDR3 Midbus Probe (Discontinued)” on page 26
- DDR2**
 - “DDR2 BGA Probes” on page 27:
 - “W2633A/B, W2634A DDR2 BGA x8 Probe” on page 27
 - “W2631A/B, W2632A DDR2 BGA x16 Probe” on page 27
- LPDDR4**
 - “LPDDR4 BGA Probes” on page 29
 - “W6601A LPDDR4 BGA Interposer, 200-ball, 2-wings” on page 29
 - “W6602A LPDDR4 RC BGA Interposer, 200-ball, Rigid” on page 29
- LPDDR3**
 - “W3301A LPDDR3 BGA Interposers” on page 30
- LPDDR**
 - “LPDDR BGA Probes” on page 31:
 - “W2638A LPDDR BGA x32 Probe” on page 31
 - “W2637A LPDDR BGA x16 Probe” on page 31
- Custom**
 - “Custom Midbus Probing” on page 32:
 - “Soft Touch / Soft Touch Pro Embedded Custom Midbus Probing” on page 32

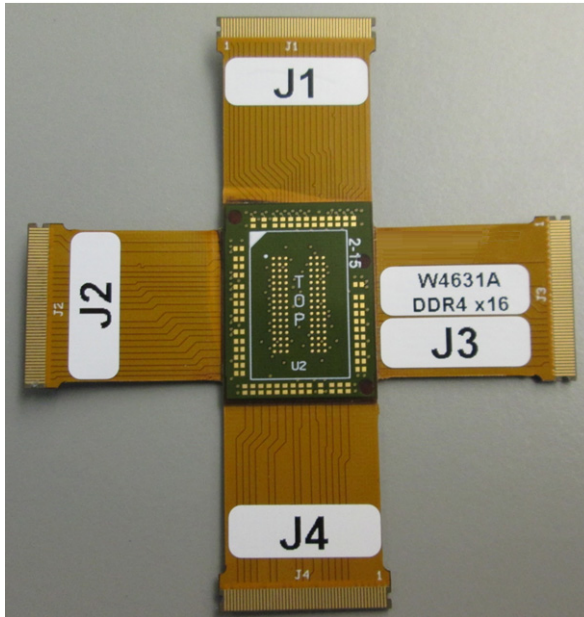
DDR4 BGA Probes

- “W4631A DDR4 x16 BGA Interposer” on page 14
- “W4633A DDR4 x4/x8 BGA Interposer” on page 15
- “W4636A DDR4 x16 KOV BGA 2-Wings Command and Reduced Data Interposer” on page 15
- “W4641A DDR4 x16 BGA 2-Wings Interposer” on page 16
- “W4643A DDR4 x4/x8 BGA 2-Wings Interposer” on page 16

The DDR4 DRAM BGA Interposers enable probing of embedded DDR4 DRAM (x4, x8, and x16) directly at the ball grid array using the Keysight logic analyzers such as U4154A, U4154B, and U4164A logic analyzer modules.

There are separate configuration files for each of the supported logic analyzer module. There are also separate configuration files for the x4, x8 and x16 probes.

W4631A DDR4 x16 BGA Interposer



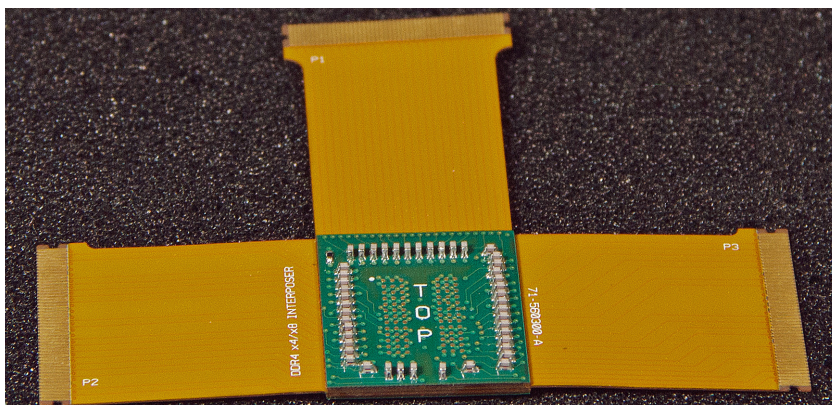
Configuration Files for W4631A Probe

See "To load a configuration file" (in the online help).

For More Information, See

- *Keysight W4630 and W4640 Series DDR4 DRAM BGA Interposers Installation Guide* which can be found on the "[Keysight web site](#)".

W4633A DDR4 x4/x8 BGA Interposer

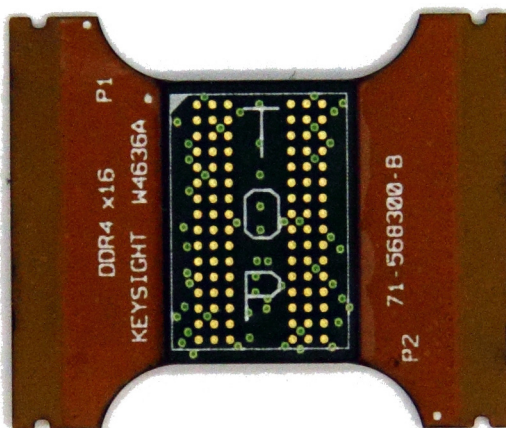
**Configuration Files for W4633A Probe**

See "To load a configuration file" (in the online help).

For More Information, See

- *Keysight W4630 and W4640 Series DDR4 DRAM BGA Interposers Installation Guide* which can be found on the "[Keysight web site](#)".

W4636A DDR4 x16 KOV BGA 2-Wings Command and Reduced Data Interposer

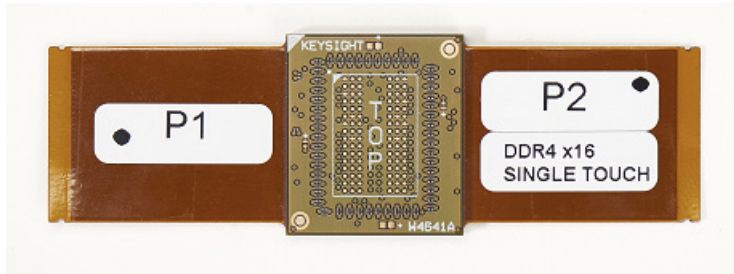
**Configuration Files for W4636A Probe**

See "To load a configuration file" (in the online help).

For More Information, See

- *Keysight W4630 and W4640 Series DDR4 DRAM BGA Interposers Installation Guide* which can be found on the "[Keysight web site](#)".

W4641A DDR4 x16 BGA 2-Wings Interposer



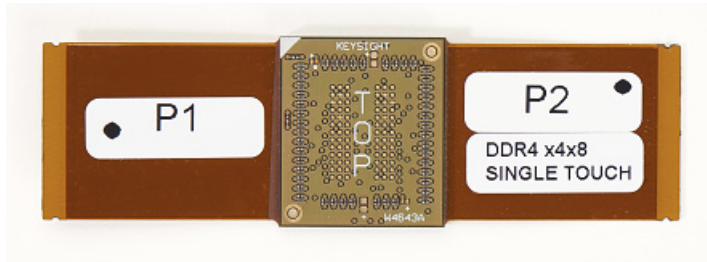
Configuration Files for W4641A Probe

See "To load a configuration file" (in the online help).

For More Information, See

- *Keysight W4630 and W4640 Series DDR4 DRAM BGA Interposers Installation Guide* which can be found on the "[Keysight web site](#)".

W4643A DDR4 x4/x8 BGA 2-Wings Interposer



Configuration Files for W4643A Probe

See "To load a configuration file" (in the online help).

For More Information, See

- *Keysight W4630 and W4640 Series DDR4 DRAM BGA Interposers Installation Guide* which can be found on the "[Keysight web site](#)".

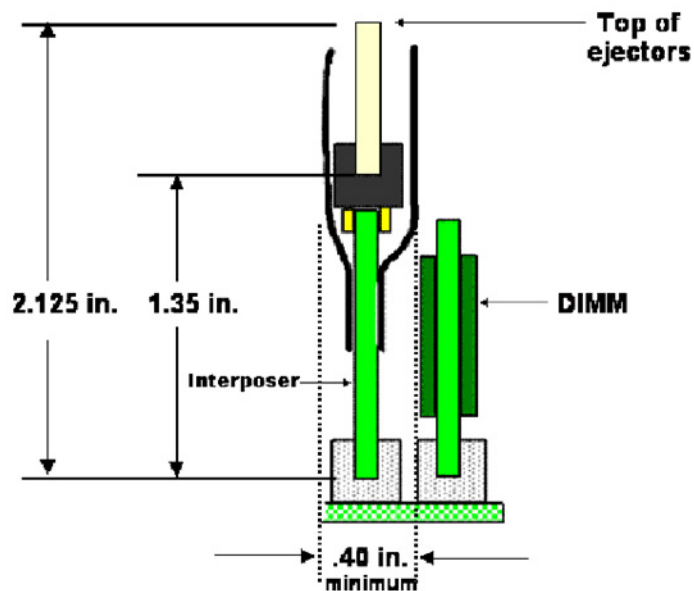
DDR3 DIMM Interposers

- “FS2352 1867 DDR3 DIMM Probe from FuturePlus” on page 18
- “Nexus DDR3 DIMM Interposer” on page 19
- “N4835A (FS2351) DDR3 DIMM Interposer (Discontinued)” on page 20
- “N4821B (FS2350) DDR3 DIMM Interposer (Discontinued)” on page 21

Handling DIMM Interposers

Handle interposers carefully.

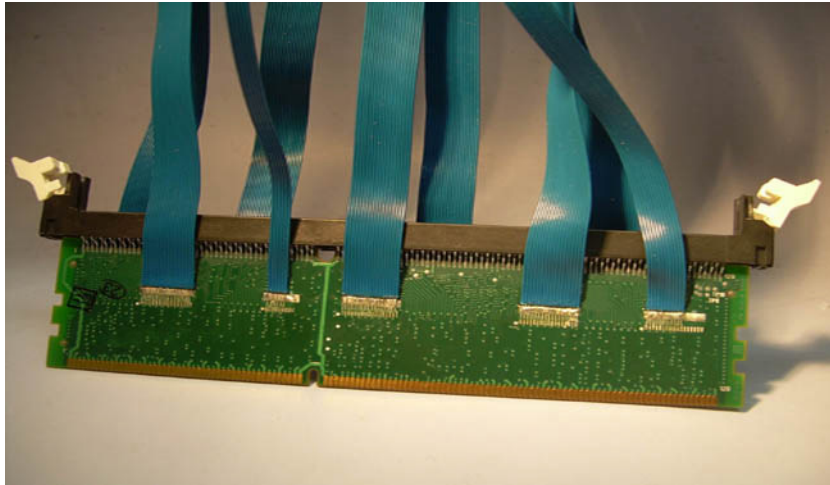
- Provide strain relief for cables.
- Store and ship flat.



Using DIMM Interposers

- 1 First, make sure that the device under test boots without the interposer.
- 2 Power down the device under test.
- 3 Insert interposer into the DIMM socket.
- 4 Fan headers out on either side of interposer.
- 5 Insert the DIMM into the interposer.
- 6 Make connections to the logic analyzer pod cables as shown in the configuration file's general-purpose probe tool.

FS2352 1867 DDR3 DIMM Probe from FuturePlus



FS2352 1867 DIMM probe from FuturePlus works with 16962A logic analyzer modules only.

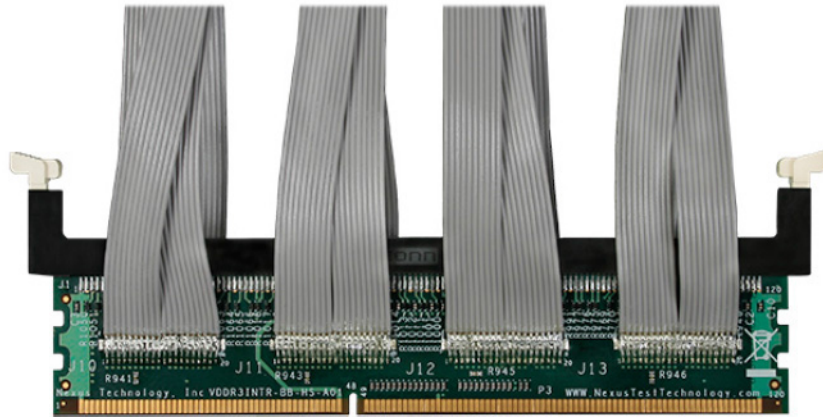
Configuration Files for FS2352

The default location for FuturePlus configuration files is: C:\Documents and Settings\All Users\Shared Documents\Keysight Technologies\Logic Analyzer\Default Configs\FuturePlus

For More Information

- Search for "FS2352" on the ["FuturePlus web site"](#).

Nexus DDR3 DIMM Interposer



The Nexus DDR3 DIMM interposer works with 16962A logic analyzer modules only.

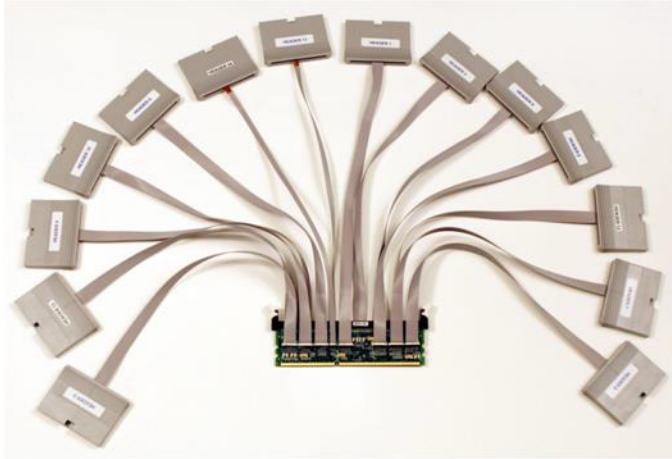
Configuration Files for Nexus DDR3 DIMM Interposer

The default location for Nexus configuration files is: C:\Documents and Settings\All Users\Shared Documents\Keysight Technologies\Logic Analyzer\Default Configs\Nexus

For More Information

- See "[NT-DDR3DIHS information on the Nexus Technology web site](#)".

N4835A (FS2351) DDR3 DIMM Interposer (Discontinued)



N4835A (FS2351) works with 16960A or 16962A logic analyzer modules.

Configuration File for N4835A

There is one configuration file for the N4835A DDR3 DIMM interposer at all data rates.

* CK0 is double probed on N4835A. You can run eye finder and eye scan (that is, logic analyzer Thresholds and Sample Positions set up) on the sample of CK0 that is not used as the actual clock.

CAUTION

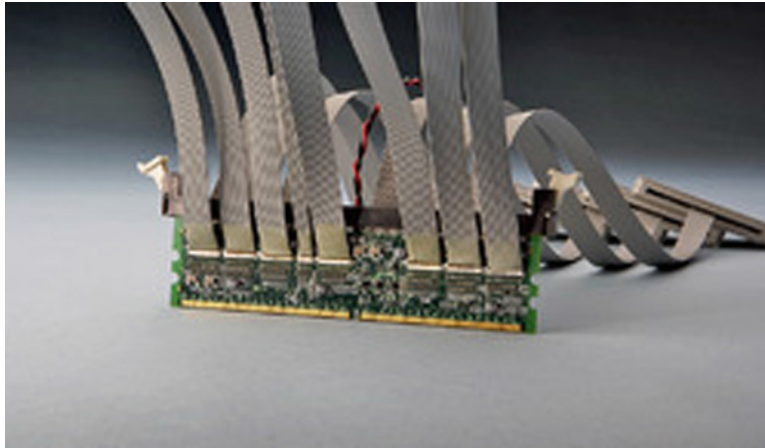
Make sure you have the proper N4835A configuration file for the N4835A (FS2351) interposer. While the pod connections are the same as with the N4821B (FS2350) interposer's 1066/1333 configuration, the signal mapping is not the same!

See "To load a configuration file" (in the online help).

For More Information

- See *Keysight N4835A DDR3 DIMM Interposer Installation Guide* which can be found on the "[Keysight web site](#)".

N4821B (FS2350) DDR3 DIMM Interposer (Discontinued)



N4821B (FS2350) works with 16960A or 16962A logic analyzer modules.

**Configuration Files
for N4821B**

There is one configuration file for the 16962A logic analyzer at all data rates. There are two configuration files for the 16960A logic analyzer module: one for 800/1600 data rates, and one for 1066/1333 data rates.

See "To load a configuration file" (in the online help).

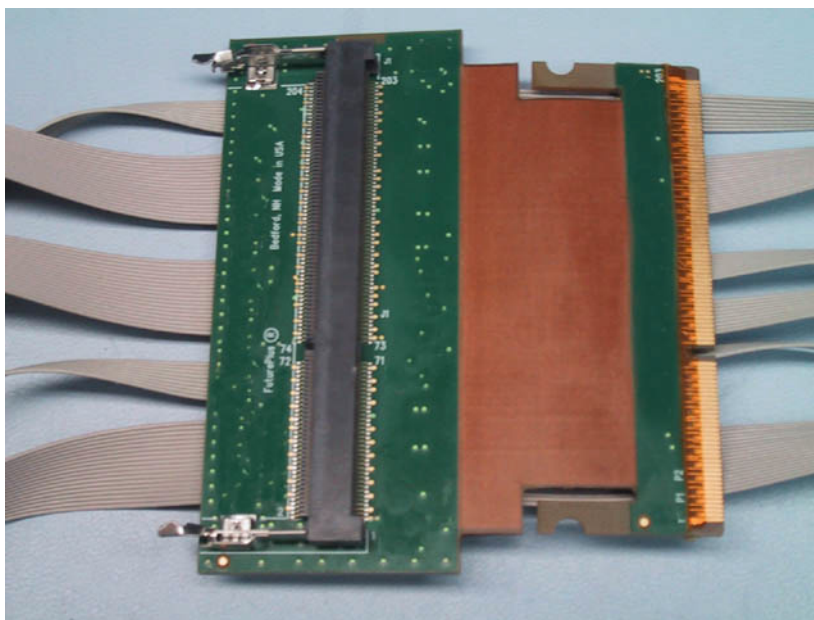
**For More
Information**

- Search for "FS2350" on the ["FuturePlus web site"](#).

DDR3 SODIMM Interposers

- “FS2354 DDR3 SODIMM Interposer” on page 22
- “Nexus DDR3 SODIMM Interposer” on page 23

FS2354 DDR3 SODIMM Interposer



FS2354 SODIMM works with 16962A logic analyzer modules only.

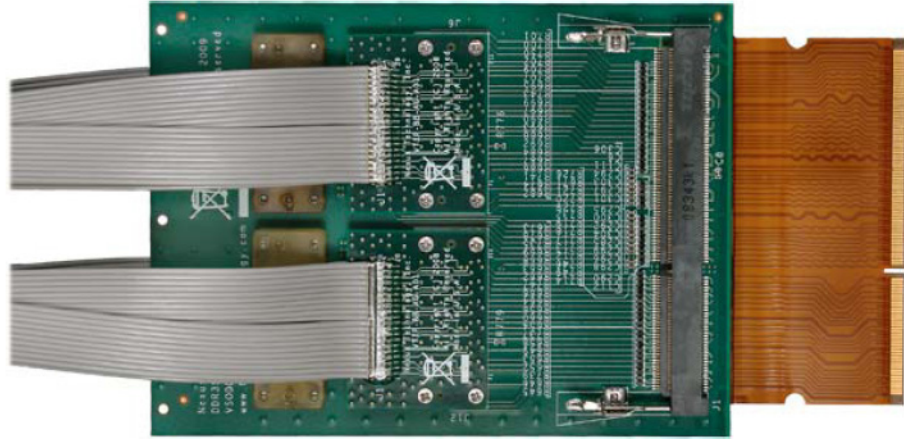
Configuration Files for FS2354

The default location for FuturePlus configuration files is: C:\Documents and Settings\All Users\Shared Documents\Keysight Technologies\Logic Analyzer\Default Configs\FuturePlus

For More Information

- Search for "FS2354" on the "[FuturePlus web site](#)".

Nexus DDR3 SODIMM Interposer



Nexus DDR3 SODIMM interposer works with 16962A logic analyzer modules only.

**Configuration Files
for Nexus DDR3
SODIMM
Interposer**

The default location for Nexus configuration files is: C:\Documents and Settings\All Users\Shared Documents\Keysight Technologies\Logic Analyzer\Default Configs\Nexus

**For More
Information**

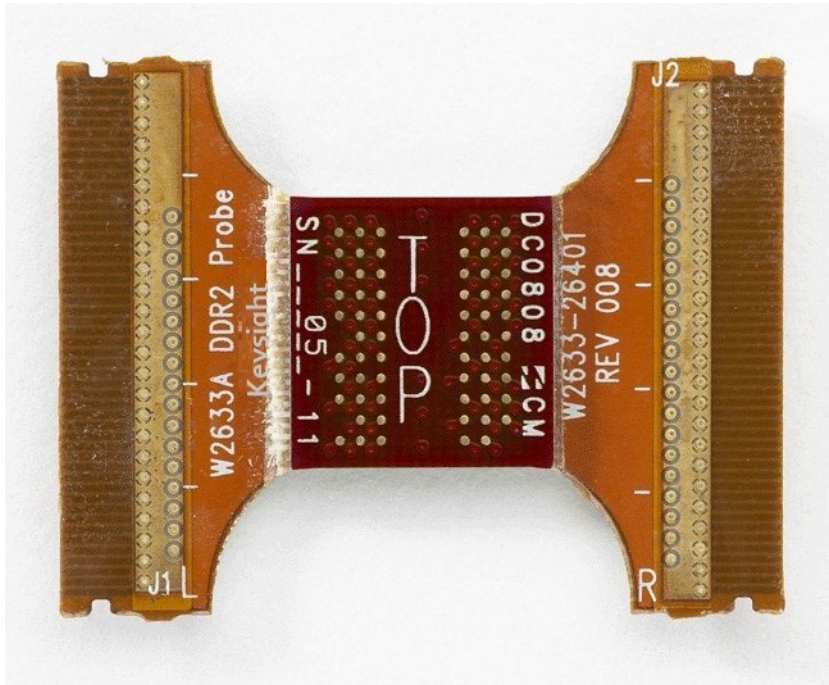
- See "[NT-DDR3SOIHS information on the Nexus Technology web site](#)".

DDR3 BGA Probes

- “W3633A DDR3 BGA x8 Probe” on page 24
- “W3631A DDR3 BGA x16 Probe” on page 25

The DDR3 BGA probes work with 16950A/B or 16962A logic analyzer modules, and there separate configuration files for each. There are also separate configuration files for the x8 and x16 probes.

W3633A DDR3 BGA x8 Probe



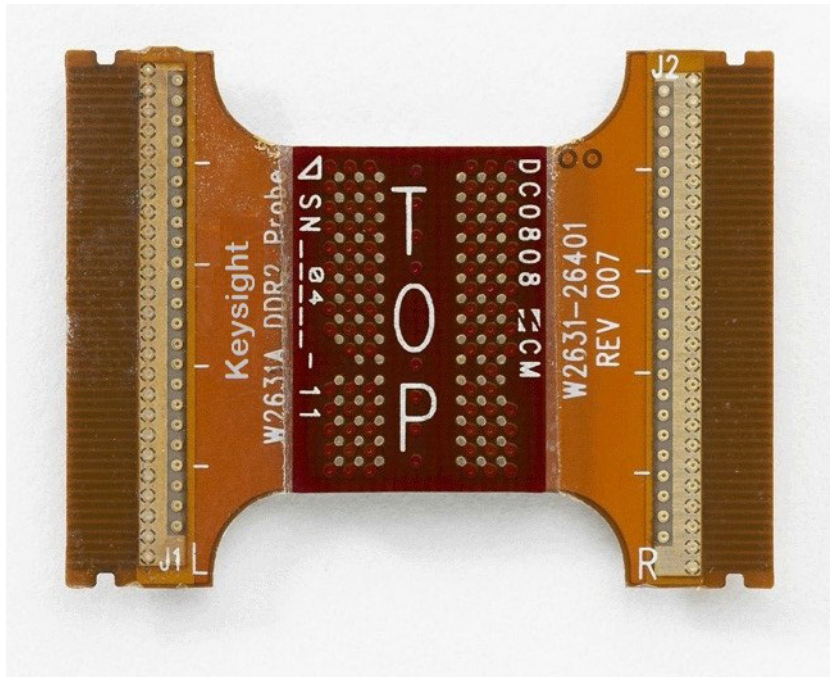
Configuration Files for W3633A Probe

See "To load a configuration file" (in the online help).

For More Information, See

- *Keysight W3630 Series DDR3 DRAM BGA Probes Installation Guide* which can be found on the "[Keysight web site](#)".

W3631A DDR3 BGA x16 Probe



Configuration Files for W3631A Probe

See "To load a configuration file" (in the online help).

For More Information, See

- *Keysight W3630 Series DDR3 DRAM BGA Probes Installation Guide* which can be found on the ["Keysight web site"](#).

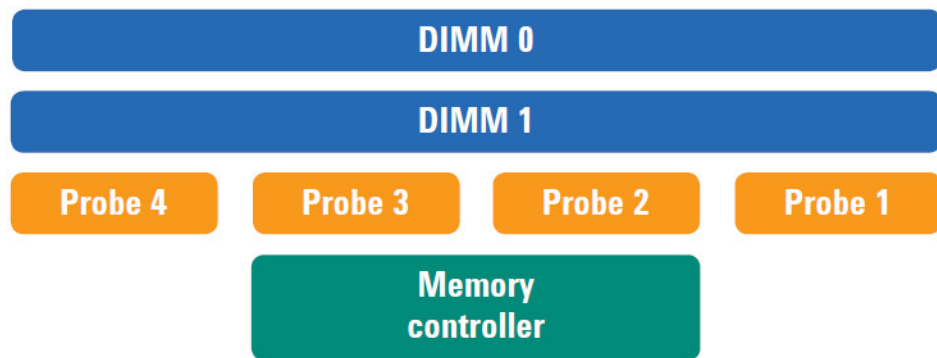
DDR3 Midbus Probes

DDR3 midbus probes require special footprints to be designed into the device under test, and they require double probing. Limited quantities of these probes were available.

- "[N4834A DDR3 Midbus Probe \(Discontinued\)](#)" on page 26

N4834A DDR3 Midbus Probe (Discontinued)

For embedded DDR3 design or validation board design with no constraints on board spaces, the N4834A double probed soft touch probe can be used for midbus probing. The N4834A comes in sets of 4 double probed soft touch probes for connection to four footprints on the board.



The N4834A DDR3 midbus probe works with 16960A or 16962A logic analyzer modules.

Configuration Files for N4834A Probe

See "To load a configuration file" (in the online help).

For More Information

- Search for "N4834A" on the "[Keysight web site](#)".

Configuration Files for W2631A/B, W2632A Probes See "To load a configuration file" (in the online help).

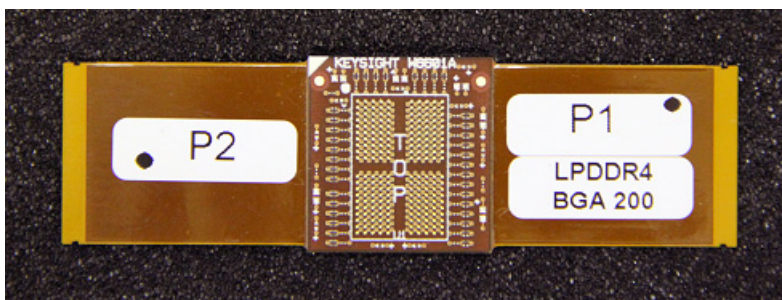
For More Information, See · *Keysight W2630 Series DDR2 DRAM BGA Probes Installation Guide* which can be found on the "[Keysight web site](#)".

LPDDR4 BGA Probes

- “W6601A LPDDR4 BGA Interposer, 200-ball, 2-wings” on page 29
- “W6602A LPDDR4 RC BGA Interposer, 200-ball, Rigid” on page 29

The LPDDR4 BGA probes work with U4164A logic analyzer modules.

W6601A LPDDR4 BGA Interposer, 200-ball, 2-wings



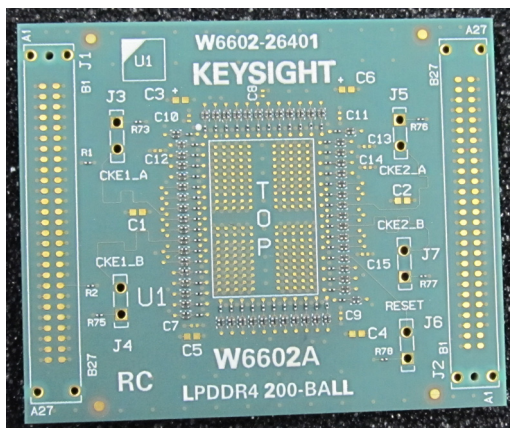
Configuration Files for W6601A Probe

See "To load a configuration file" (in the online help).

For More Information, See

- Keysight W6600A-series LPDDR4 BGA Interposers Installation Guide which can be found on the "[Keysight web site](#)".

W6602A LPDDR4 RC BGA Interposer, 200-ball, Rigid



Configuration Files for W6602A Probe

See "To load a configuration file" (in the online help).

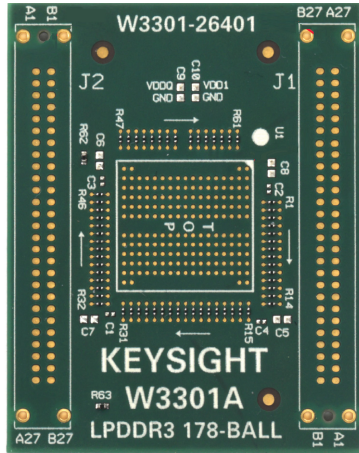
For More Information, See

- Keysight W6600A-series LPDDR4 BGA Interposers Installation Guide which can be found on the "[Keysight web site](#)".

LPDDR3 BGA Probes

The LPDDR3 BGA interposer enables probing of 178-pin JEDEC standard footprint directly at the ball grid array using the Keysight U4154A/B and U4164A logic analyzers.

W3301A LPDDR3 BGA Interposers



Configuration Files for W3301A Probe

See "To load a configuration file" (in the online help).

For More Information, See

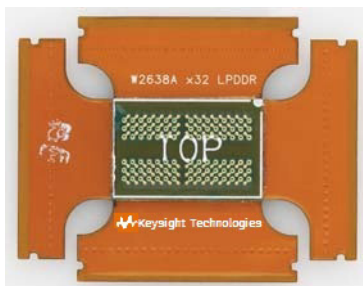
- *Keysight W3301A LPDDR3 BGA Interposers Installation Guide* which can be found on the "[Keysight web site](#)".

LPDDR BGA Probes

- “W2638A LPDDR BGA x32 Probe” on page 31
- “W2637A LPDDR BGA x16 Probe” on page 31

The LPDDR BGA probes work with 16950A/B or 16962A logic analyzer modules, and there separate configuration files for each.

W2638A LPDDR BGA x32 Probe



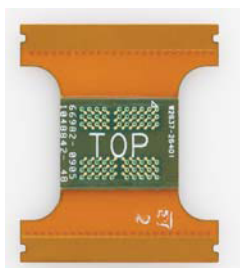
Configuration Files for W2638A Probe

See "To load a configuration file" (in the online help).

For More Information, See

- *W2637A and W2638A LPDDR BGA Probes / W2639A Oscilloscope Adapter Board User's Guide* which can be found on the "[Keysight web site](#)".

W2637A LPDDR BGA x16 Probe



Configuration Files for W2637A Probe

See "To load a configuration file" (in the online help).

For More Information, See

- *W2637A and W2638A LPDDR BGA Probes / W2639A Oscilloscope Adapter Board User's Guide* which can be found on the "[Keysight web site](#)".

Custom Midbus Probing

For custom midbus probing, you can design Soft Touch or Soft Touch Pro footprints into your device under test and route signals to the footprint pads.

- ["Soft Touch / Soft Touch Pro Embedded Custom Midbus Probing"](#) on page 32

Soft Touch / Soft Touch Pro Embedded Custom Midbus Probing

You can design Soft Touch or Soft Touch Pro footprints into your device under test (DUT) and route signals to the footprint pads. Because this type of probing is *custom*, DUT designs are unique. However, there are some common things to consider.

Because DDR data reads and writes occur at different times relative to the bus (and sampling) clock, you must use the logic analyzer's Dual Sample clock mode (see "Dual Sample Sampling Clock Mode" (in the online help)). This affects how signals are probed and mapped to logic analyzer pods. When DDR data rates exceed 2500MT/s, the Quad Sample clock mode must be used (see "Quad Sample Sampling Clock Mode" (in the online help)).

Other considerations for embedded Soft Touch footprints for 16962A or 16960A logic analyzers:

- The CK0 signal must be probed differentially and must be connected to the pod 1 clock of the clocking module (this is the second card up from the bottom of the mainframe).
- The CKE0 signal should be connected to the clock input on pod 2 of the master module. When setting up the state sampling clock options in the logic analyzer, select:
 - CKE0 – latched high for capture out of reset.
 - CKE0 – enabled high as clock qualifier.
- Make sure there are no signal stubs!
- The minimum signals required for DDR logic analysis tools are:
 - CK0, COMMAND, CS#, Data_W, Data_R, CKE*, BA, ADDR, RowADDR, and ColADDR.
 - Custom triggers may require additional signals.

Configuration Files for Soft Touch Probes

With custom probing, you will likely have custom configuration files. Be sure to include a general-purpose probe tool in your Overview configuration to describe how logic analyzer pod connectors should be connected to the probes.

To simplify the procedure of custom configuration file creation, Keysight provides the DDR/LPDDR Custom Configuration Creator tool. The tool ensures that all the layout information needed by DDR/LPDDR Decoder is included in the created configuration file. This tool is a part of the Keysight DDR Setup Assistant and Eyefinder software package. Therefore, the tool is available only after you install this package. To know more about this tool, refer to its online help that gets installed with this tool's software.

For More Information, See

- *Keysight Technologies E5400-Pro Series Soft Touch Connectorless Probes User's Guide* which can be found on the ["Keysight web site"](#).
- *Keysight Technologies Soft Touch Connectorless Probes User's Guide* which can be found on the ["Keysight web site"](#).

2 Before Using the DDR Setup Assistant

Installing Required and Optional Software / 34

Tuning Your DDR DUT to Make the Best Measurements / 35

Setting Up Read and Write Traffic in the DUT / 36

Once you have chosen a solution for probing your DDR device, you must make sure you have the required logic analysis system hardware and software. This includes any necessary probe to logic analyzer cable adapters.

There are also some things you can do to prepare your DDR device under test in order to make the best measurements.

Installing Required and Optional Software

NOTE

While the DDR Setup Assistant works with the *Keysight Logic Analyzer* application on a computer remotely connected to logic analyzer hardware, we recommend you run the DDR Setup Assistant on the logic analysis system that contains the logic analyzer hardware. This is because the logic analyzer's automated Thresholds and Sample Positions set up (also known as logic analyzer *eye finder*) and DDR3 Eyefinder run faster in this configuration.

You can use the Windows operating system's Remote Desktop Connection feature to log into the logic analysis system that has the logic analyzer hardware. The Remote Desktop Connection provides good performance.

Before you begin using the DDR Setup Assistant, make sure the required software (and any desired optional software) is installed.

This software can be downloaded from the Keysight web site at:
["www.keysight.com/find/lpa-sw-download"](http://www.keysight.com/find/lpa-sw-download)

Required Software

The following software is required in order to use the DDR Setup Assistant:

- Keysight Logic Analyzer Application Software, version 04.00 or higher.
- DDR2 and DDR3 Bus Decoder (B4621B, requires a license), version 04.00 or higher. This software decodes the captured signals, showing commands, cycle types, etc. DDR configuration files are included with the bus decoder and many of them assume the bus decoder is present.
- DDR3 Eyefinder, version 04.00 or higher. This software is necessary to set sample positions for Data signals.
- If you have a third-party (non-Keysight) probe, there may be third-party software that is also required.

Optional DDR Tools

The following software is optional but is useful for DDR analysis:

- DDR2/3 Protocol Compliance and Analysis Tool (B4622B, requires a license), version 04.00 or higher. This is an automated test application that evaluates captured LPDDR/LPDDR2 and DDR/DDR2/DDR3 data against a set of user-defined limits to help you validate that a memory system is operating properly. When used with the U4154A/B module, it can evaluate LPDDR3 and DDR4 data as well.

Tuning Your DDR DUT to Make the Best Measurements

There are a couple things you can do to prepare your DDR device under test for making measurements:

- Turn off data scrambling.
- Turn off power management (for initial measurements).

Setting Up Read and Write Traffic in the DUT

READ and WRITE traffic in the DDR device under test (DUT) is required for both Read and Write signal sampling set up. For example:

- Random pattern data tests:
 - Memtest 86 test #7.
- Memory test with alternating patterns:
 - Memtest 86 test #5.
- Video clips.

3 Using the DDR Setup Assistant

Starting the DDR Setup Assistant /	38
Step - Specify Input Parameters /	39
Step - Verify Software Installation /	40
Step - Load Configuration File /	42
Step - Do Hardware Setup /	45
Step - Set Initial Thresholds /	48
Step - Set Sample Positions of Clk/CS Signals (only applicable to U4154A/B Logic Analyzer) /	49
Step - Set Sample Positions of Command/Addr Signals (only applicable to U4154A/B Logic Analyzer) /	51
Step - Set Sample Positions of Ctrl/Addr Signals (not applicable to U4154A/B Logic Analyzer) /	53
Step - Find Latency Values /	55
Step - Set Sample Positions of Data-related Signals (not applicable to U4154A/B logic analyzer) /	66
Step - Set Sample Positions of Data Read/Write (only applicable to U4154A/B Logic Analyzer) /	67
Step - Save Setup /	70
Setup Complete /	71

Starting the DDR Setup Assistant

NOTE

While the DDR Setup Assistant works with the *Keysight Logic Analyzer* application on a computer remotely connected to logic analyzer hardware, we recommend you run the DDR Setup Assistant on the logic analysis system that contains the logic analyzer hardware. This is because the logic analyzer's automated Thresholds and Sample Positions set up (also known as logic analyzer *eye finder*) and DDR3 Eyefinder run faster in this configuration.

You can use the Windows operating system's Remote Desktop Connection feature to log into the logic analysis system that has the logic analyzer hardware. The Remote Desktop Connection provides good performance.

-
- 1 After installing the DDR Setup Assistant, double-click the **DDR Setup Assistant** icon on your desktop to start the DDR Setup Assistant.
The DDR Setup Assistant automatically starts the *Keysight Logic Analyzer* application if it is not already started.

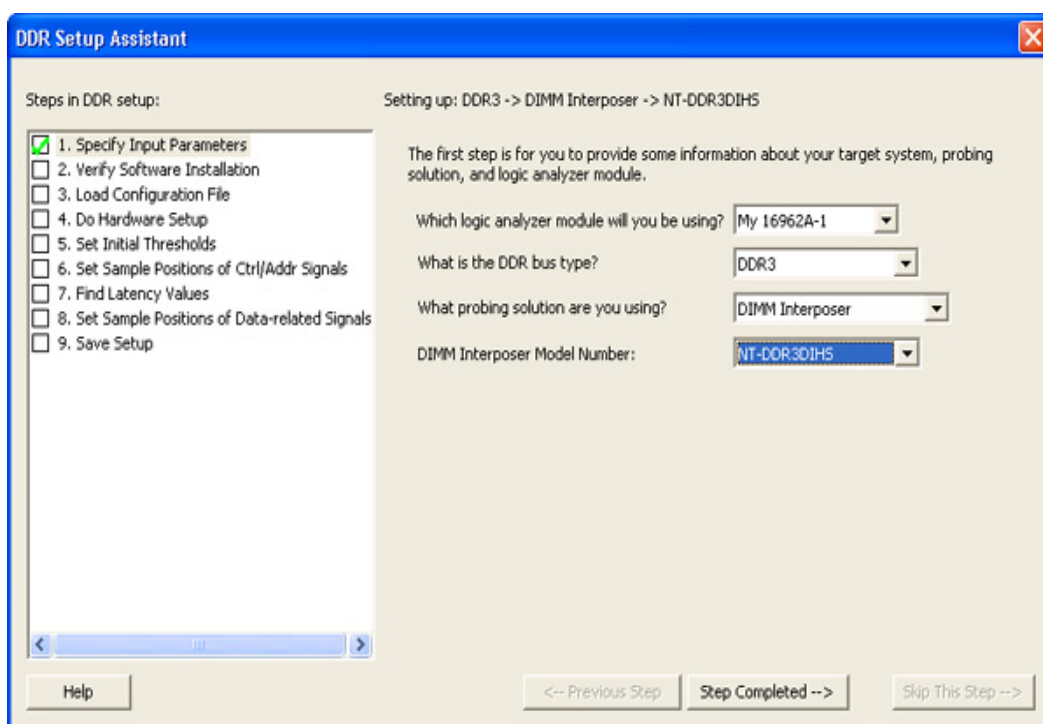
Step - Specify Input Parameters

In this step, you give the DDR Setup Assistant relevant information about your DDR test setup.

- 1 Select the name of the logic analyzer module that will be used to capture DDR signals.
- 2 Select the **DDR bus type**.
- 3 Specify your **probing solution** (see “Options for Probing DDR Devices” on page 13).

Depending on the probing solution you select, you may have additional input parameters to specify. For example:

- When you select the **BGA** probing solution, you have an additional selection for your **DRAM type and data width**.
- When you select the **DIMM Interposer** probing solution, there is an additional selection for the model number.
- When you select the **Softtouch** probing solution, there are no other input parameters to specify.



- 4 When you are finished selecting input parameters, click **Step Completed -->**.

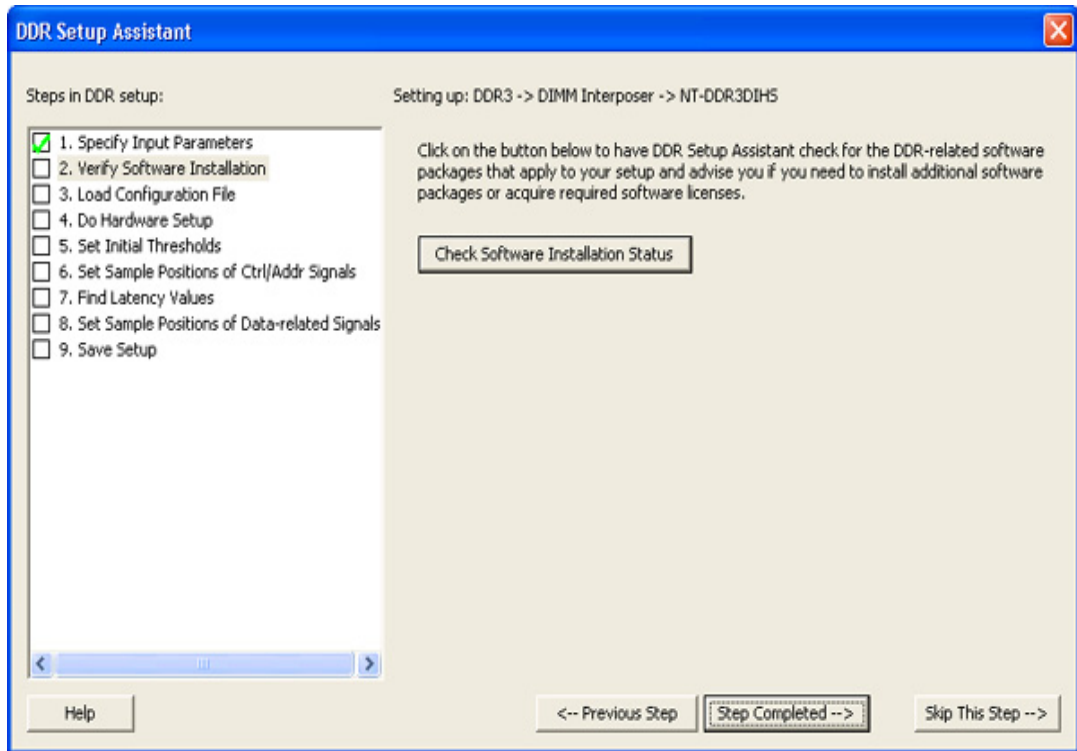
The selections you make in this step identify your setup for the automated DDR Setup Assistant actions that follow.

Next • “Step - Verify Software Installation” on page 40

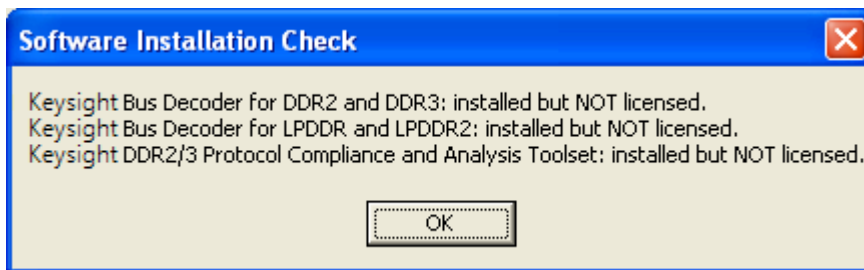
Step - Verify Software Installation

In this step, the DDR Setup Assistant checks to see if the required and optional DDR analysis software has been installed.

- 1 Click **Check Software Installation Status**.



When the check is complete, an information with the software installation status appears.



- 2 If you need to install software:
 - a Close the DDR Setup Assistant.
 - b Close the *Keysight Logic Analyzer* application.
 - c Install the software (see "Installing Required and Optional Software" on page 34).
 - d Restart the *Keysight Logic Analyzer* application.
 - e Restart the DDR Setup Assistant.
 - f Continue with the DDR set up steps.
- 3 Click **Step Completed -->**.

Next · ["Step - Load Configuration File"](#) on page 42

Step - Load Configuration File

In this step, the DDR Setup Assistant loads the selected XML configuration file.

- 1 Select whether you want to load an Keysight-supplied standard configuration file (if you are using an Keysight probing solution) or a custom configuration file (if you are using a custom probing solution).

If you select to load a standard configuration file, the DDR Setup Assistant automatically tries to locate and load an appropriate configuration file based on the input parameters you selected in the first step. The file is loaded from the set of standard configuration files. The default location for these standard configuration files is:

C:\Documents and Settings\All Users\Documents\Keysight Technologies\Logic Analyzer\Default Configs\Keysight

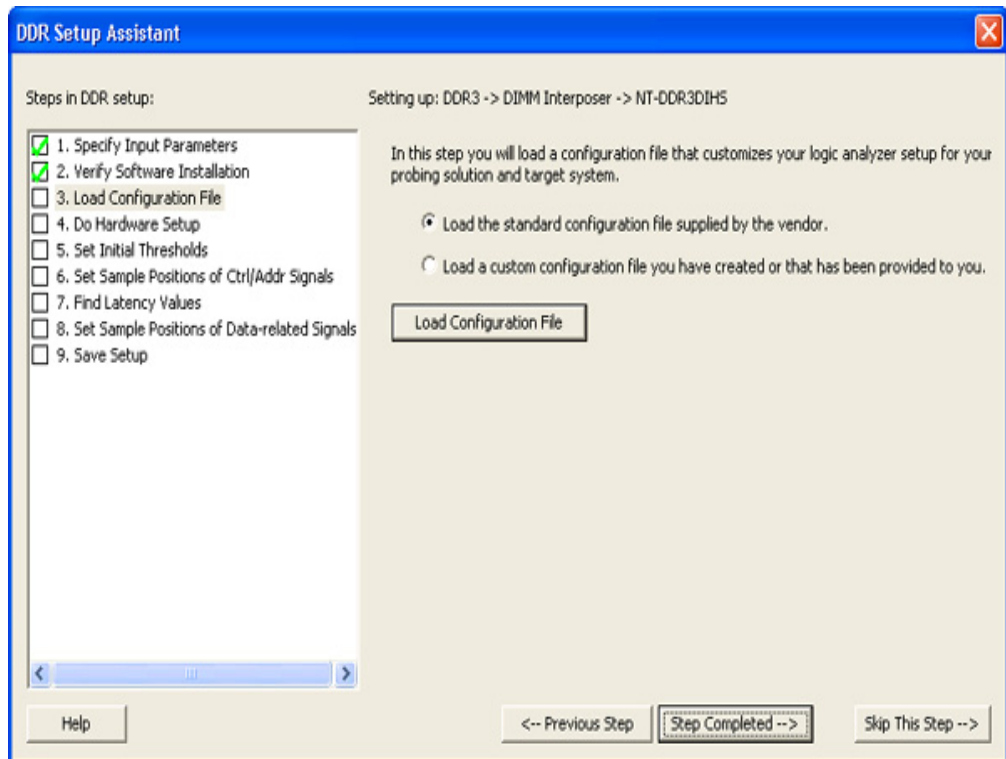
If you select to load a custom configuration file, the DDR Setup Assistant allows you to navigate to the custom configuration file location and select it for loading.

NOTE

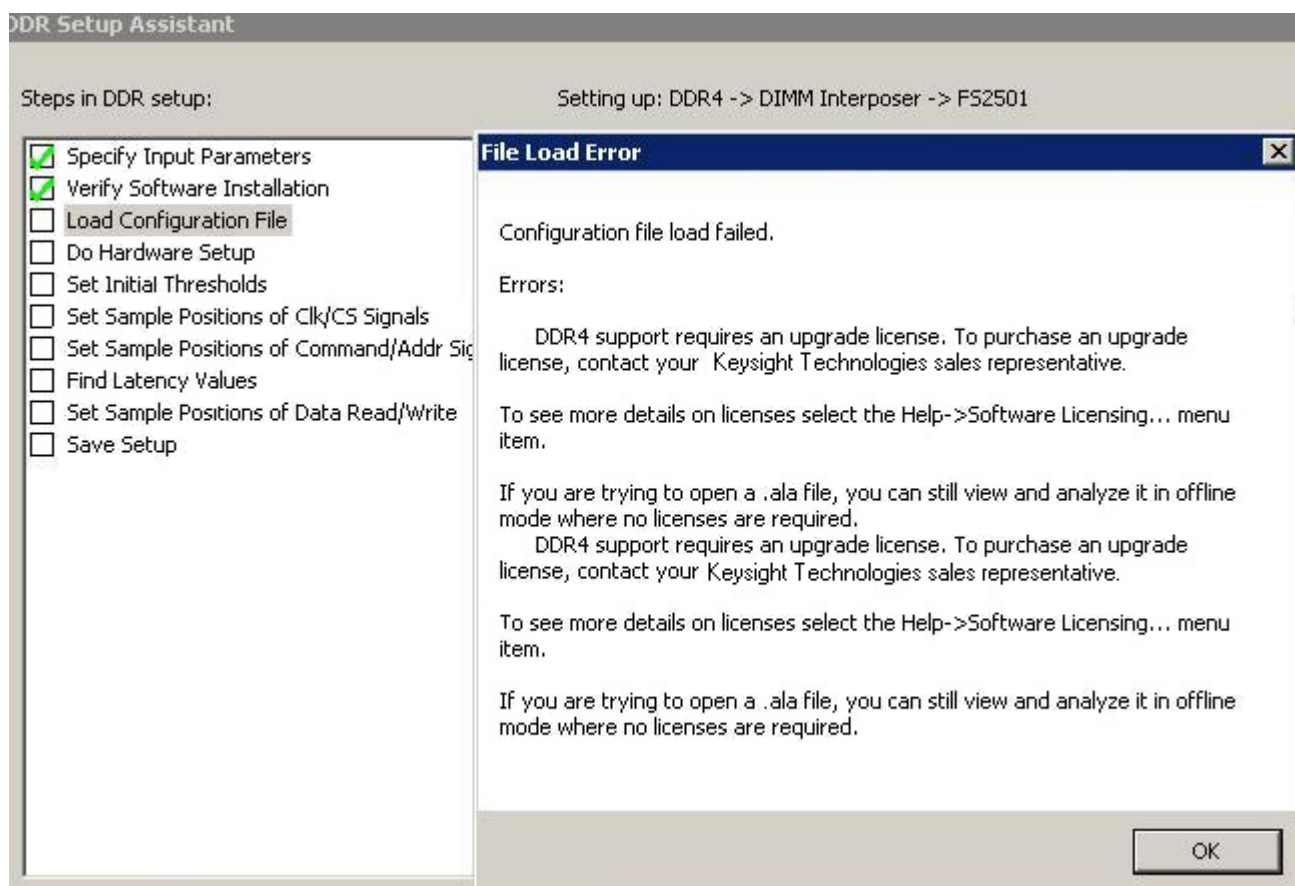
To simplify the procedure of custom configuration file creation, Keysight3 provides the DDR/LPDDR Custom Configuration Creator tool. The tool ensures that all the layout information needed by DDR/LPDDR Decoder is included in the created configuration file. This tool is a part of the Keysight DDR Setup Assistant and Eyefinder software package. Therefore, the tool is available only after you install this package.

To know more about this tool, refer to its online help that gets installed with this tool's software.

- 2 Click **Load Configuration File**.



- If the DDR Setup Assistant cannot find the configuration file for a probe, an error dialog is displayed, and you are given an opportunity to browse for the file.
- If you are using a Soft Touch probing solution, a file browser appears for you to select the configuration file for your custom probing solution.
- In some cases, you may know of a modified configuration file that should be used for a particular probing setup. In this case, you can manually load the configuration file.
- If you selected DDR4 or LPDDR3 as the DDR Bus Type in Step 1 of the wizard and you do not have the B4621B (for DDR) and B4623B (for LPDDR) software licenses installed, then you will not be able to load a standard or a custom DDR4/LPDDR3 configuration file in this step. In such a situation, the following error message will be displayed. To get DDR4 and LPDDR3 support, you must purchase the B4621B and B4623B license respectively.



- 3 If necessary, navigate to the configuration file.
The default location for standard configuration files is:
C:\Documents and Settings\All Users\Documents\Keysight Technologies\Logic Analyzer\Default Configs\Keysight\
Then, select the file and click **Open**.
 - 4 Click **Step Completed -->**.
- Configuration files typically include:
- A general purpose probe tool to define the mapping between device under test signals and logic analyzer pods. If the configuration file doesn't include one, you can add it yourself. See "To define probes" (in the online help).

- A DDR Bus Decoder tool for decoding the captured data. If the configuration file doesn't include one, you can add it yourself. See "To add new tools" (in the online help).

For more information about the configuration files provided for the different DDR probing options, see ["Options for Probing DDR Devices"](#) on page 13.

- Next**
- ["Step - Do Hardware Setup"](#) on page 45

Step - Do Hardware Setup

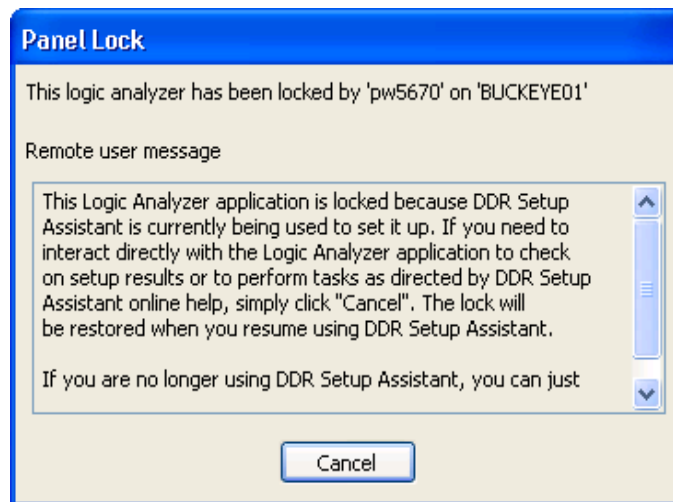
The DDR Setup Assistant takes no actions in this step; it just waits until you tell it the step is completed.

In this step, you must make the proper connections between the device under test and the logic analyzer. This includes:

- Connecting the probing solution to the device under test. (For more information, see [Chapter 1](#), “Options for Probing DDR Devices,” starting on page 13.)
- Connecting the probing solution to the logic analyzer.

When connecting the probing solution to the logic analyzer, the configuration's probe set maps out the probing solution to logic analyzer connection. To access the probe set's mapping:

- 1 Go to the *Keysight Logic Analyzer* application.
- 2 You may have to click **Cancel** in the Panel Lock dialog.

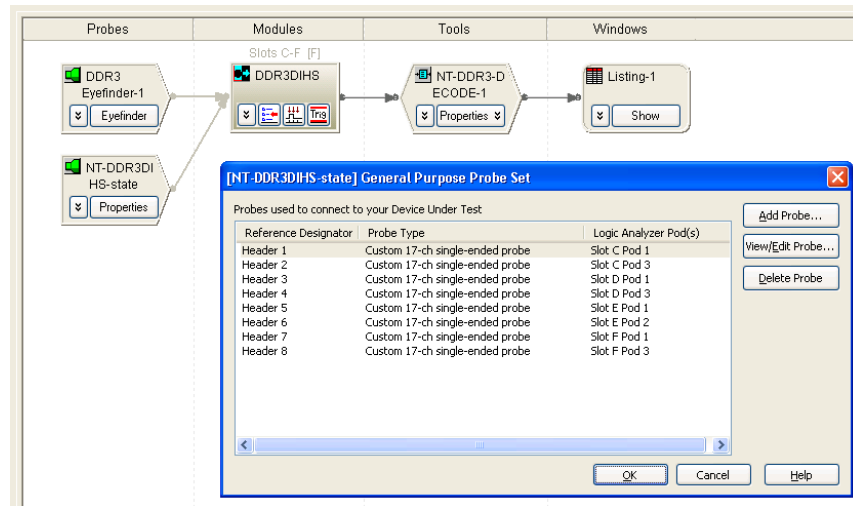


- 3 In the *Keysight Logic Analyzer* application, click the **Overview** tab (or the System Overview icon) to view the Overview window.

In the Overview window, you see a picture of the Probes, Modules, Tools, and Windows used in the configuration.

- 4 Click the probe's **Properties** button.

The General Purpose Probe Set dialog shows how the probe's reference designators map to the logic analyzer pod cables. For example:

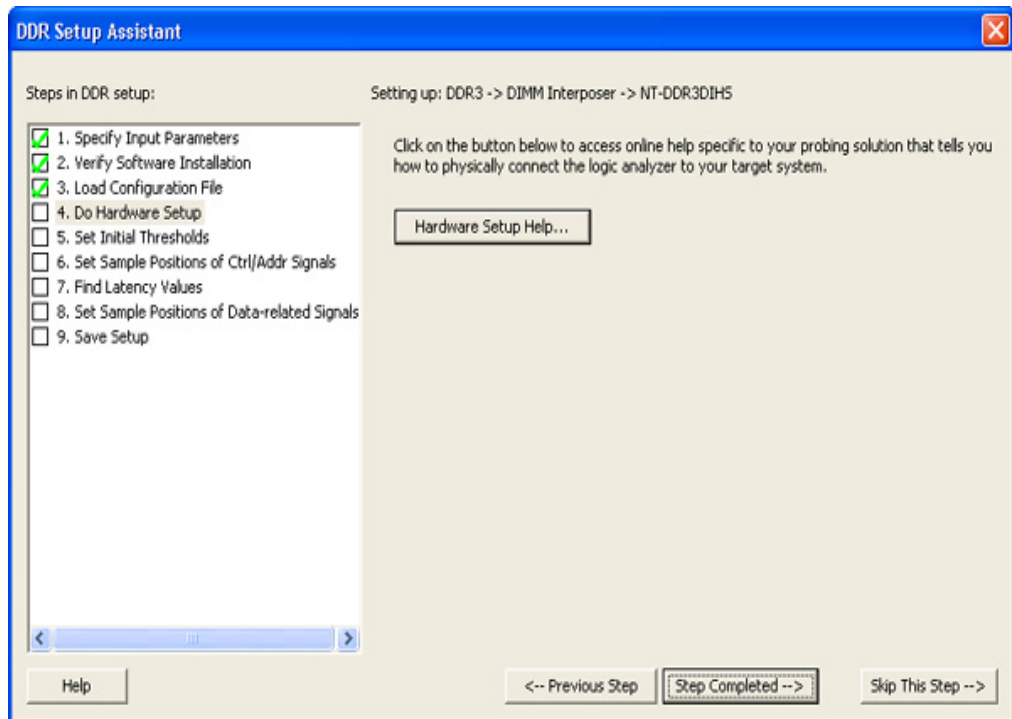


NOTE

The General Purpose Probe Set mapping is different for each configuration. Yours will likely be different than the one shown in the previous screen.

- Carefully connect the probes to the logic analyzer pod cables using the mapping shown in the General Purpose Probe Set dialog.

After you have made the proper probing solution to device under test and probing solution to logic analyzer connections, click **Step Completed -->**.

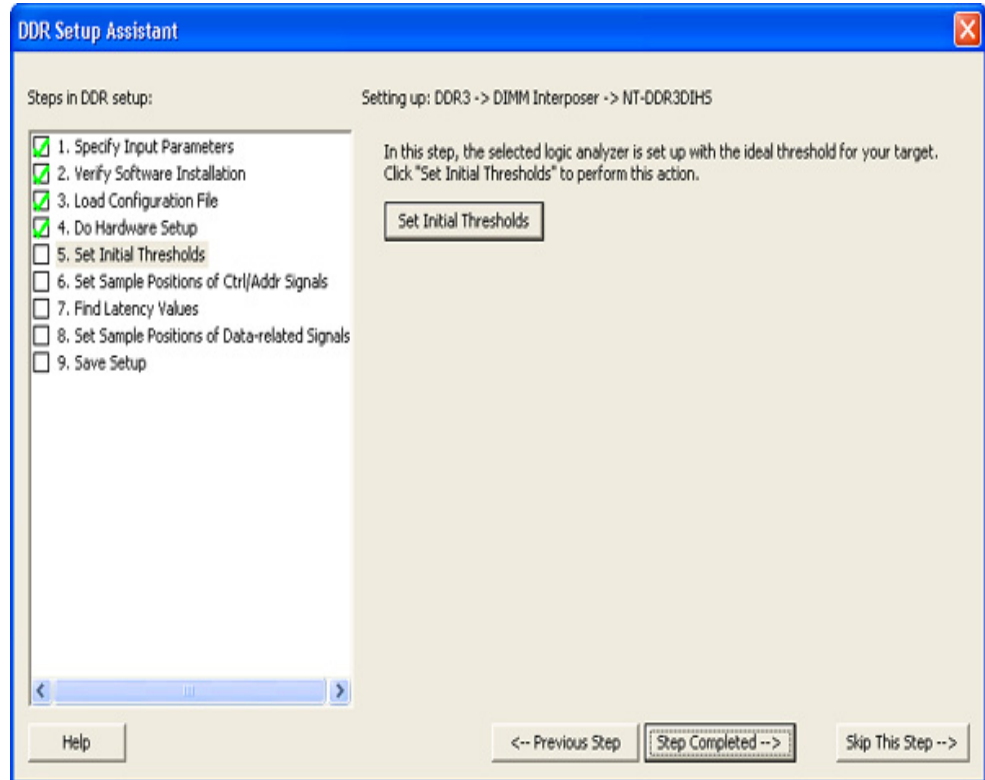


Next · ["Step - Set Initial Thresholds"](#) on page 48

Step - Set Initial Thresholds

In the **Set Initial Thresholds** step, the DDR Setup Assistant automatically sets the initial threshold voltages and detects if there are any problems with the settings.

- 1 Set up your device under test to have read and write traffic (see ["Setting Up Read and Write Traffic in the DUT"](#) on page 36).
- 2 Click **Set Initial Thresholds**.



The DDR Setup Assistant analyzes the swing of certain control signals to determine the best threshold voltage settings.

- 3 If there are problems with the automated initial threshold voltage settings, use the default threshold specified by the configuration file.
- 4 Click **Step Completed -->**.

Next · ["Step - Set Sample Positions of Ctrl/Addr Signals \(not applicable to U4154A/B Logic Analyzer\)"](#) on page 53

Step - Set Sample Positions of Clk/CS Signals (only applicable to U4154A/B Logic Analyzer)

In this step, you set the sample positions of clock and chip select signals when using the U4154A/B Logic Analyzer module. For this step, DDR Setup Assistant runs the eyescan feature of the U4154A/B Logic Analyzer module to automatically calculate and set the optimal sample positions for the clock and chip select signals.

This step is only applicable to the U4154A/B Logic Analyzer.

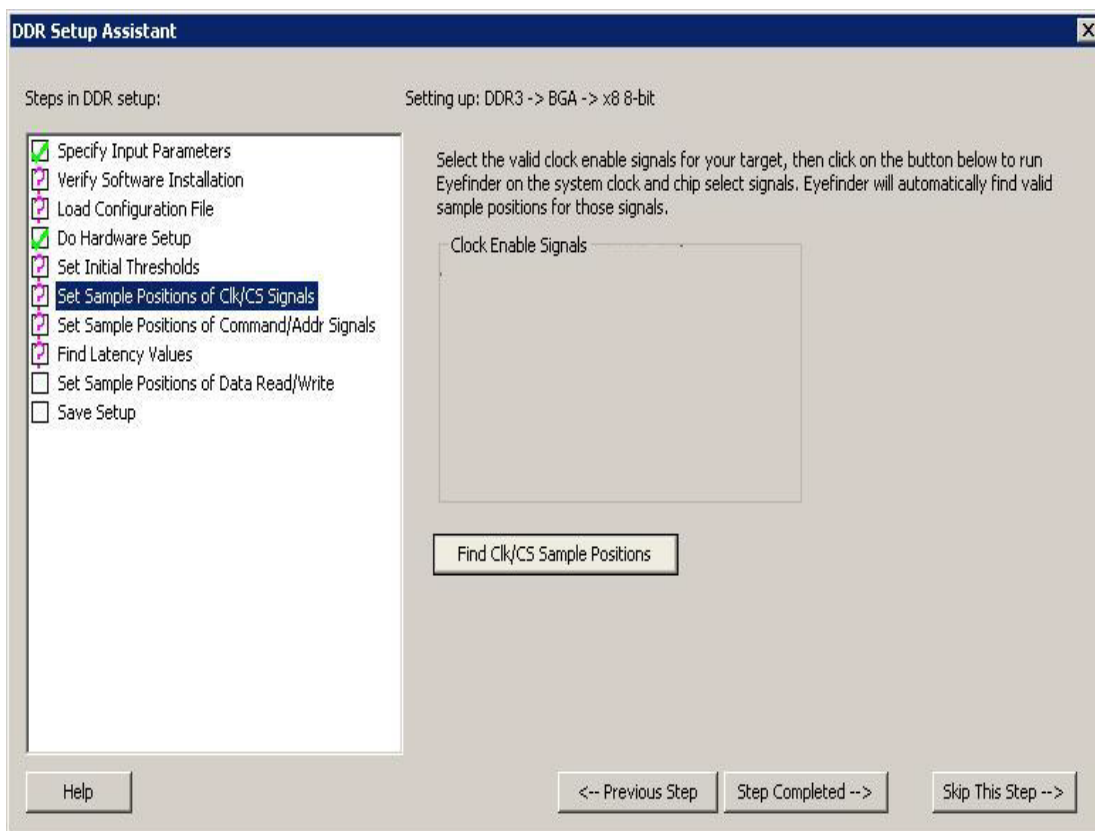
NOTE

If you selected DDR4 as the bus type in step 1 - Specify Input Parameters, then an additional field **DDR4 Command Latency** is displayed in this step.

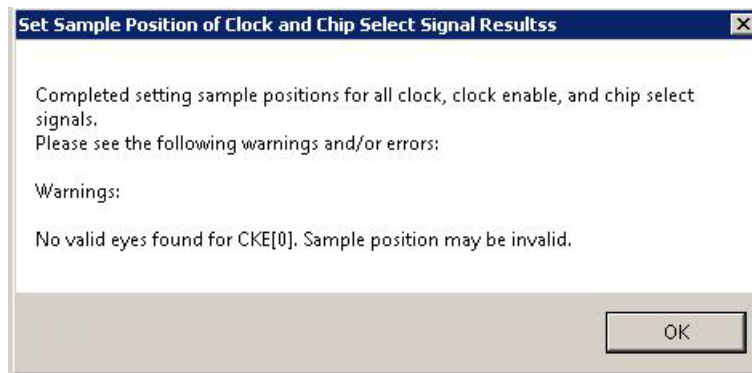
DDR4 Command latency is defined as the number of clocks from chip select going low until the command and address busses are valid.

Select valid clock enable signals and specify a value (ranging from 0 to 6) for DDR4 Command Latency.

- 1 Click Find Clk/CS Sample Positions.



- 2 If the eyescan run completes but gives you warnings, you should check the warnings and re-run if necessary.



- 3 When the clock and chip select signal sample positions have been properly set, click Step Completed -->.

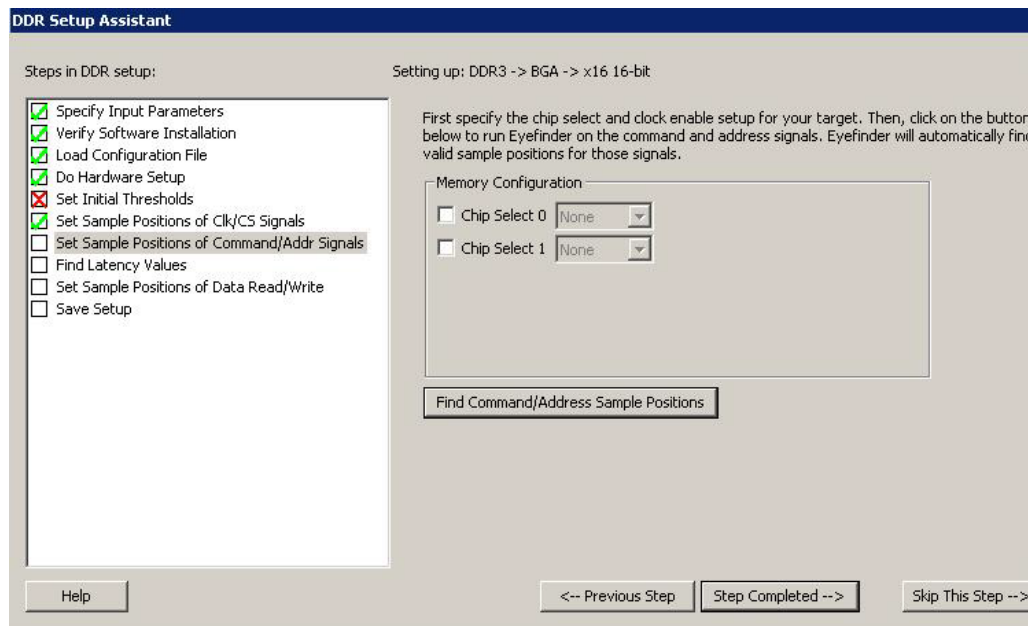
Next · ["Step - Set Sample Positions of Command/Addr Signals \(only applicable to U4154A/B Logic Analyzer\)"](#) on page 51

Step - Set Sample Positions of Command/Addr Signals (only applicable to U4154A/B Logic Analyzer)

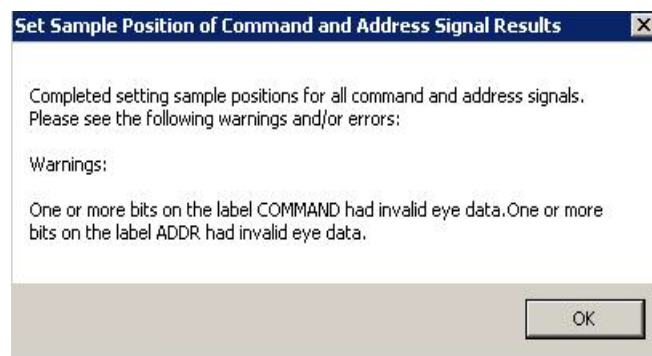
In this step, you set the sample positions of command and address signals when using the U4154A/B Logic Analyzer module. For this step, DDR Setup Assistant runs the eyescan feature of the U4154A/B Logic Analyzer module to automatically calculate and set the optimal sample positions for the command and address signals.

This step is only applicable to the U4154A/B Logic Analyzer.

- 1 Click Find Command/Address Sample Positions.



- 2 If the eyescan run completes but gives you warnings, you should check the warnings and re-run if necessary.



You should determine the cause of these messages by looking at the Keysight Logic Analyzer application's Thresholds and Sample Positions dialog and perhaps re-running the set up. See ["Setting Up Thresholds and Sample Positions on DDR Address/Control Signals"](#) on page 73.

- 3 When the command and address signal sample positions have been properly set, click Step Completed -->.

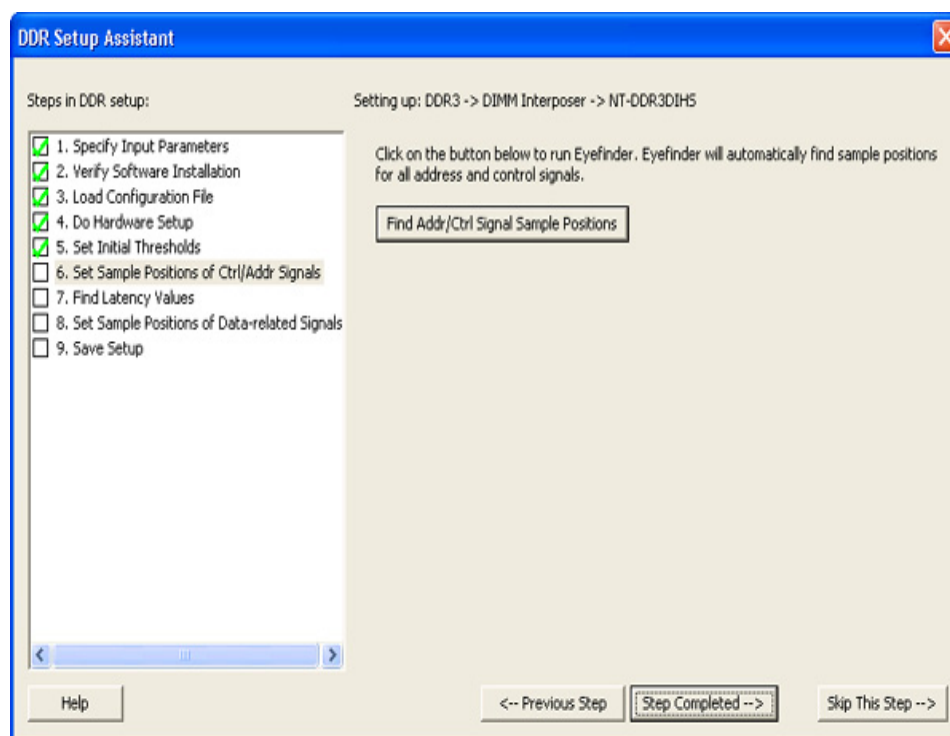
Next • ["Step - Find Latency Values"](#) on page 55

Step - Set Sample Positions of Ctrl/Addr Signals (not applicable to U4154A/B Logic Analyzer)

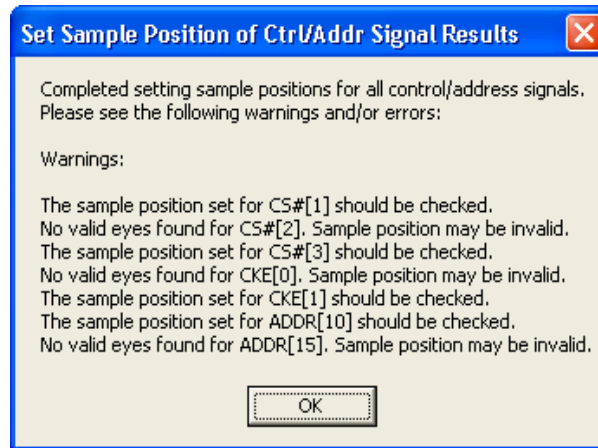
In this step, the DDR Setup Assistant runs the logic analyzer Thresholds and Sample Positions set up (also known as normal logic analyzer *eye finder*) to set the sample positions of the Control and Address signals.

This step is not applicable to the U4154A/B Logic Analyzer.

- 1 Again, make sure your device under test has read and write traffic (see [“Setting Up Read and Write Traffic in the DUT”](#) on page 36).
- 2 Click **Find Addr/Ctrl Signal Sample Positions**.



- 3 If the Thresholds and Sample Positions set up cannot run for some reason, click **Addr/Ctrl Signal Sample Position Help...** (which directs you to [“If there are problems with finding Ctrl/Addr sample positions”](#) on page 54).
- 4 If the Thresholds and Sample Positions set up run completes but gives you warnings, you should check the warnings and re-run if necessary.



For example, in the previous dialog, it may be that the CS#1-3, CKE0-1, ADDR15 signals are not being used, and these messages can safely be ignored. However, ADDR10 is generally used, so you should determine the cause of these messages by looking at the *Keysight Logic Analyzer* application's Thresholds and Sample Positions dialog and perhaps re-running the set up. See [Chapter 4](#), "Setting Up Thresholds and Sample Positions on DDR Address/Control Signals," starting on page 73.

- 5 When the Addr/Ctrl signal sample positions have been properly set, click **Step Completed -->**.

Next · ["Step - Find Latency Values"](#) on page 55

If there are problems with finding Ctrl/Addr sample positions

Generally, problems finding the Ctrl/Addr signal sample positions are basic. Check these things:

- Make sure the device under test is powered on and that the probing solution connections to the device under test and to the logic analyzer are good.
- Make sure there is memory traffic on the DDR bus. Dense traffic is better than sparse traffic when running the logic analyzer Thresholds and Sample Positions set up to determine the Ctrl/Addr signal sample positions.

See Also · ["Solving Problems with Thresholds and Sample Positions Set Up"](#) on page 78

Step - Find Latency Values

In this step, if you don't already know the latency values of the device under test, you set up the Mode Register Settings (MRS) trigger, take a trace, and scan it for latency values. See:

- ["Taking a Mode Register Settings \(MRS\) Trace"](#) on page 56

When you have the proper latency values for the device under test, enter the values into the DDR Setup Assistant; then, click **Apply**.

NOTE

The latency values that you specify in this step represent the total latency for your system and therefore should include parameters that affect total latency. For instance, if your system has Additive Latency (AL), then you must include it in the Total Latency values. Similarly, if tDQSS or tDQSK parameters are greater than one full clock cycle, then you must add these values (rounded to the nearest integer) in the Total Latency values.

DDR Setup Assistant

Steps in DDR setup: Setting up: DDR3 -> SODIMM Interposer -> NT-DDR350IHS

- Specify Input Parameters
- Verify Software Installation
- Load Configuration File
- Do Hardware Setup
- Set Initial Thresholds
- Set Sample Positions of Clk/CS Signals
- Set Sample Positions of Command/Addr Signals
- Find Latency Values
- Set Sample Positions of Data Read/Write
- Save Setup

Click on the button below to access online help that tells you how to find the latency specific to your target system.

Latency Help...

Once you know the latency values, enter them in the fields below and click "Apply" those values in the Logic Analyzer DDR tools.

Total Read Latency

Total Write Latency

NOTE: Total Latency is the total number of clock cycles from the valid Read or Write command to valid data. This includes CAS Latency, CAS Write Latency, Additive Latency (AL), and tDQSS or tDQSK (rounded to the nearest integer).

Apply

Help <-- Previous Step Step Completed --> Skip This Step

When you apply the latency values settings, the DDR Setup Assistant automatically transfers these settings to the DDR Bus Decoder and in the DDR3 Eyefinder / Eyescan.

You can also modify the DDR Bus Decoder and DDR3 Eyefinder / Eyescan settings yourself (or edit them later) by following these instructions:

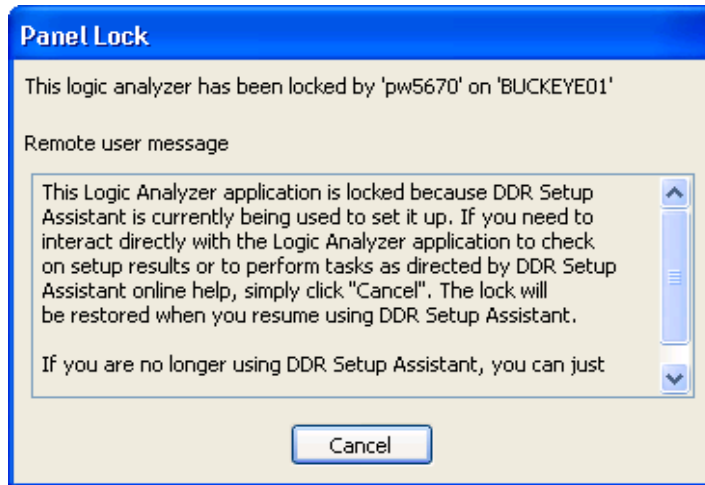
- ["Setting Latency Values in DDR Bus Decoder"](#) on page 59
- ["Setting Latency Values in DDR3 Eyefinder"](#) on page 61
- ["Setting Latency Values in Eyescan"](#) on page 62

When you have found and transferred the latency values, click **Step Completed -->**.

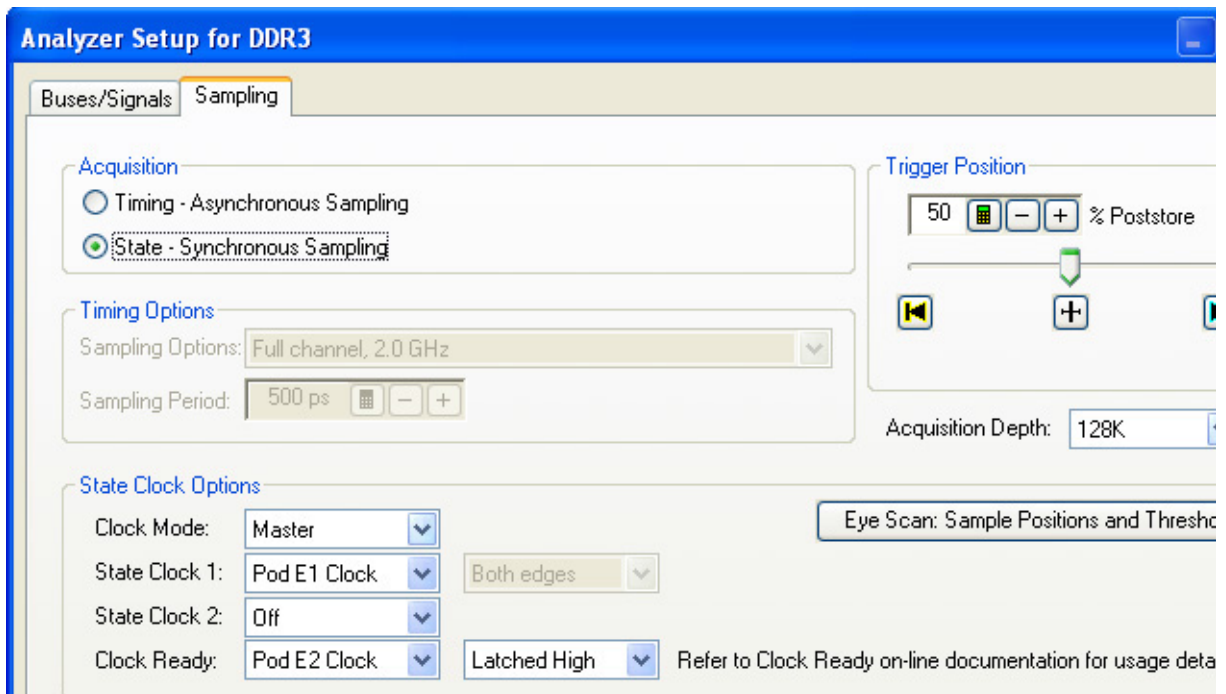
- Next**
- “Step - Set Sample Positions of Data-related Signals (not applicable to U4154A/B logic analyzer)” on page 66
 - “Step - Set Sample Positions of Data Read/Write (only applicable to U4154A/B Logic Analyzer)” on page 67

Taking a Mode Register Settings (MRS) Trace

- 1 Go to the *Keysight Logic and Protocol Analyzer* application.
- 2 You may have to click **Cancel** in the Panel Lock dialog.

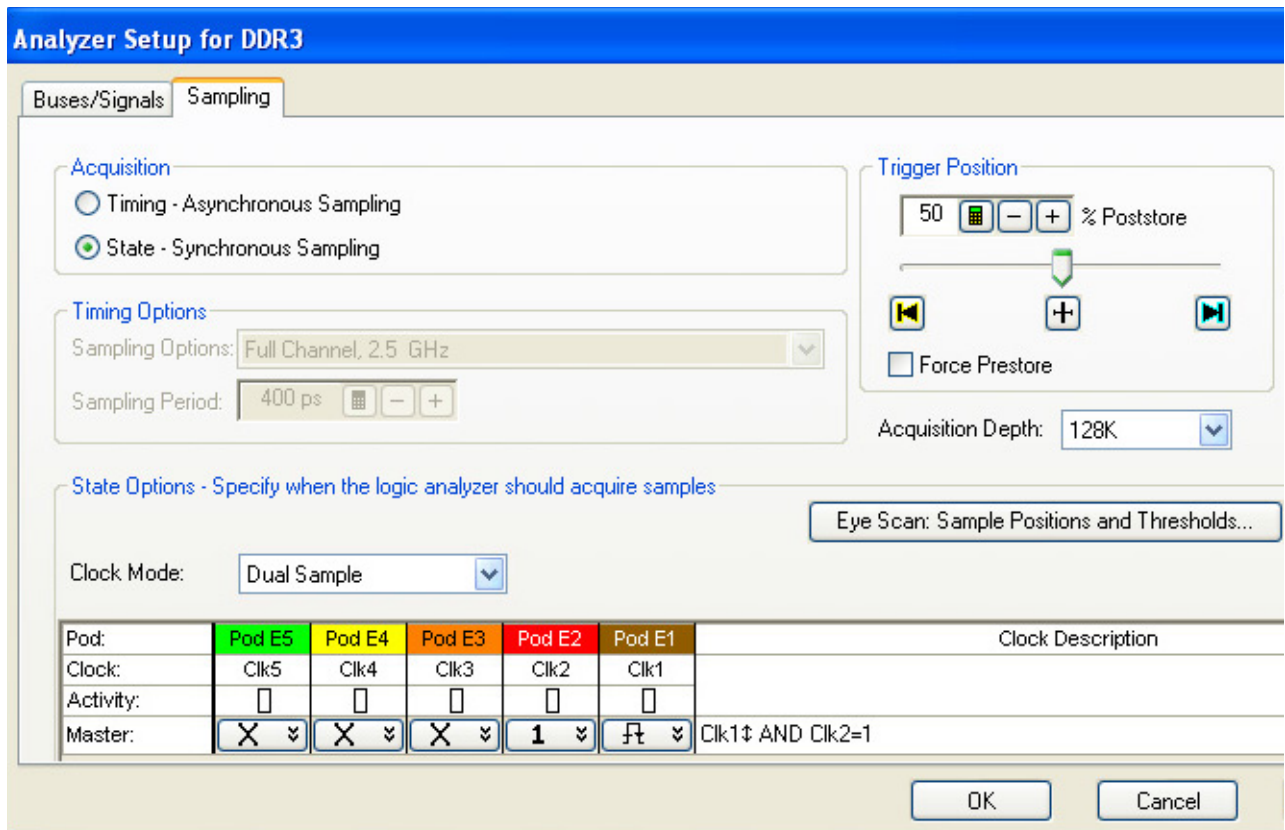


- 3 For 16962A or 16960A Logic Analyzers - In the Keysight and Protocol Logic Analyzer application's Sampling Setup, change the Clock Ready state clock option to Latched High for the clock input of Pod 2 (Clk2) as displayed in the following screen.



The CKE0 signal is routed to the CLK input on pod 2 of the logic analyzer module and CK0 is routed to the CLK input on pod 1.

For U4154A/B Logic Analyzers - In the Keysight Logic and Protocol Analyzer application's Sampling Setup, set the clock input of Pod 2 (Clk2) as the state clock qualifier - Qualifier -High as displayed in the following screen. Notice that the Qualifier - High option is represented by "1" in the following screen.



- 4 Power off the device under test.
- 5 In the *Keysight Logic Analyzer* application's Advanced Trigger dialog, recall the **Mode Register Settings** trigger.

NOTE

If your device under test does not complete Mode Register Setting before the first memory write, change the Mode Register Settings trigger by replacing the sequence step that triggers on the first memory write with the "Run until user stop" trigger function. (Do not change the default storage.)

- 6 Run the logic analyzer with Mode Register Settings trigger (clock ready latched high on CKE0_qual)
The logic analyzer runs status shows "Waiting for trigger in Trigger Step 1...".
- 7 Power on the device under test.
- 8 In the *Keysight Logic Analyzer* application's Listing window, go to the trigger.
The trigger is the first Write to Memory.
- 9 Scroll backward from the trigger to find the last Latency settings before the memory write.


Sample Number	DDR Bus Decode	Cycle Type
		Click here for tri
28.3	RZQ/4	Extended ...
28.4	AL Disable	Extended ...
28.5	Write Leveling Disable	Extended ...
28.6	TDQS Disabled	Extended ...
28.7	Qoff = 'Output Buffer Disabled'	Extended ...
29		Idle
30	MRO	Command
30.1	Burst Length = '8'	Extended ...
30.2	Read Burst Type = 'Interleave'	Extended ...
30.3	CAS Latency = '7'	Extended ...
30.4	TM Mode = 'Normal'	Extended ...
30.5	DLL Reset = 'Yes'	Extended ...
30.6	Write recovery cycle = '10'	Extended ...
30.7	Precharge Power Down = 'Fast exit(...	Extended ...
31		Idle
32	MR3	Command
32.1	MPR Location = 'Predefined Pattern'	Extended ...
32.2	Data Flow From MPR	Extended ...
33		Idle

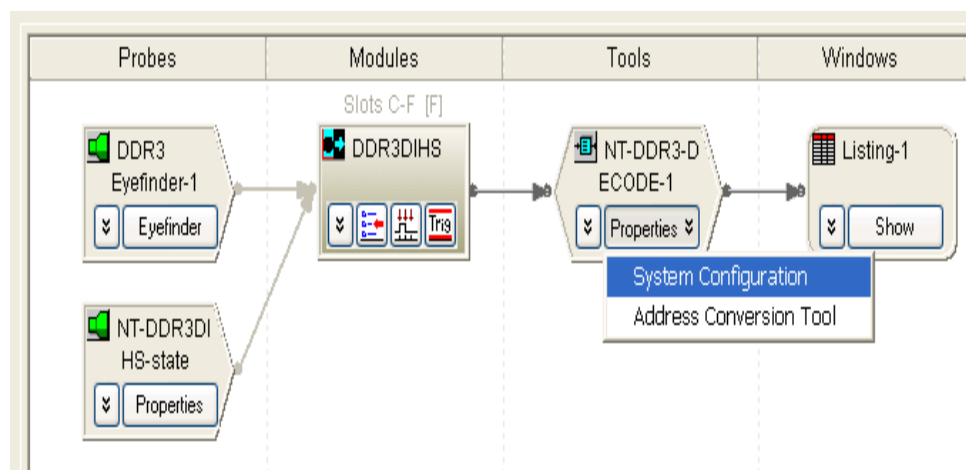
10 Record the values for:

- Read latency.
- Write latency.
- Burst length.
- Burst type (sequential or interleaved).

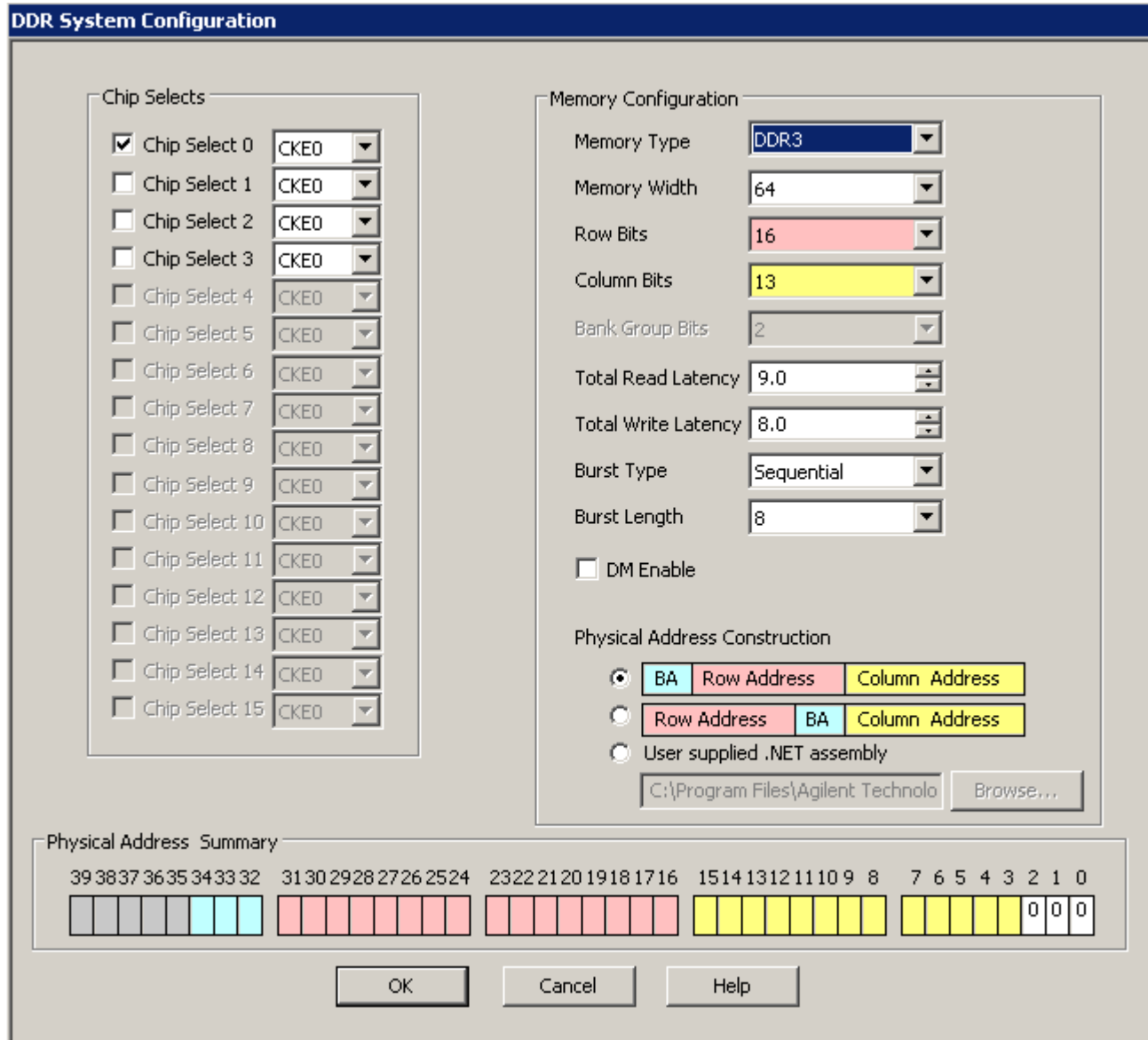
Setting Latency Values in DDR Bus Decoder

To set the device under test's latency and burst values in the DDR Bus Decoder:

- 1 In the *Keysight Logic and Protocol Analyzer* application, click the **Overview** tab (or the  System Overview icon) to view the Overview window.
- 2 In the DDR Bus Decoder tool (in the Tools column), click the **Properties** button and choose **System Configuration**.



The System Configuration dialog is displayed.



- 3 In the System Configuration dialog, enter or select:
 - The appropriate **Chip Select** and **CKE** for the device under test.
 - **Total Read Latency**(or **Read Offset**in some decoders) – Enter the total Read latency value recorded earlier.
 - **Total Write Latency**(or **Write Offset**in some decoders) – Enter the total Write latency value recorded earlier.


NOTE

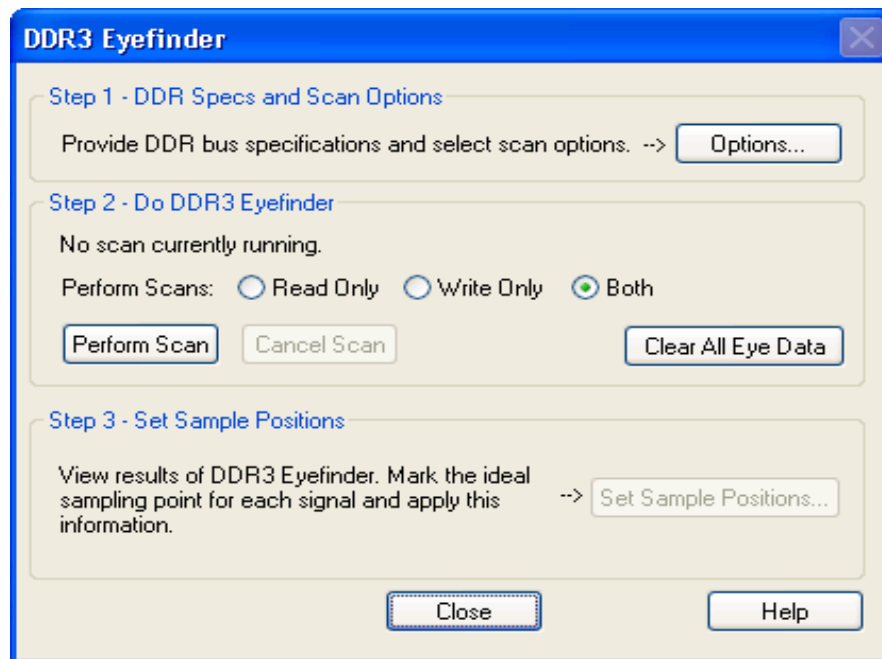
The latency values that you specify in the System Configuration dialog represent the total latency for your system and therefore should include parameters that affect total latency. For instance, if your system has Additive Latency (AL), then you must include it in the Total Latency values. Similarly, if tDQSS or tDQSK parameters are greater than one full clock cycle, then you must add these values (rounded to the nearest integer) in the Total Latency values.

- **Burst Type**— Enter the Burst type value recorded earlier.
 - **Burst Length**— Enter the Burst length value recorded earlier.
- 4 Click **OK**.

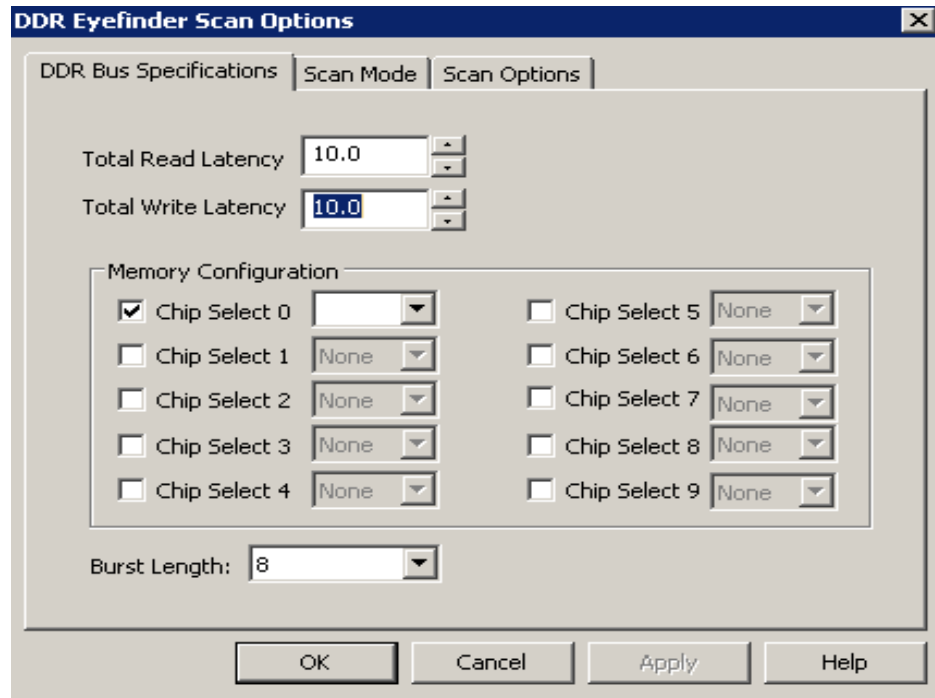
Setting Latency Values in DDR3 Eyefinder

To set the device under test's latency and burst values in DDR3 Eyefinder:

- 1 In the *Keysight Logic and Protocol Analyzer* application, click the **Overview** tab (or the  System Overview icon) to view the Overview window.
- 2 In the DDR3 Eyefinder probe (in the column on the left), click the **Eyefinder** button.
- 3 In the DDR3 Eyefinder dialog, click **Options...**



- 4 In the DDR3 Eyefinder Scan Options dialog's DDR Bus Specifications tab, enter or select:



- **Total Read Latency**– Enter the total read latency value recorded earlier.
- **Total Write Latency**– Enter the total Write latency value recorded earlier.

NOTE



The latency values that you specify in the DDR3 Eyefinder represent the total latency for your system and therefore should include parameters that affect total latency. For instance, if your system has Additive Latency (AL), then you must include it in the Total Latency values. Similarly, if tDQSS or tDQSK parameters are greater than one full clock cycle, then you must add these values (rounded to the nearest integer) in the Total Latency values.

- **Memory Configuration**– Choose the appropriate Chip Select(s) for the memory path being traced.
 - **Burst Length**– Enter the Burst length value recorded earlier.
- 5 Click **OK**.

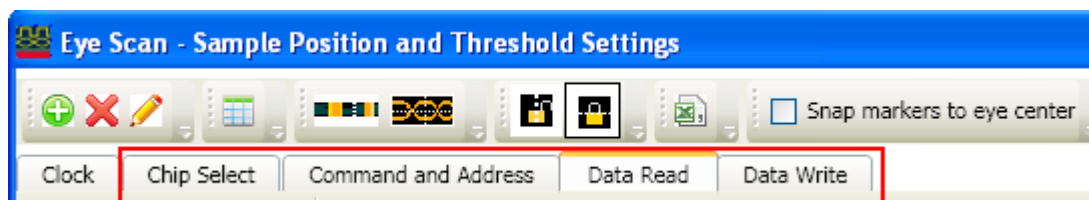
Setting Latency Values in Eyescan


When using the U4154A/B Logic Analyzer module, you can modify the device under test's latency and burst values in Eyescan. The Eyescan feature of U4154A/B displays the default latency values or the latency values that you initially set using the DDR Setup Assistant tool. If required, you can modify these values for subsequent eyescan runs.

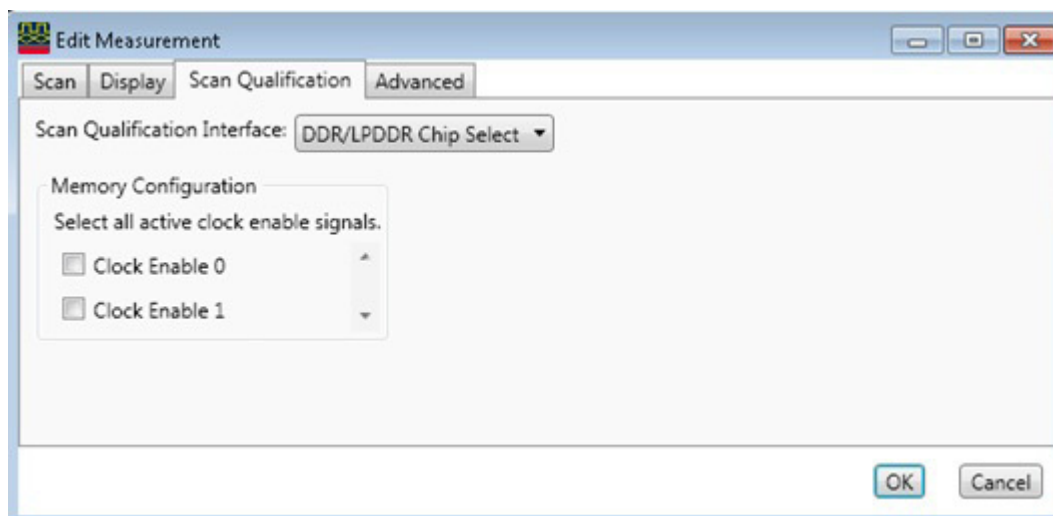
To modify the latency and burst values using the Eyescan feature:

- 1 In the Keysight Logic and Protocol Analyzer application, click the Overview tab (or the  System Overview icon) to view the Overview window.
- 2 Click the  Sampling Setup icon in the U4154A/B logical module displayed under the Modules column in the Overview window.
The Sampling tab of the Analyzer Setup dialog box is displayed.

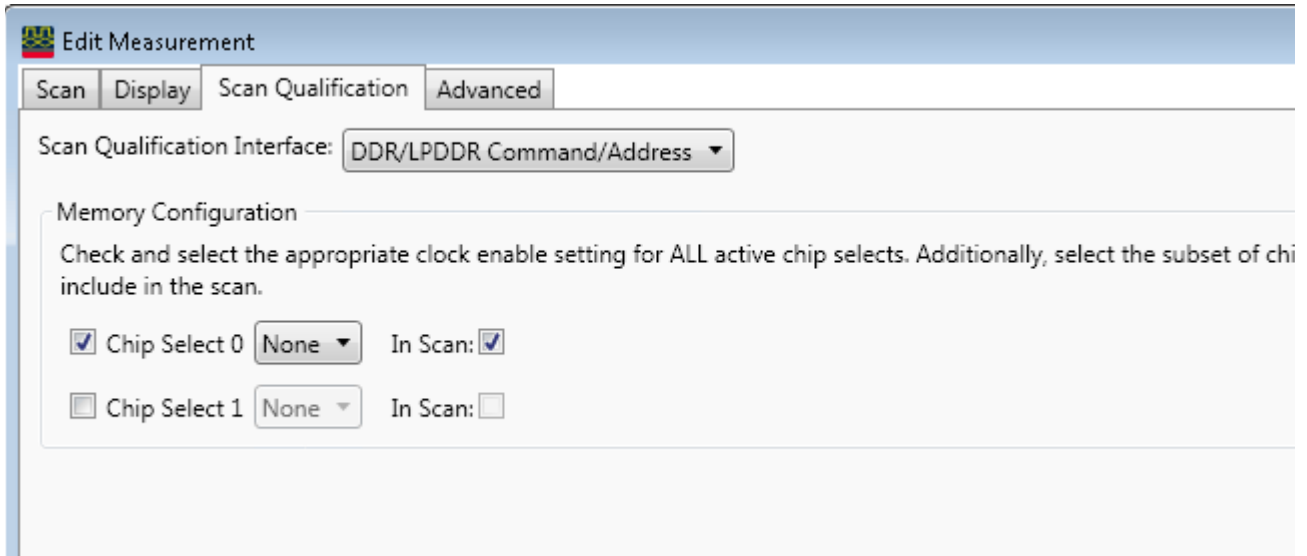
- 3 Click the Eye Scan: Sample Positions and Thresholds... button.
The Eye Scan - Sample Position and Threshold Settings dialog box is displayed.
- 4 In the Eye Scan - Sample Position and Threshold Settings dialog box, select the tab for Chip Select, Command and Address, Data Read or Data Write to modify the scan qualification for the appropriate signals.



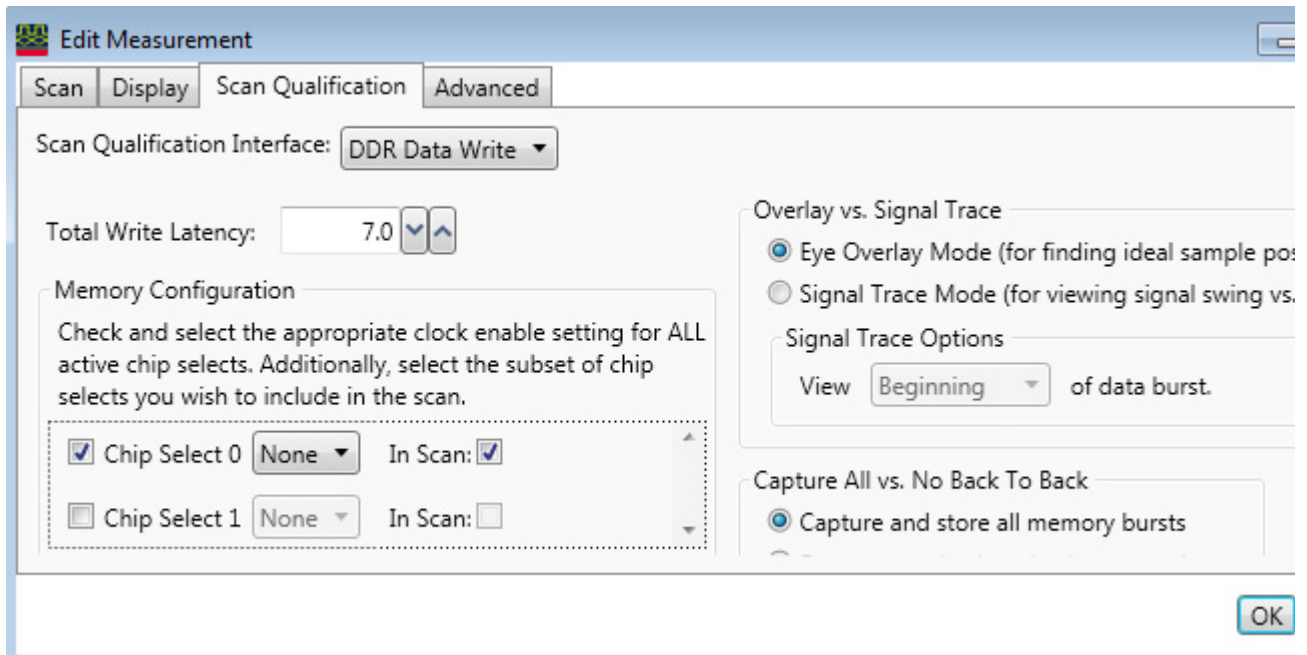
- 5 Click the Edit Current Measurement  toolbar button.
The Edit Measurement dialog box is displayed.
- 6 Click the Scan Qualification tab in this dialog box.
- 7 Based on the signals tab you selected in step 4, the options are displayed in the Scan qualification interface listbox. Select one of the following options from this listbox:
 - DDR/LPDDR Chip Select option - to modify the scan qualification for chip select signals.
 - DDR/LPDDR Command and Address option - to modify the scan qualification for command and address signals.
 - DDR Data Read option - to modify the scan qualification for data read signals.
 - DDR Data Write option - to modify the scan qualification for data write signals.
 On selecting the DDR/LPDDR Chip Select option in the previous step, the following fields are displayed for chip select scan qualification:



- 8 For the DDR/LPDDR Chip Select signals, make the appropriate selections based on the active clock enable signals.
On selecting the DDR/LPDDR Command and Address option in the step 7, the following fields are displayed for scan qualification:



- 9 For the DDR/LPDDR Command and Address signals, make the appropriate Memory Configuration selections based on the chip selects used in the DUT.
On selecting the DDR/LPDDR Data Read or Data Write interface in step 7, the following fields are displayed for scan qualification:



- 10 For DDR Data Read or Write signals:
 - g The DUT's Total Read/Write Latency value that you set up in the initial DDR setup is displayed. If needed, modify this value. To find an appropriate value of Total Read/Write Latency, you can set up the Mode Register Settings (MRS) trigger, take a trace, and scan it for latency values.

NOTE

The latency values specified here represent the total latency for your system and therefore should include parameters that affect total latency. For instance, if your system has Additive Latency (AL), then you must include it in the Total Latency values. Similarly, if tDQSS or tDQSK parameters are greater than one full clock cycle, then you must add these values (rounded to the nearest integer) in the Total Latency values.

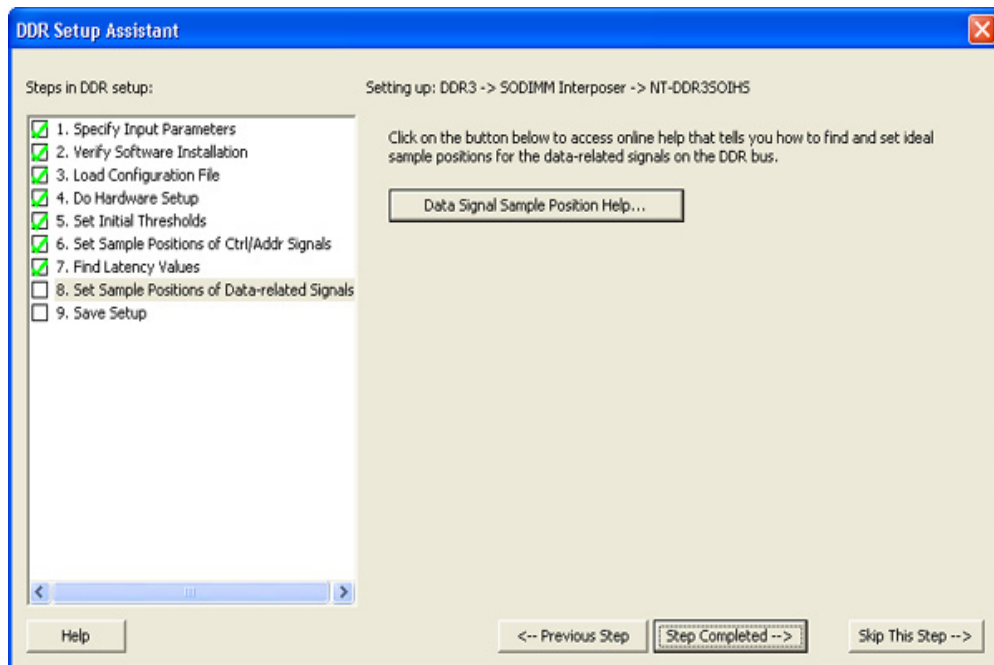
- h* In the Memory Configuration section, choose the appropriate Chip Select(s) for the memory path being traced.
 - i* In the Burst Length field, specify the number of words read or written for each read/write command. To find appropriate value of Burst Length for the DUT, you can set up the Mode Register Settings (MRS) trigger, take a trace, and scan it for burst length.
- 11 Click OK to confirm the settings.
- You can save the modified latency and burst values in the Logic Analyzer .ala or .xml configuration file.

Step - Set Sample Positions of Data-related Signals (not applicable to U4154A/B logic analyzer)

In this step, you set the sample positions of Data signals.

- With the 16960A or 16962A logic analyzers, use DDR3 Eyefinder to set the sample positions of data signals. See ["Your First DDR3 Eyefinder Scan \(16962A logic analyzers only\)"](#) on page 86.
- With the 16950A/B or 16951B logic analyzers, use the logic analyzer's *timing zoom* feature to set the sample positions of data signals. See [Appendix A, "Setting Data Sample Positions with the 1695x Logic Analyzers,"](#) starting on page 125.

This step is not applicable to U4154A/B Logic Analyzer module. For setting the sample positions of Data signals when using the U4154A/B module, refer to the topic ["Step - Set Sample Positions of Data Read/Write \(only applicable to U4154A/B Logic Analyzer\)"](#) on page 67.



After setting the sample positions of Data signals, click **Step Completed -->**.

Next • ["Step - Save Setup"](#) on page 70

Step - Set Sample Positions of Data Read/Write (only applicable to U4154A/B Logic Analyzer)

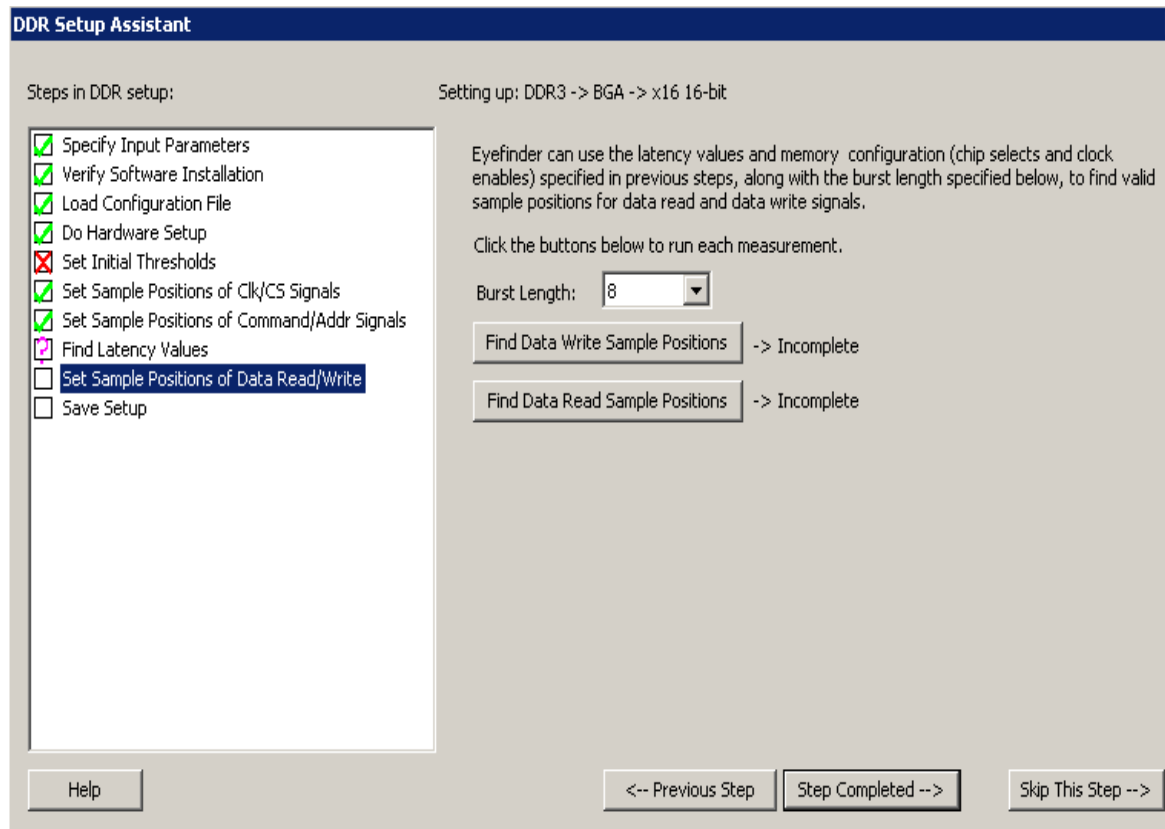
In this step, you set the sample positions of Data signals when using the U4154A/B Logic Analyzer module.

NOTE

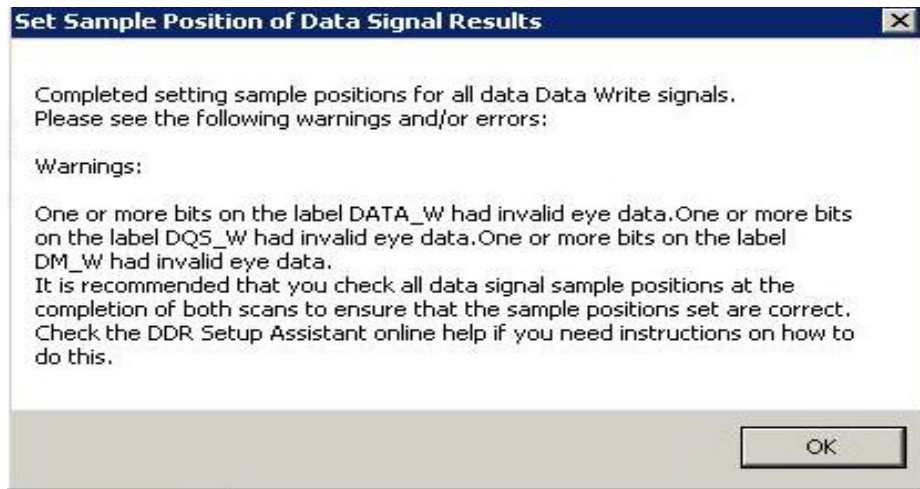
The fields displayed in this step differ if you selected DDR4 bus type in step 1. Therefore, the procedure for setting sample positions for DDR4 Data signals is described separately in this topic.

For this step, DDR Setup Assistant runs the eyescan feature of the U4154A/B Logic Analyzer module to automatically calculate and set the optimal sample positions for the data signals.

- Click Find Data Write Sample Positions to find the optimal and valid sample positions for the data write signals.
- Click Find Data Read Sample Positions to find the optimal and valid sample positions for the data read signals.

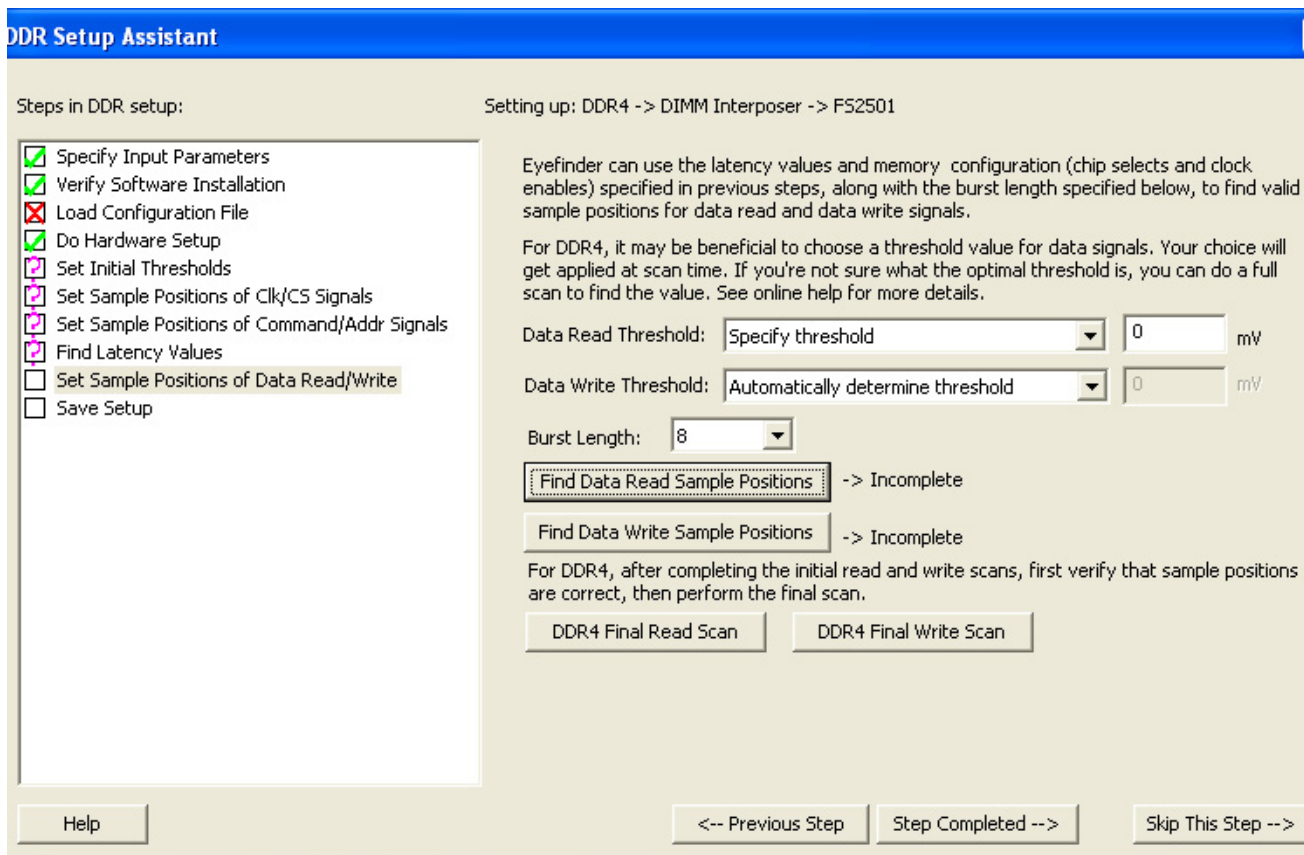


If the eyescan run completes but gives you warnings, you should check the warnings and re-run the eyescan in this step.



After setting the sample positions of Data signals, click Step Completed -->.

To find and set sample positions for DDR4 Data related signals



- 1 Set the threshold for DDR4 data read and write signals. You can set the threshold in either of the following two ways:

- From the Data Read Threshold and Data Write Threshold listboxes, select the Automatically determine threshold option to let DDR Setup Assistant automatically determine the best threshold setting. The middle of the signal swing is used in this case.
- From the Data Read Threshold and Data Write Threshold listboxes, select the Specify threshold option to manually specify the threshold value. This is particularly useful in case of DDR4 signals for which the automatically determined threshold value may not be an ideal threshold to use.

If you selected to manually specify the threshold value for DDR4 data signals, you can determine the best threshold setting by performing the following steps:

- i Access the already open Logic and Protocol Analyzer application. To do this, you need to cancel the "Panel Lock" dialog displayed by DDR Setup Assistant.
 - ii Open the Setup dialog box of the logic analyzer module.
 - iii Click the Sampling tab.
 - iv Click the Eye Scan: Sample Positions and Thresholds button
 - v Click the Data Read measurement tab.
 - vi Click Edit Current Measurement toolbar button and then select Do full time/voltage scan in the Scan tab.
 - vii Click OK.
 - viii Run the eyescan measurement by clicking Run this measurement.
 - ix View the eyescan results to decide which threshold is likely to result in the best eye openings. Note down the threshold value. If required, you can unlock the threshold settings to move the threshold marker.
 - x Click the Data Write measurement tab.
 - xi Repeat steps vi-ix to view threshold for the Data Write measurement.
 - xii Once you have noted down the threshold that would result in best eye openings, click Cancel to cancel the Eye scan - Sample Positions and Threshold Settings dialog.
 - xiii Click Cancel again to cancel the Analyzer Setup dialog.
 - xiv Access the already open DDR Setup Assistant and specify the obtained threshold values in the Data Read Threshold and Data Write Threshold fields.
- 2 Select the Burst Length.
 - 3 Click Find Data Read Sample Positions to find the optimal and valid sample positions for the data read signals based on the specified threshold settings.
 - 4 Click Find Data Write Sample Positions to find the optimal and valid sample positions for the data write signals based on the specified threshold settings.
 - 5 Once you have verified that the obtained sample positions for DDR4 data read and write signals are correct, perform a final scan. You perform a final scan by clicking the DDR4 Final Read Scan and DDR4 Final Write Scan buttons.

A final scan is a comparatively shorter scan than a main scan and is used to perform a final setting to fine tune the obtained sample positions. A final scan verifies that the sample positions are optimal not just for the first bit but for all 8 bits in the burst.

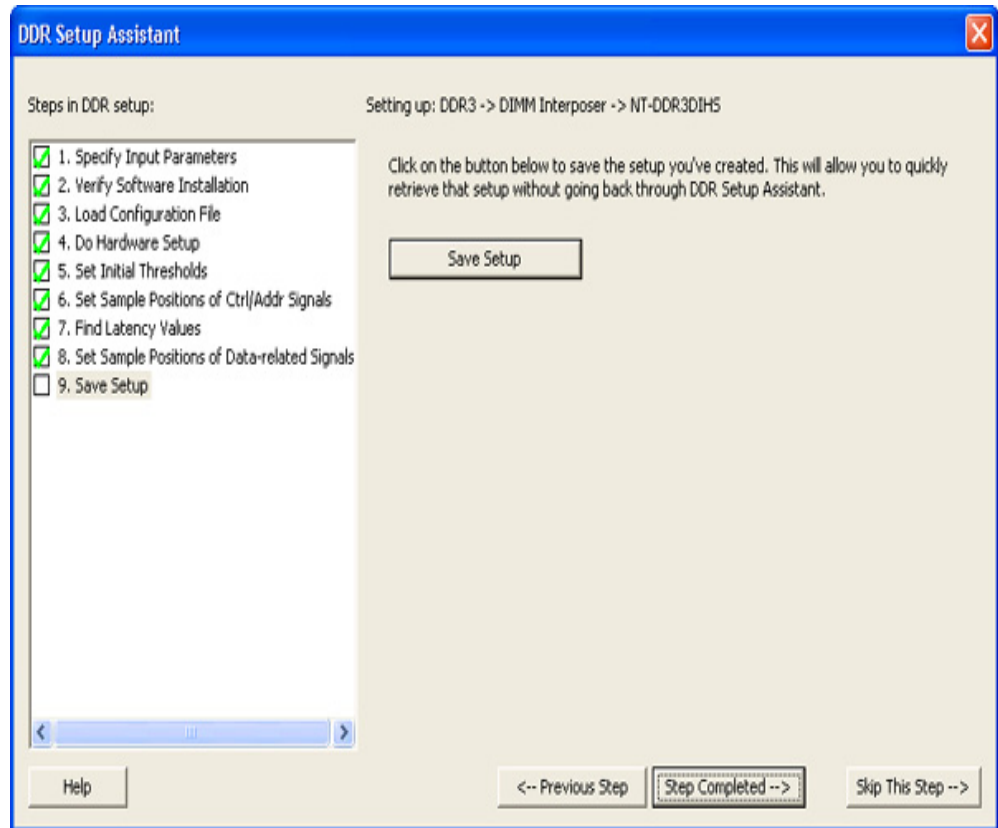
Based on the fine tuning needed, a final scan may result in only a minor change or no change at all to the sample positions.

Next "Step - Save Setup" on page 70

Step - Save Setup

In this step, save your logic analyzer setup so that it can be opened later without having to perform the DDR Setup Assistant steps again..

- 1 Click **Save Setup**.



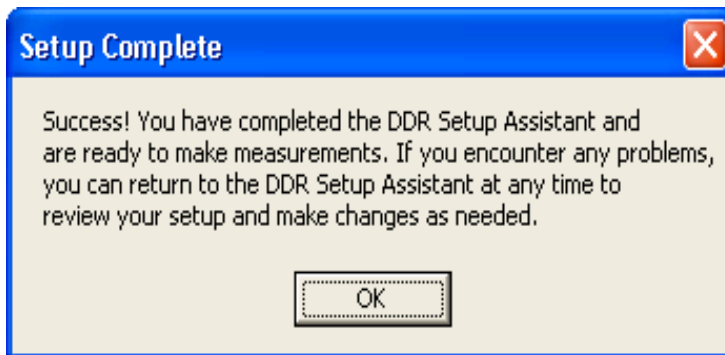
- 2 In the Save Setup dialog, browse to the location where you want to save the setup file, enter the file name, and click **Save**.
- 3 In the message dialog that says the setup was saved successfully, click **OK**.
- 4 Click **OK**.

After saving the configuration, click **Step Completed -->**.

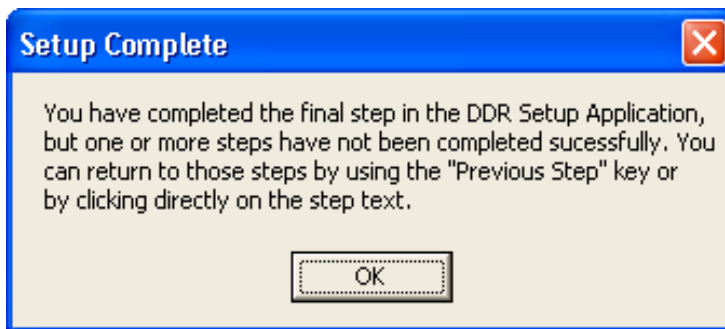
Next • "Setup Complete" on page 71

Setup Complete

After clicking **Step Completed** --> in the last step of the DDR Setup Assistant, you get a Setup Complete message.



The Setup Complete message will tell you if any of the steps still need to be completed.



When the DDR setup is complete, you can use the DDR bus decoder and other tools to analyze captured data.

- See Also**
- ["Setting Up Thresholds and Sample Positions on DDR Address/Control Signals"](#) on page 73
 - ["Using DDR3 Eyefinder"](#) on page 85
 - ["Validating the DDR Setup"](#) on page 117
 - ["Capturing Data \(Triggering\)"](#) on page 119
 - ["Decoding Captured Data"](#) on page 123

4 Setting Up Thresholds and Sample Positions on DDR Address/Control Signals

Setting Up Thresholds and Sample Positions / 74

Solving Problems with Thresholds and Sample Positions Set Up / 78

The Thresholds and Sample Positions dialog in the *Keysight Logic Analyzer* application's sampling setup tab (also known as normal logic analyzer *eye finder*), is used to set the sampling positions of the DDR address and control signals. This is necessary before DDR3 Eyefinder can be used to set the data signal sample positions on 16960A or 16962A logic analyzers.

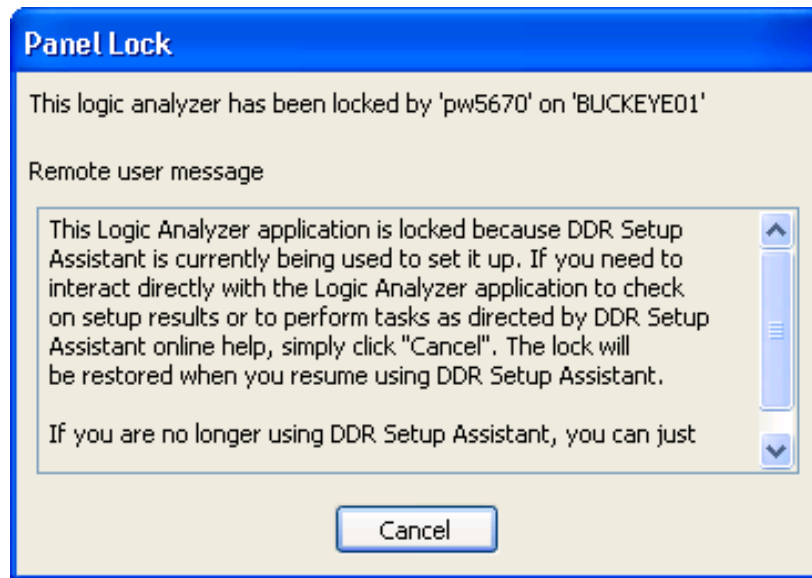
For U4154A/B logic analyzer, the DDR Setup Assistant sets the sampling positions on DDR command, address, and data read and write signals using the U4154A/B eyescan feature. This feature is also available in the Keysight Logic Analyzer application. You can also set the threshold and sample positions on individual channels of U4154A/B using the Eye Scan - Sample positions and Threshold Settings dialog box accessible by clicking the Eye scan: Sample Positions and threshold button in the Sampling tab of the Setup dialog box.

The DDR Setup Assistant runs the Thresholds and Sample Positions set up for you; however, it may run into some problems that require you to open and re-run the set up.

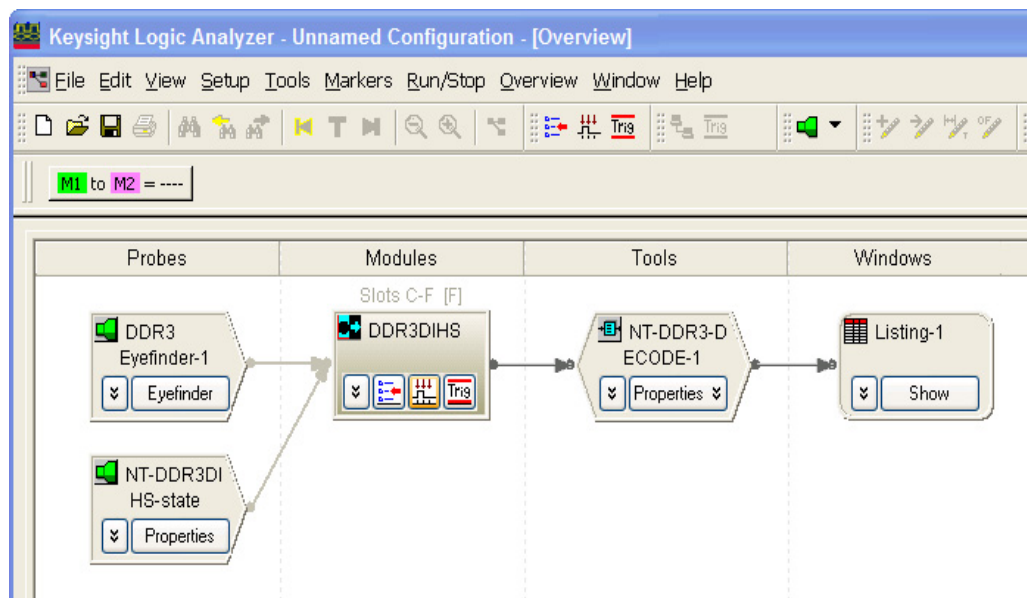
Setting Up Thresholds and Sample Positions

The Thresholds and Sample Positions set up (also known as normal logic analyzer *eye finder*) is used to set the sampling positions of the DDR address and control signals. This is necessary before DDR3 Eyefinder can be used to set the data signal sample positions (on 16962A and 16960A logic analyzers).

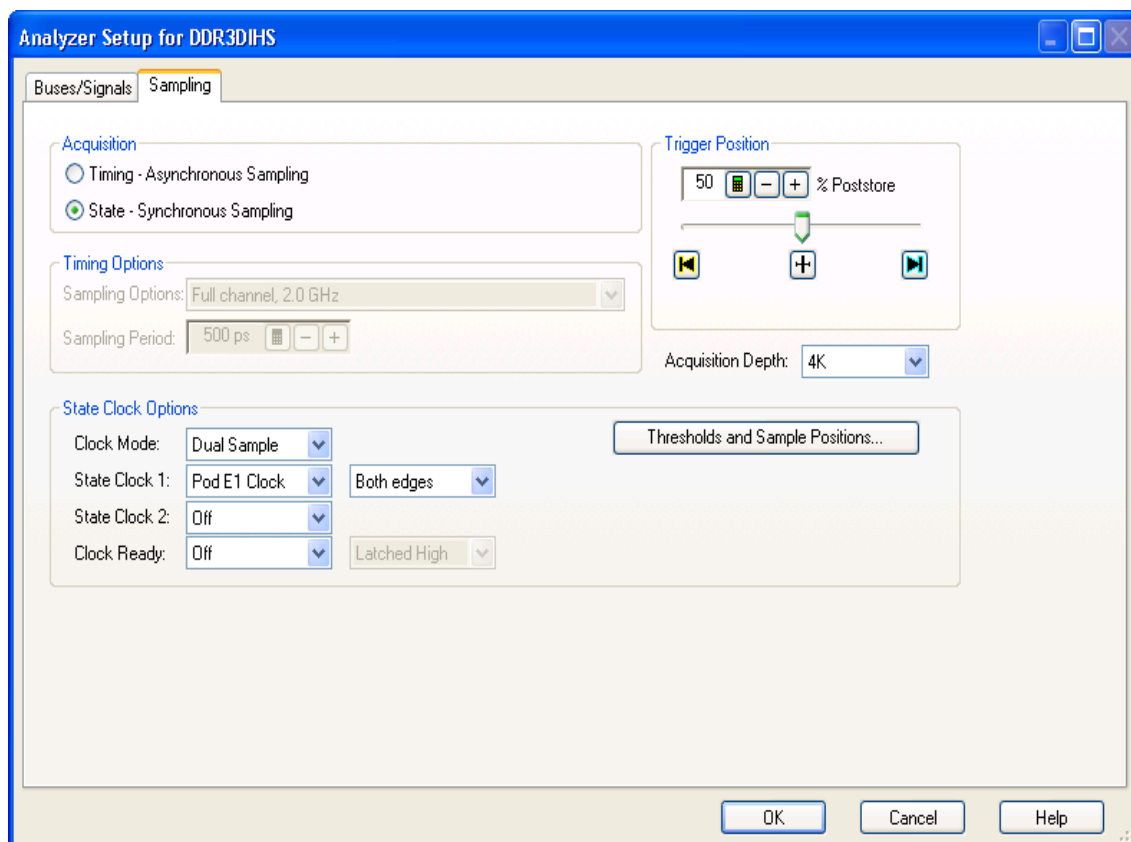
- 1 Go to the *Keysight Logic Analyzer* application.
- 2 If you are currently using the DDR Setup Assistant, you may have to click **Cancel** in the Panel Lock dialog.



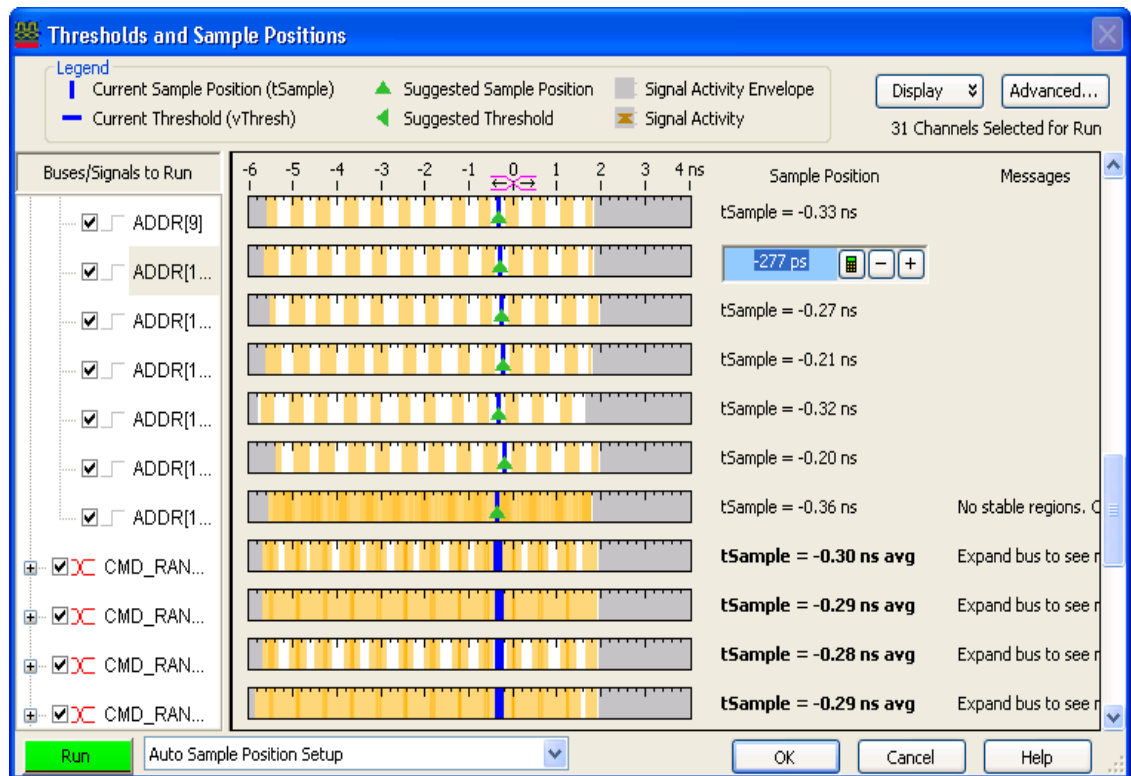
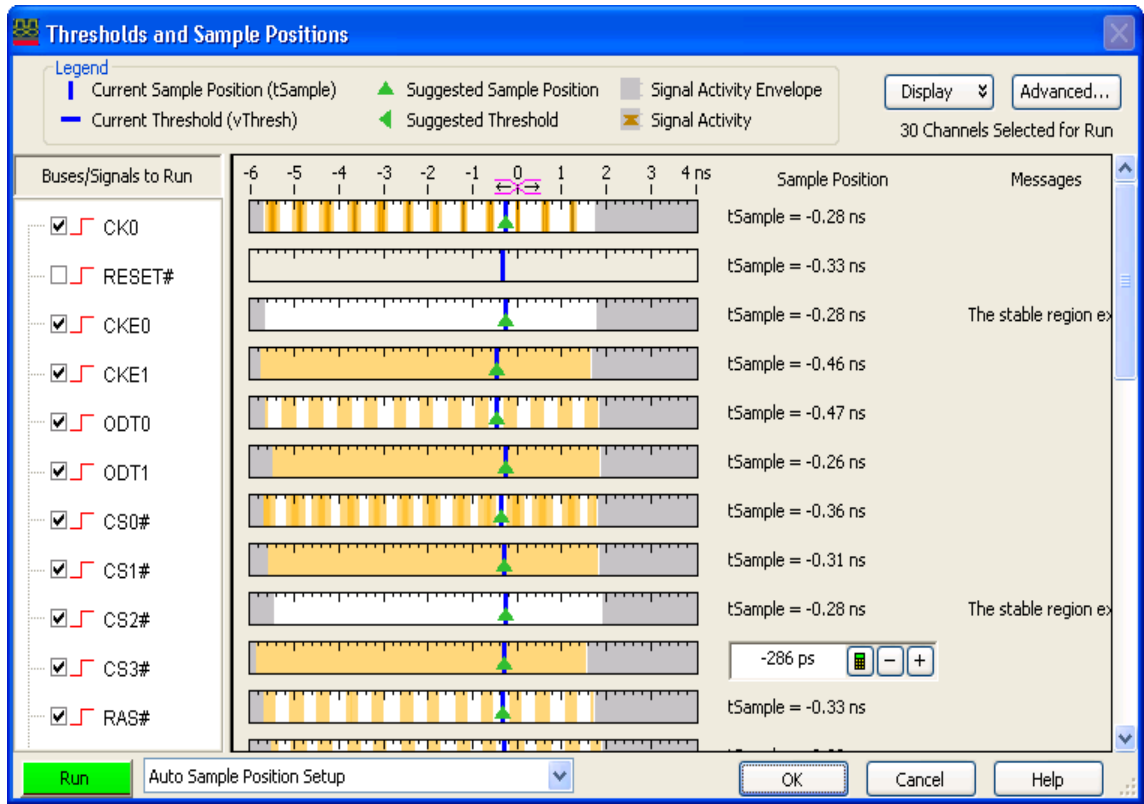
- 3 In the *Keysight Logic Analyzer* application, click the  Sampling Setup icon.



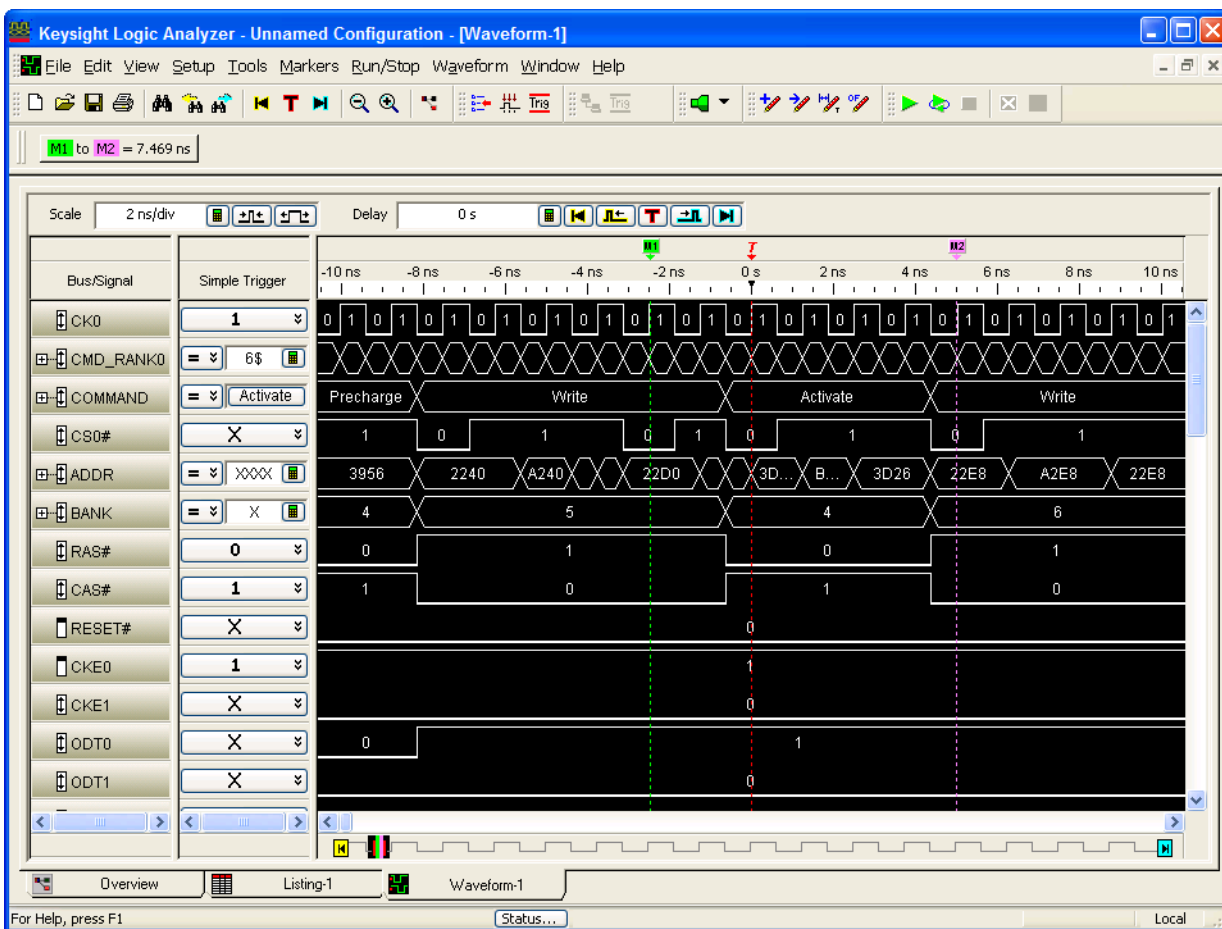
- 4 In the Sampling Setup dialog, click **Thresholds and Sample Positions...**



- 5 In the Thresholds and Sample Positions dialog, make sure the address and control signal sample positions are aligned.
- 6 If necessary, click **Run** to rerun the Thresholds and Sample Positions set up. The resulting sampling positions should be aligned and just left of zero (0).



- Take a trace to ensure that Command, CK, BANK, and ADDR are sampled correctly.



Because we are sampling on both the rising and falling edges of CK, you want to check that the rising edge of CK must be in the middle of CS# low.

Solving Problems with Thresholds and Sample Positions Set Up

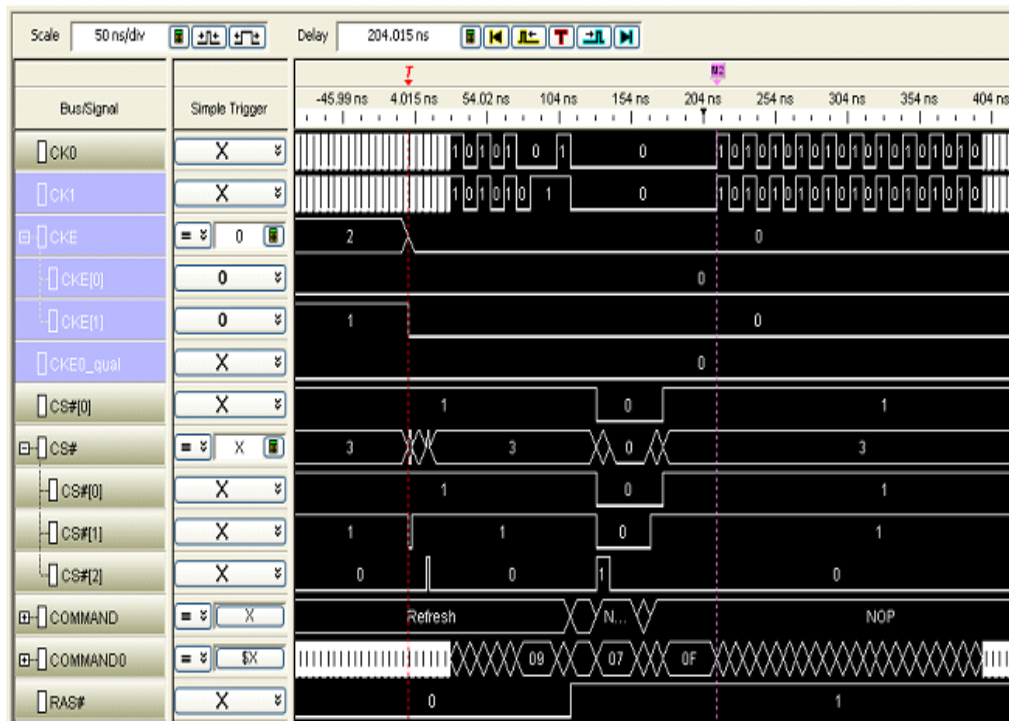
- “Clock edges "too close together" error message on Run" on page 78
- “Determining Correct Sample Position on Eyes that are Closing" on page 80
- “Determining Read and Write latencies using Timing Zoom" on page 82

Clock edges "too close together" error message on Run

Possible causes and solutions:

Possible Cause:	Possible Solution:
Poor signal integrity on clock signal.	Check the clock signal quality by sampling the signal in timing mode, by using the logic analyzer Thresholds and Sample Positions set up in state mode, or by using an oscilloscope.
You are attempting to take a trace on a system with CK0 turning off and on	You can use the Clock Hysteresis feature provided by the U4164A logic analyzer modules and 16860A-series logic analyzers. To know more about this feature, refer to the <i>Logic and Protocol Analyzer Online Help</i> .
You are attempting to take a trace from reset.	In the sampling setup, set Clock Ready to latch high on CKE0.
Power management (clocks tri-state).	<p>Try these steps:</p> <ol style="list-style-type: none"> 1 You can use the Clock Hysteresis feature provided by the U4164A logic analyzer modules and 16860A-series logic analyzers. Typically a setting of 120 - 140 mV works well in DDR4 and LPDDR4 systems. To know more about this feature, refer to the Logic and Protocol Analyzer Online Help. 2 To verify the issue, in timing mode, Trigger on both CKE = low. Check if the clock appears to stop or tri-state when both CKEs are low. 3 For logic analyzers other than the U4164A or 16860A series, that do not provide the clock hysteresis feature, change the CK0 threshold voltage setting from "differential" to 50 mV. This helps prevent the Clock edge error message as CK0 fluctuates at 0 V during tri-state. 4 Or, disable Power Management mode in target BIOS. 5 Or, use Clock Ready set to Enable High. (For older interposers, this works for single rank DIMMs if used on Dual Rank DIMMs. Some data from CKE1 rank could be lost when CKE0 is low when CKE1 isn't low. Some FuturePlus interposers OR the CKE0 and CKE1 signals which is good for Dual and Quad Rank DIMMs.) 6 Or, consider using a Timing mode on your logic analyzer with sampling resolution appropriate for the data rate you are probing. Probing solutions vary for different Timing modes. Please refer to your logic analyzer and probing user manuals for details.

What to Expect if Clocks Tri-State



When CKE and CKE1 are both low – system enters self refresh – clocks will turn off.

When the clock tri-states, the Waveform display will be different:

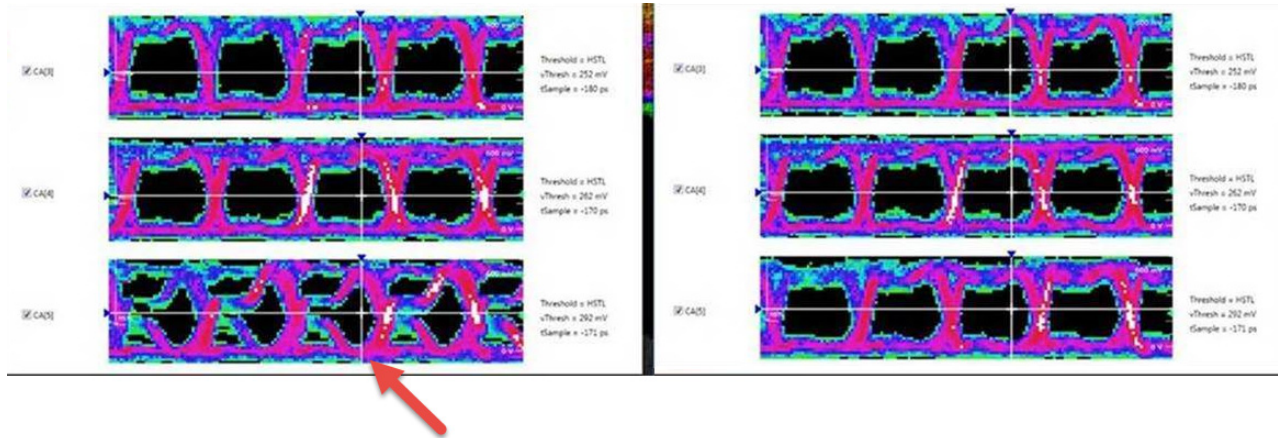
- Time tags will be wrong for approximately 40 cycles before and after the clock tri-states.
- However, sampled data is accurate.
- The DDR Bus Decoder decodes self refresh and power down modes.
- The Listing display may be preferred in this situation.

Determining Correct Sample Position on Eyes that are Closing

The signal integrity (SI) of the device under test, routing of logic analyzer probing, and probing limitations can influence DDR Eyescans generated in the Logic and Protocol Analyzer GUI.

Example 1

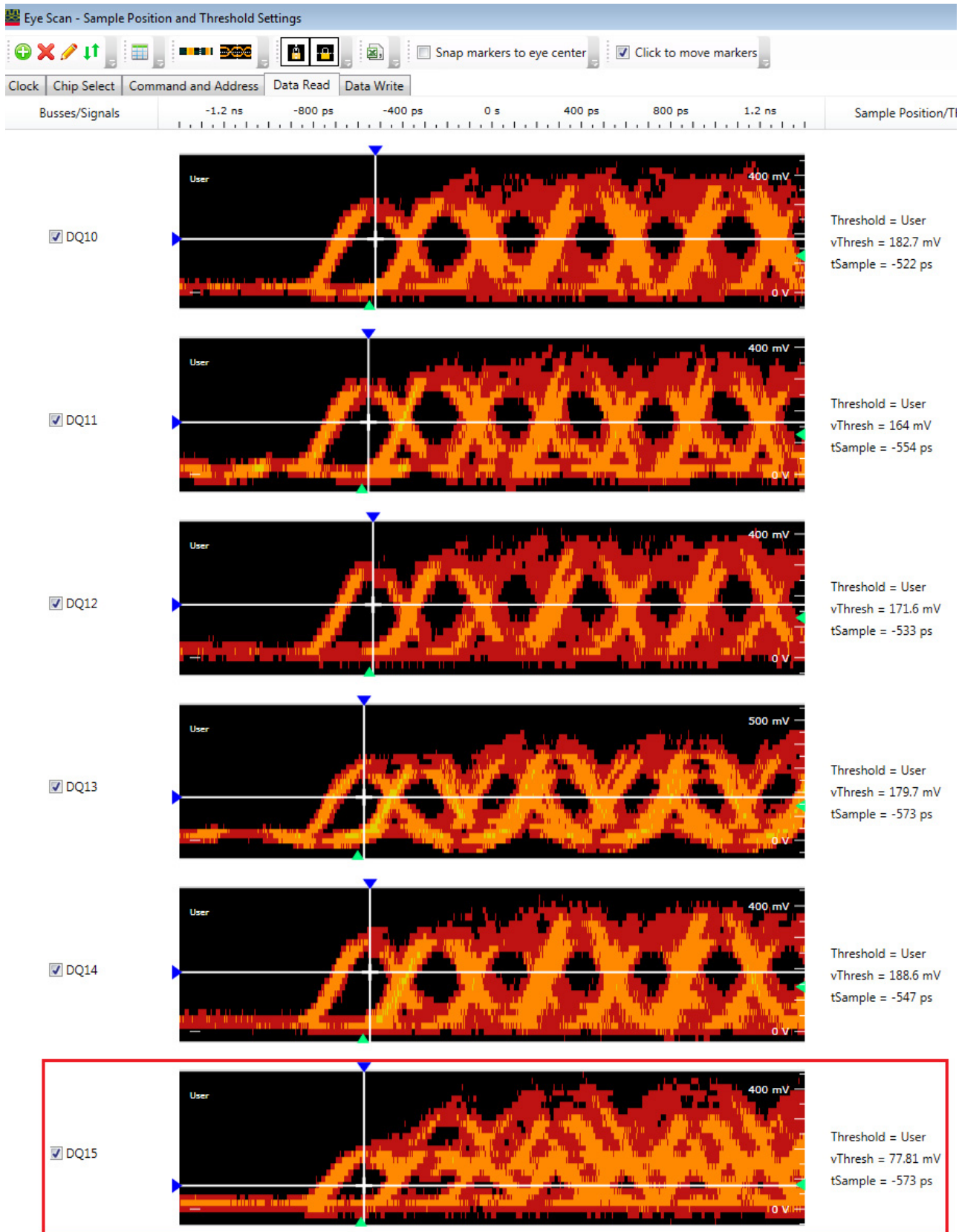
In the example below, although DUT SI or probing irregularities may have closed the eye for CA(5) somewhat, valid state mode sampling is still possible anywhere in the open (black area) of the eye indicated with the cross hatch.



Example 2

In the example screen shown on the next page, a 3200 MT/s READ DQ signal trace mode scan is displayed. In this scan, it will be difficult to tune DQ15 for error free capture. The white time and voltage markers cross at the suggested sample positions for each DQ. If you encounter results like those shown in the example screen on the next page, and the system under test is running error free, and the probe is a BGA interposer, the issue is most likely in probing limitations. Results might be improved by removing the probing and then cleaning and reseating the probe connection to the BGA interposer. (Please refer to the user guide for your specific probe.) Or a scope can be used to access bottom-side vias on the probed DRAM to validate integrity of the signals to the DRAM and confirm that the closure is only in the probing signal path to the logic analyzer.

Individual suspect signals on scans from a DIMM interposer typically indicate damage to components on the interposer.

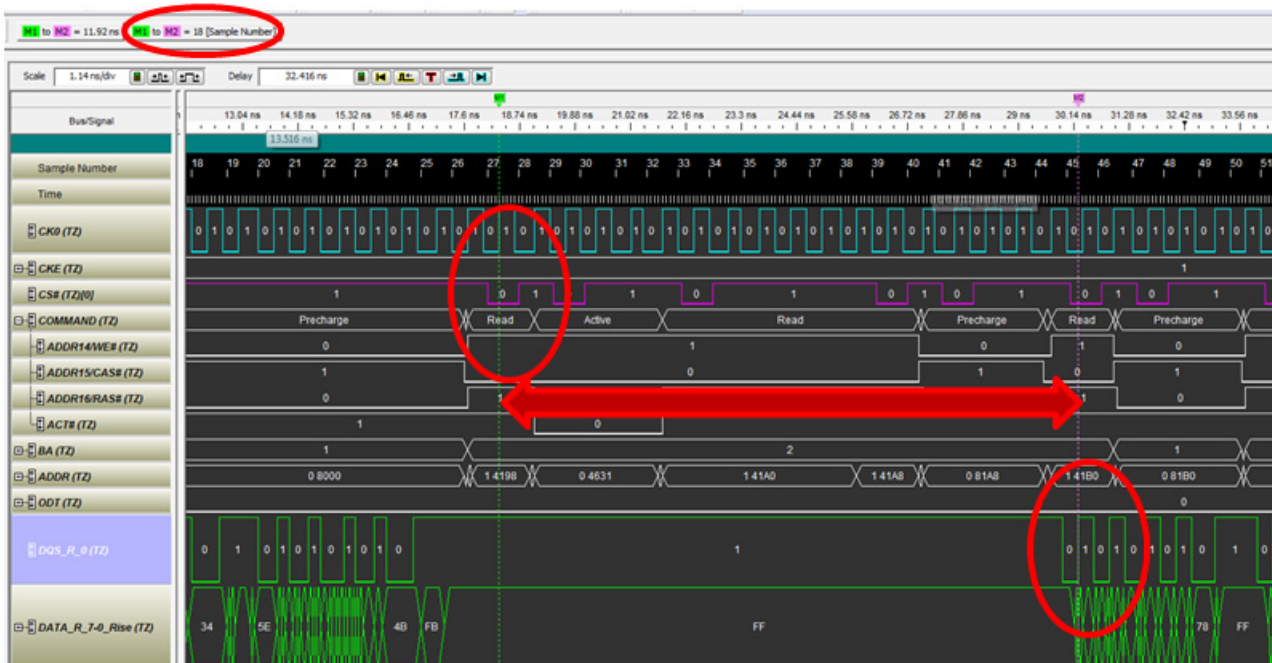


Determining Read and Write latencies using Timing Zoom

You can use the *Timing Zoom* feature of logic analyzers to determine the Total Read or Total Write Latency of a DDR/LPDDR system.

- 1 Locate a valid command. The command should not be back to back so that you can determine where the burst starts by viewing DQS0.
- 2 Place a marker at the rising edge of CK0 while CS#0 is low (represented as M1 in the example screen below)
- 3 Place another marker at the first rising edge of DQS0 (represented as M2 in the example screen below)
- 4 Make a marker measurement of samples between the two markers (M1 and M2 in the example screen below) on the Sample label. The total latency is represented by the number of samples *.

In the example screen below, 18 is the Read latency.



NOTE

* The total latency is represented by the sample rate when the logic analyzer configuration is sampling on just one edge of CK0 for operation above 2500 MT/s. The total latency is represented by 1/2 of the sample rate when the logic analyzer configuration is sampling on both edges of CK0 for configurations that support data rates below and up to 2500 MT/s.

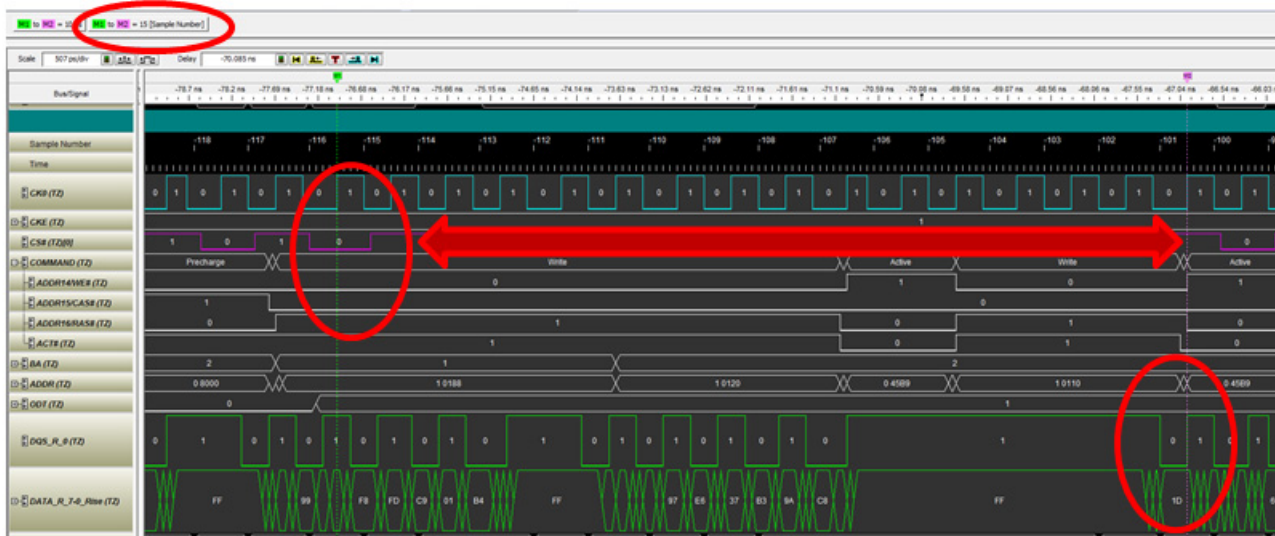
NOTE

The number of samples between the markers is same as the total latency when operating over 2500 MT/s and sampling on a single clock edge.

The number of samples between the markers is double the total latency when operating under 2500 MT/s and sampling on both edges.

In the example screen below, for the same configuration, a marker measurement of samples between the two markers M1 and M2 for the Write command has been made. The Write latency is represented by the number of samples, which is 15 in the example screen below.

Notice that we can use either the DQS_W TZ or DQS_R TZ labels for the Write latency measurement, since the Read and Write labels are just double probed copies of the same signal when in TZ.



5 Using DDR3 Eyefinder

Getting Started with DDR3 Eyefinder (for 16962A/16960A) / 86

Setting Scan Options / 97

Performing Scans / 103

Setting Sample Positions / 104

Viewing Signal Swing vs. Time / 109

Solving DDR3 Eyefinder Problems / 110

DDR3 Eyefinder is similar to the logic analyzer Thresholds and Sample Positions set up (also known as normal logic analyzer *eye finder*) except that it is specifically designed to find DDR3 data signal eyes, given the relationship between DDR3 control/address signals and data signals. DDR3 Eyefinder also provides additional features to help you locate data signal eyes and properly set sample positions, including the ability to analyze scan data using different scales, color schemes, and filtering.

NOTE

DDR3 Eyefinder can be used with the 16960A and 16962A logic analyzers. It cannot be used with the 16950A/B logic analyzers.

DDR3 Eyefinder is unable to perform threshold scans when used with the 16960A logic analyzer, and only time scans are available.

See Also

- Logic analyzer Thresholds and Sample Positions set up ("To automatically adjust state sampling positions and threshold voltages" (in the online help))

Getting Started with DDR3 Eyefinder (for 16962A/16960A)

- “Before Running DDR3 Eyefinder” on page 86
- “Your First DDR3 Eyefinder Scan (16962A logic analyzers only)” on page 86

Before Running DDR3 Eyefinder

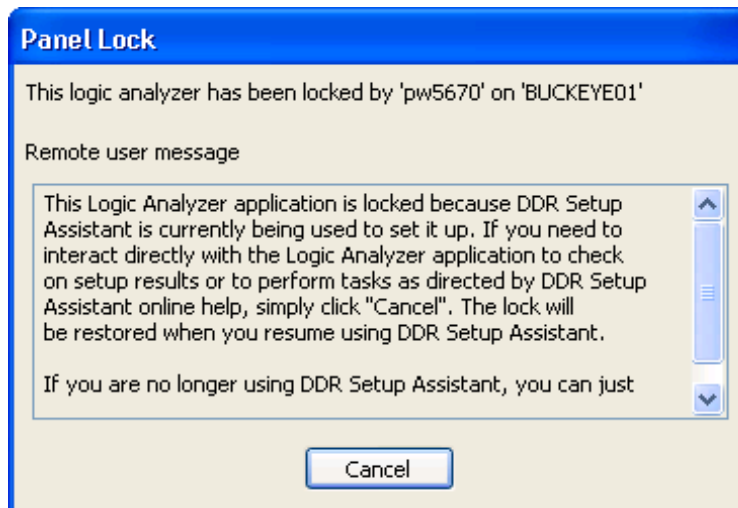
Before running DDR3 Eyefinder, you must set the sample positions for the control/address signals using the DDR Setup Assistant (see “Using the DDR Setup Assistant” on page 37) or the logic analyzer Thresholds and Sample Positions set up (also known as normal logic analyzer *eyefinder*, see “To automatically adjust state sampling positions and threshold voltages” (in the online help)).

After setting the control/address signal sample positions, you can set up and run DDR3 Eyefinder scans.

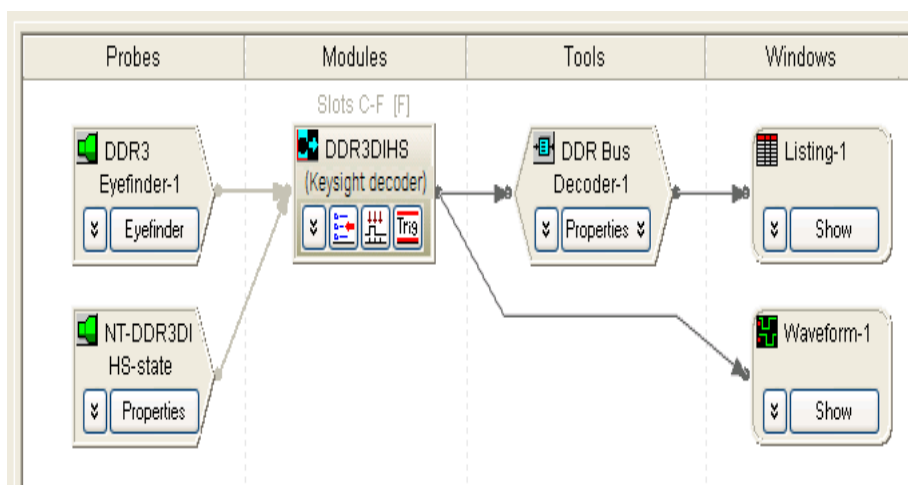
Your First DDR3 Eyefinder Scan (16962A logic analyzers only)

We recommend your first DDR3 Eyefinder scan be a “threshold” scan to give you a good first picture of the signal eyes and proper sampling positions. This type of scan can take about an hour to complete, but the results are worthwhile.

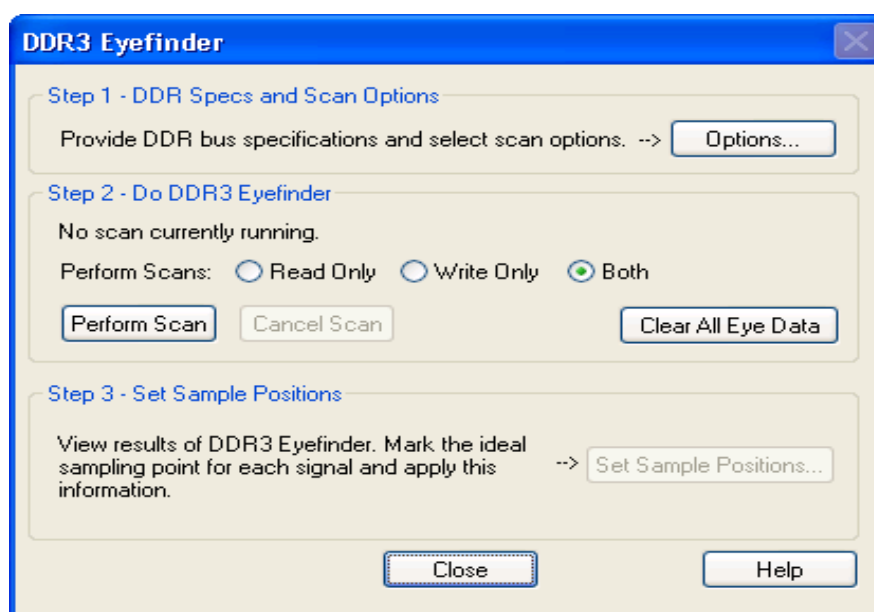
- 1 Go to the *Keysight Logic Analyzer* application.
- 2 If you are using the DDR Setup Assistant, you may have to click **Cancel** in the Panel Lock dialog.



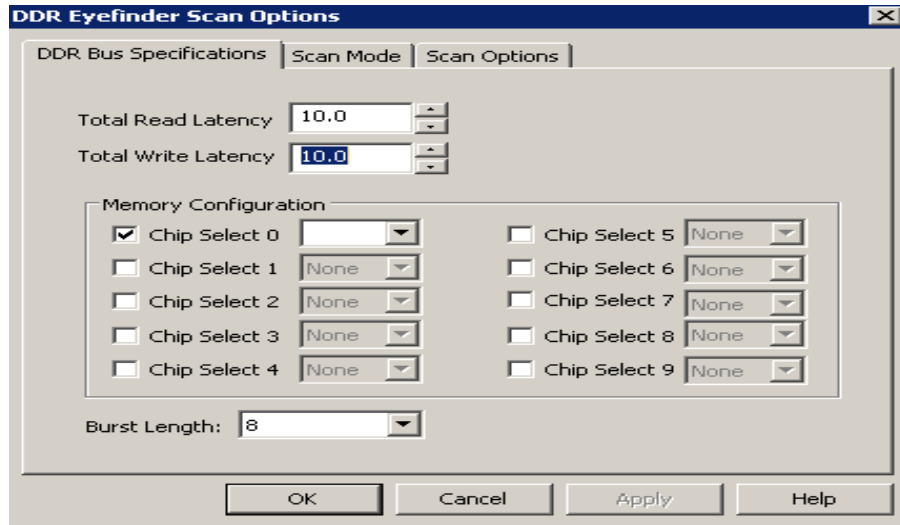
- 3 In the *Keysight Logic Analyzer* application, click the **Overview** tab (or the System Overview icon) to view the Overview window.
- 4 In the DDR3 Eyefinder probe (in the column on the left), click the **Eyefinder** button.



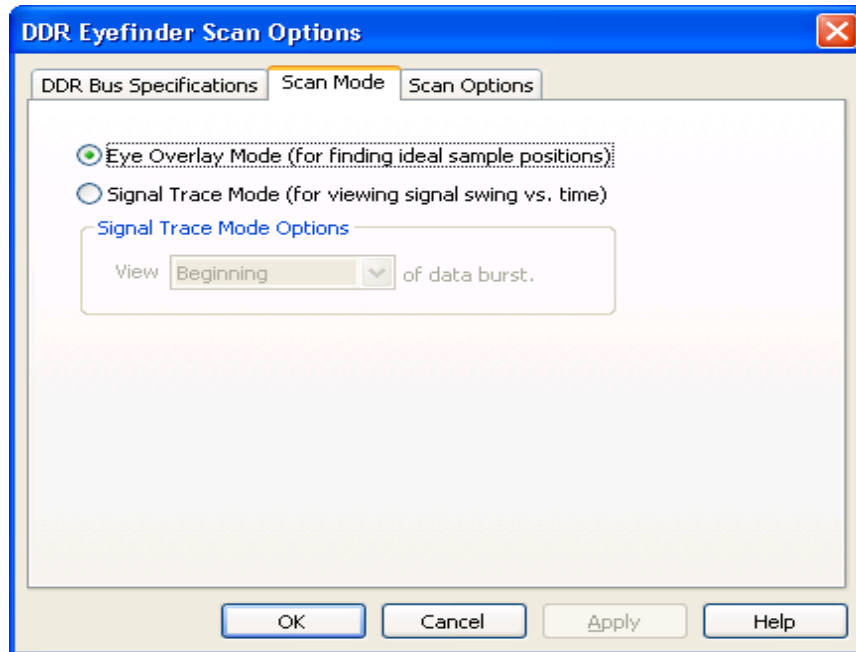
5 In the DDR3 Eyefinder dialog, first provide the scan values:



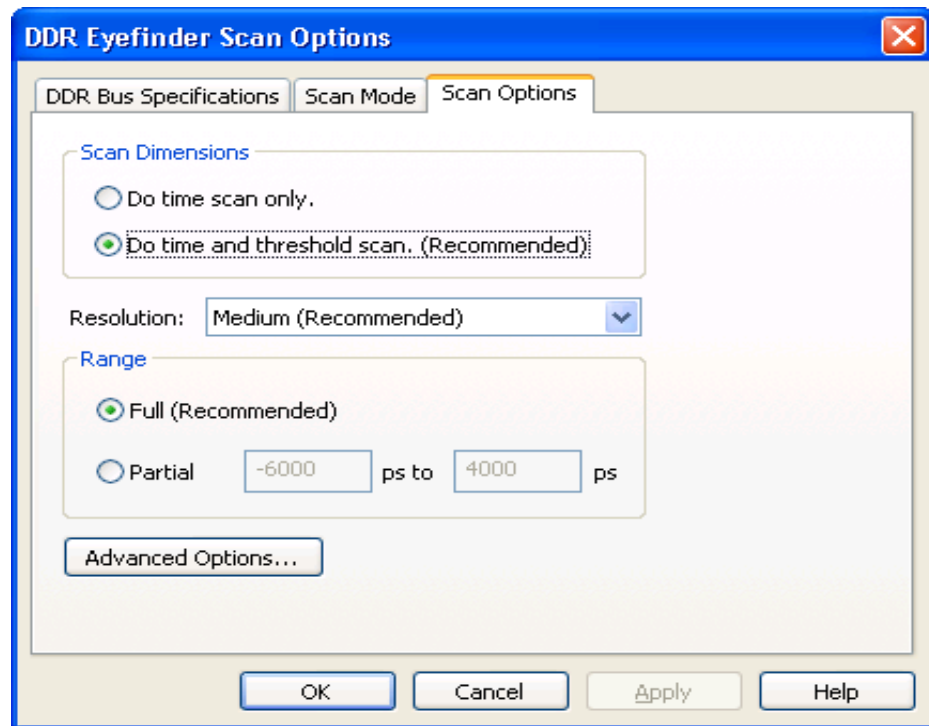
- a Click **Options...**
- b In the DDR Eyefinder Scan Options dialog's DDR Bus Specifications tab, enter the appropriate **Total Read Latency**, **Total Write Latency**, **Memory Configuration**, and **Burst Length** values.



- If you do not know the appropriate values for your device under test, you can find the appropriate scan values using an Mode Register Settings (MRS) trigger as described in [“Step - Find Latency Values”](#) on page 55 and [“Setting Latency Values in DDR3 Eyefinder”](#) on page 61.
- c In the **Scan Mode** tab, use the recommended settings (eye overlay mode).



- d In the **Scan Options** tab, use the recommended settings (time and threshold scan, medium resolution, and full range).

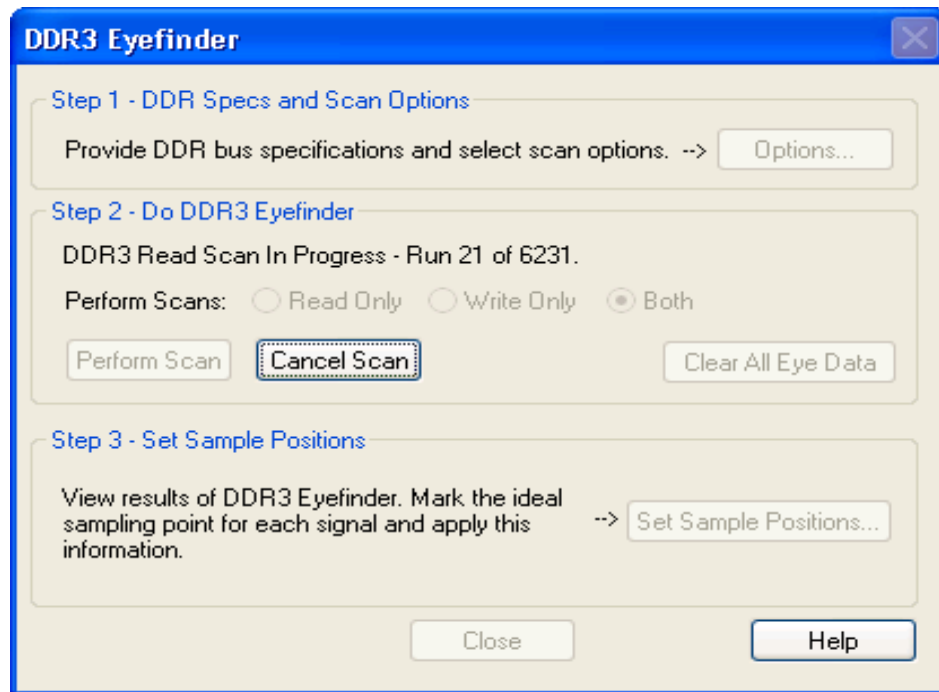


e Click **OK** to save the scan values/options and close the dialog.

For more information on setting scan values and options, see ["Setting Scan Options"](#) on page 97.

- 6 Back in the DDR3 Eyefinder dialog, select **Both** read and write scans; then, click **Perform Scan** to run DDR3 Eyefinder scan.

As configured in the previous steps, the scan takes over an hour to complete. The DDR3 Eyefinder run status is shown in the dialog.



For more information on performing scans, see [“Performing Scans”](#) on page 103.

- 7 After the read and write scans complete, click **Set Sample Positions...** to view the scan results and set the sample positions.
- 8 In the Set Sample Positions dialog:

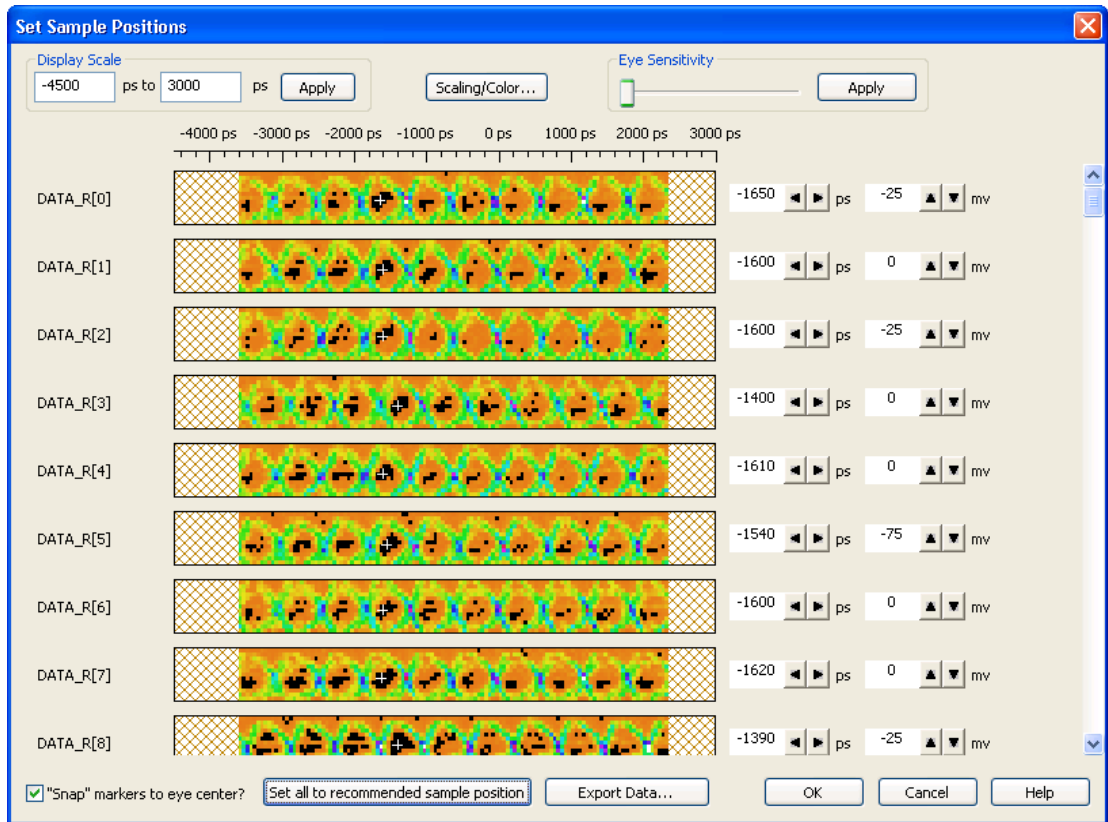


- a Click **Set all to recommended sample position**.

The white crosshair markers show the recommended sample positions (see the following example).

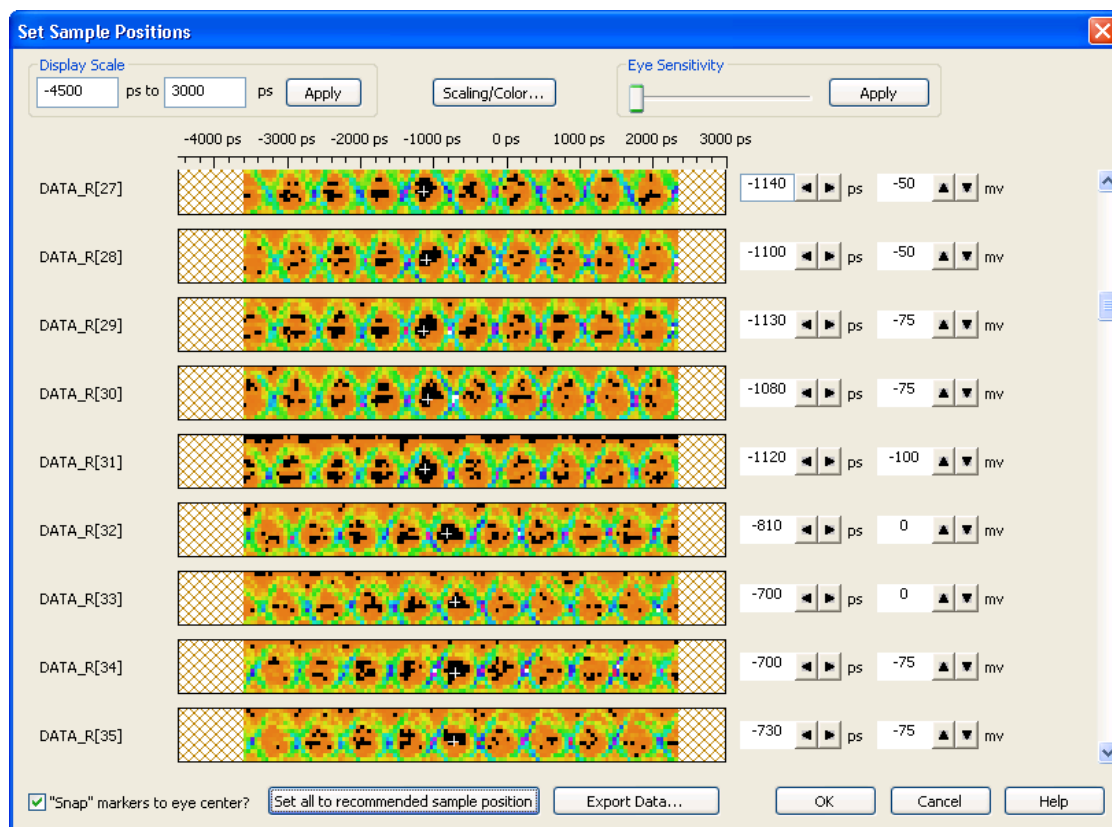
CAUTION

Recommended sample positions might be at incomplete eyes nearest the last sample position settings. Always visually inspect the results of setting all to the recommended sample positions (see the next step).

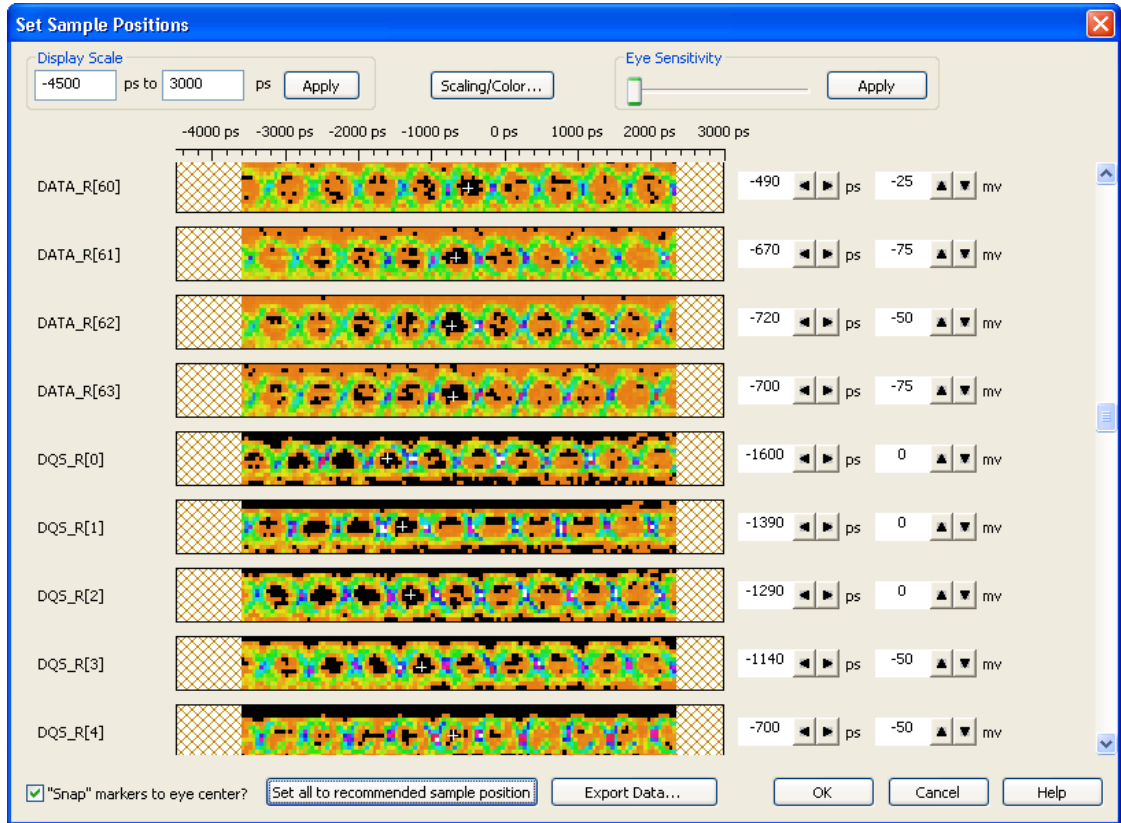


- b Scroll through the signals and adjust sample positions as necessary. You can uncheck the **"Snap" markers to eye center?** option for greater control over the sample position placement.
- Single-click to move to center of suggested eyes.
 - When there is only one obvious eye, pick that eye.
 - If there are problems, see ["Solving DDR3 Eyefinder Problems"](#) on page 110.

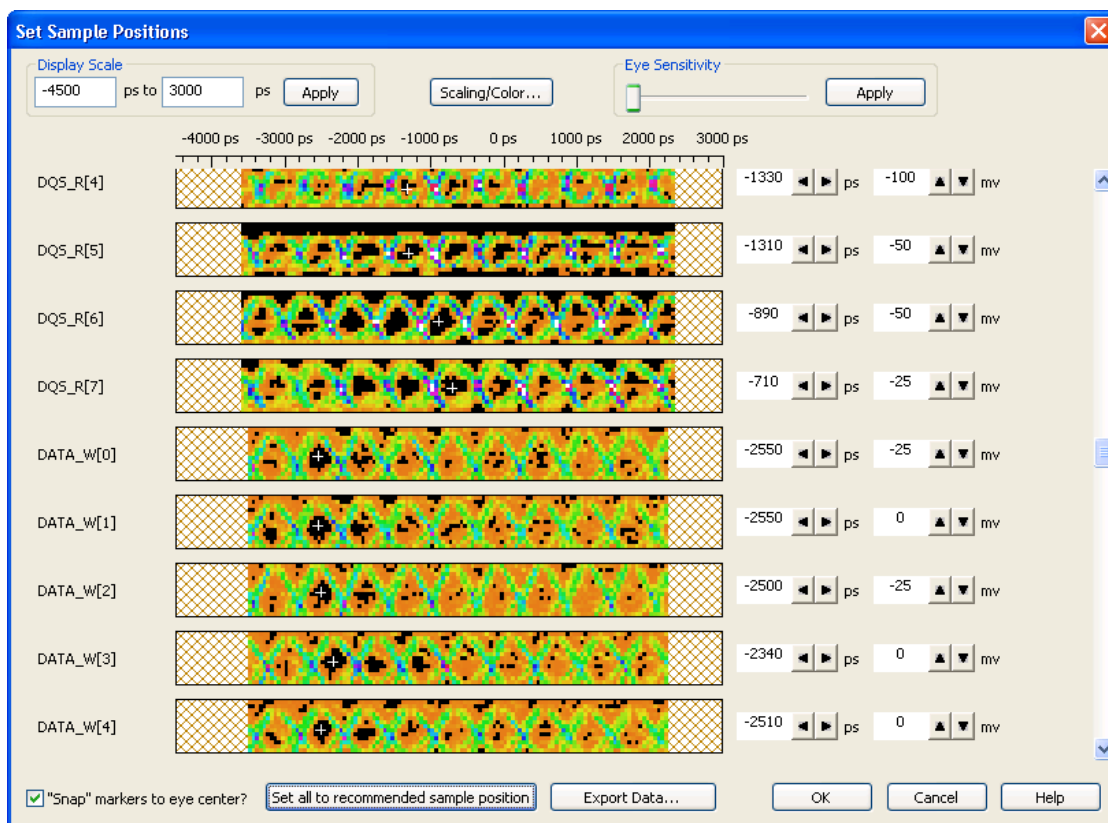
Take note of the eye positions for each group of eight signals. You may notice *byte shifts* on eight bit boundaries as shown in the following example.



It's important to note the eye positions for each byte lane (set of eight signals) because the strobe signal eyes are roughly at the same position as the corresponding byte lane. Knowing this can help you select the correct eyes for the strobe signals. The following example shows strobe eye position differences.

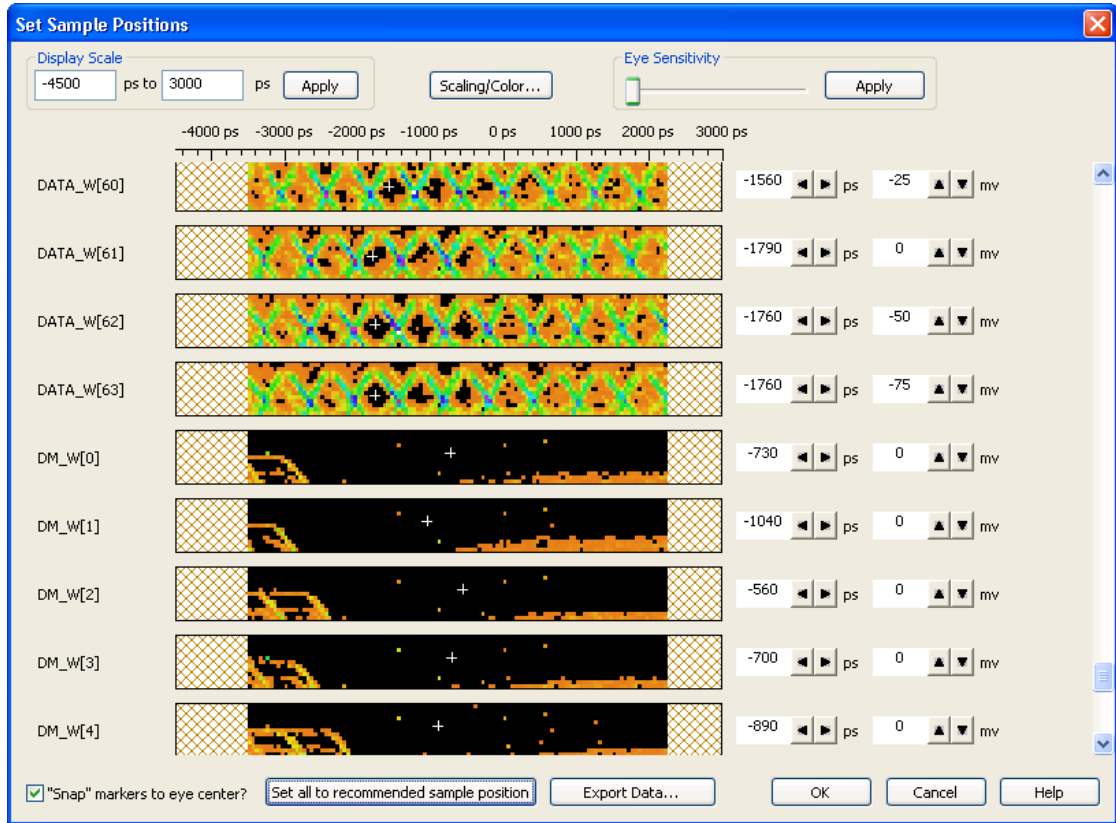


Data write signal eyes appear in different positions than data read signal eyes, as shown in the following example.

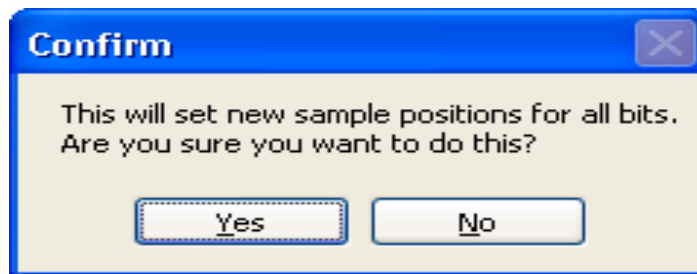


Sometimes for data read or write signals, two eyes appear. You can use the **Do not store back-to-back memory bursts** advanced scan option to prevent this (see ["Setting Advanced Scan Options"](#) on page 101). Higher resolution scans will also help clear up uncertainties.

You may notice signals that are not used, as in the following example.



- c When you are done setting sample positions, click **OK**. Then, click **Yes** in the confirmation dialog.



- d In the message dialog that says the sample positions have been successfully applied, click **OK**.
- 9 Click **Close** to close the DDR3 Eyefinder dialog.

If you are running the DDR Setup Assistant, you have completed “[Step - Set Sample Positions of Data-related Signals \(not applicable to U4154A/B logic analyzer\)](#)” on page 66. Return to the DDR Setup Assistant, and continue with “[Step - Save Setup](#)” on page 70.

After running DDR3 Eyefinder to set sample positions for read and write signals, you are ready to capture DDR3 traces with the logic analyzer.

- See Also**
- “[Setting Scan Options](#)” on page 97
 - “[Performing Scans](#)” on page 103
 - “[Setting Sample Positions](#)” on page 104
 - “[Solving DDR3 Eyefinder Problems](#)” on page 110

Setting Scan Options

The first step in using DDR3 Eyefinder is to set the scan values and options. In the DDR Eyefinder Scan Options dialog, there are tabs for:

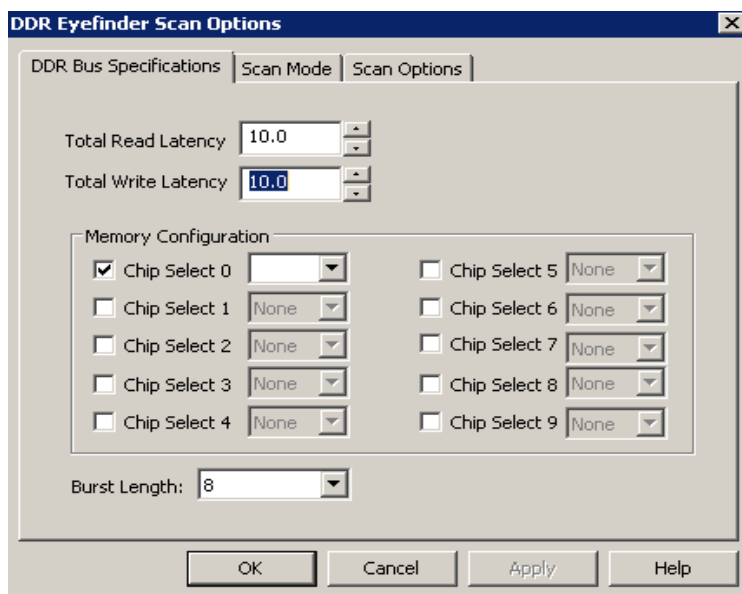
- “Setting DDR Bus Specifications” on page 97
- “Setting Scan Options” on page 99
- “Setting Scan Mode” on page 98

There is also a dialog for:

- “Setting Advanced Scan Options” on page 101

Setting DDR Bus Specifications

In the DDR Eyefinder Scan Options dialog's DDR Bus Specifications tab, you enter the basic characteristics of the DDR bus.

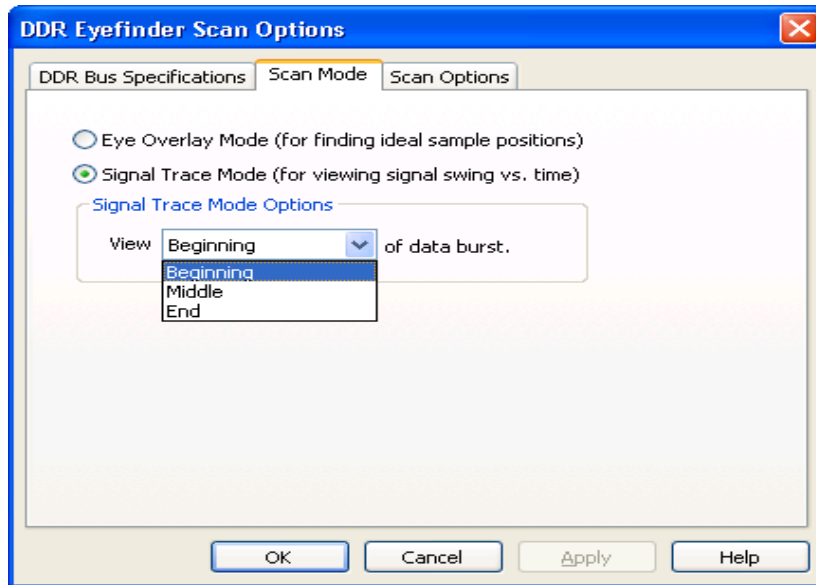


Field	Description
Total Read Latency	The total number of clock cycles from the valid Read command to valid data.
Total Write Latency	The total number of clock cycles from the valid Write command to valid data.
<p>Note: The latency values that you specify here represent the total latency for your system and therefore should include parameters that affect total latency. For instance, if your system has Additive Latency (AL), then you must include it in the Total Latency values. Similarly, if tDQSS or tDQSK parameters are greater than one full clock cycle, then you must add these values (rounded to the nearest integer) in the Total Latency values.</p>	
Memory Configuration	Make the appropriate Memory Configuration selections based on the chip selects used in the device under test.
Burst Length	This is the number of words read or written for each read/write command.

You can find the appropriate values for **Total Read Latency**, **Total Write Latency**, and **Burst Length** using an Mode Register Settings (MRS) trigger as described in “[Step - Find Latency Values](#)” on page 55 and “[Setting Latency Values in DDR3 Eyefinder](#)” on page 61.

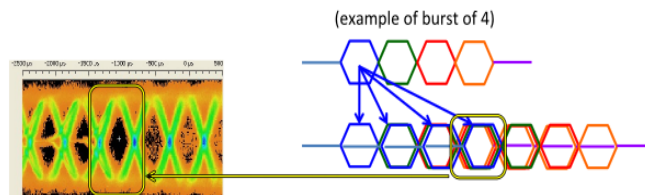
Setting Scan Mode

In the DDR Eyefinder Scan Options dialog's Scan Mode tab, you can specify the scan mode.



Scan Mode	Use
Eye Overlay Mode	Use this mode when setting sample positions for data signals. In this mode, DDR3 Eyefinder overlays the eyes for each bit in a burst in order to show a composite eye, without tri-state or noise, that helps you locate the best sample position.

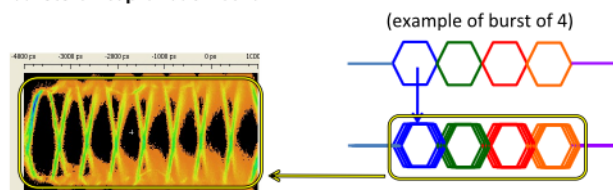
Eye Overlay Mode: Overlaying each bit of 4, 8, or 16 bursts on top of each other



Signal Trace Mode

Use this mode for viewing signal swing vs. time. Although sample positions can be checked and modified in this mode, it is generally not recommended. In this mode, DDR3 Eyefinder overlays complete bursts in order to provide additional qualitative insight into the signal integrity on the DDR system at the logic analyzer probe location.

Signal Trace Mode: Overlaying multiple captures of 4, 8, or 16 bursts on top of each other



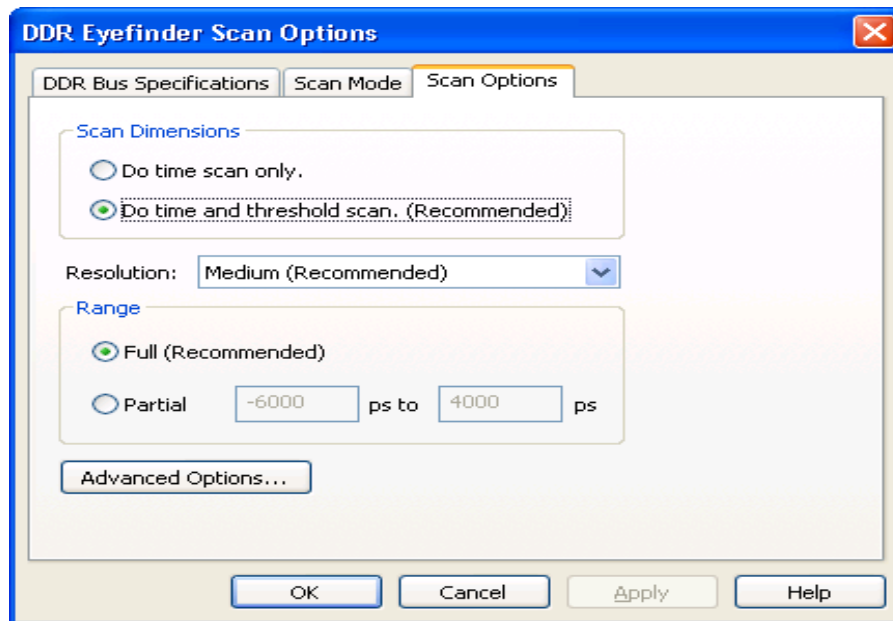
When the Signal Trace Mode is selected, you can select from these data burst areas to view:

- **Beginning**– Scans are made at the beginning of a data burst.
- **Middle**– Scans are made at the middle of the data burst.
- **End**– Scans are made at the end of the data burst.

For more information, see [“Viewing Signal Swing vs. Time”](#) on page 109.

Setting Scan Options

In the DDR Eyefinder Scan Options dialog's Scan Options tab, you can specify the scan type, the scan resolution, and the scan range.

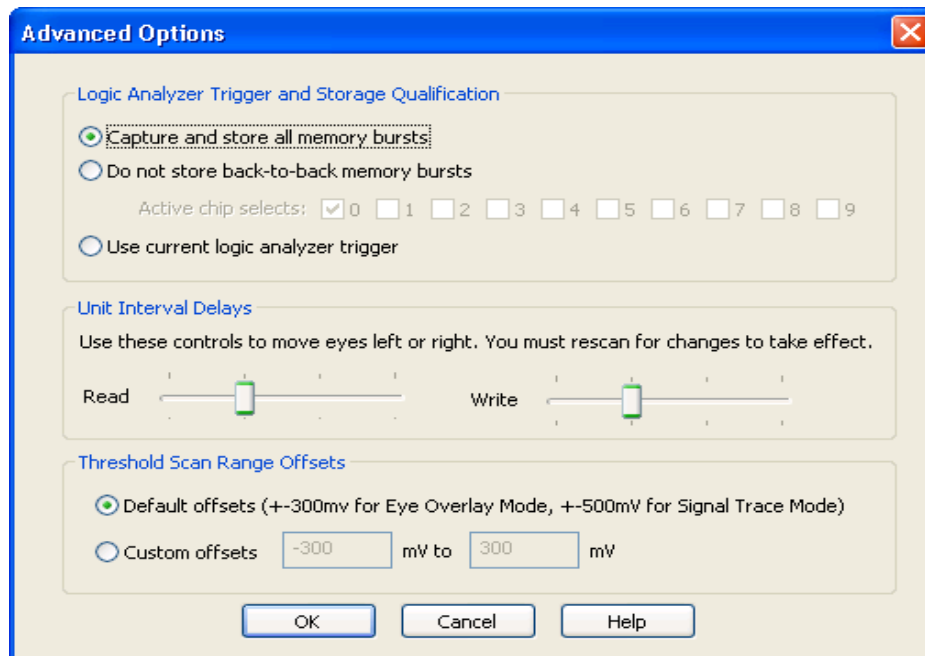


Scan Options	Application/Use
Scan Type	<p>Time scans divide the sample position time range into "buckets". During the scan, many samples are taken at different signal delay settings (and one threshold voltage), and the number of signal transitions that occur in the buckets is recorded. When the scan completes, buckets that have a greater number of transitions are colored brighter or with more intensity than buckets with fewer transitions. Buckets with no transitions have no color. This gives you a picture of where signal crossing points occur and can tell you where to set sample positions. Time scans are done at a single threshold voltage setting and provide the fastest scan for setting sample positions.</p> <p>Time and threshold scans divide time buckets vertically into voltage range buckets. During the scan, different threshold voltage settings are used as well as different delay settings. The scan results show more signal detail and help you better identify eyes and proper sampling positions. Threshold scans take longer because they scan voltages as well as time.</p>
Resolution	<p>You can select from these resolutions:</p> <ul style="list-style-type: none"> ▪ Ultra Fine (Slowest)– 5 ps time, 5 mV threshold resolution – uses the most buckets, and the scan takes longest to run. ▪ Fine– 10 ps time, 10 mV threshold resolution – uses many buckets, and the scan takes longer to run. ▪ Medium-Fine– 25 ps time, 20 mV threshold resolution – uses setting between Fine and Medium. ▪ Medium (Recommended)– 50 ps time, 50 mV threshold resolution – uses an intermediate number of buckets and results in an intermediate scan time. ▪ Coarse (Fastest)– 50 ps time, 75 mV threshold resolution – uses fewer buckets, and scans complete in a shorter amount of time.
Range	<p>Full performs the scan over the full sample position time range.</p> <p>Partial lets you narrow the time range and perform faster scans. However, be careful when changing these values. If you scan too short a time range, you could miss the proper signal eyes.</p> <p>Generally, you use this option when there is a portion of a signal you want to view in more detail and you want to shorten the time it takes the scan to run.</p>

See Also · [“Setting Advanced Scan Options”](#) on page 101

Setting Advanced Scan Options

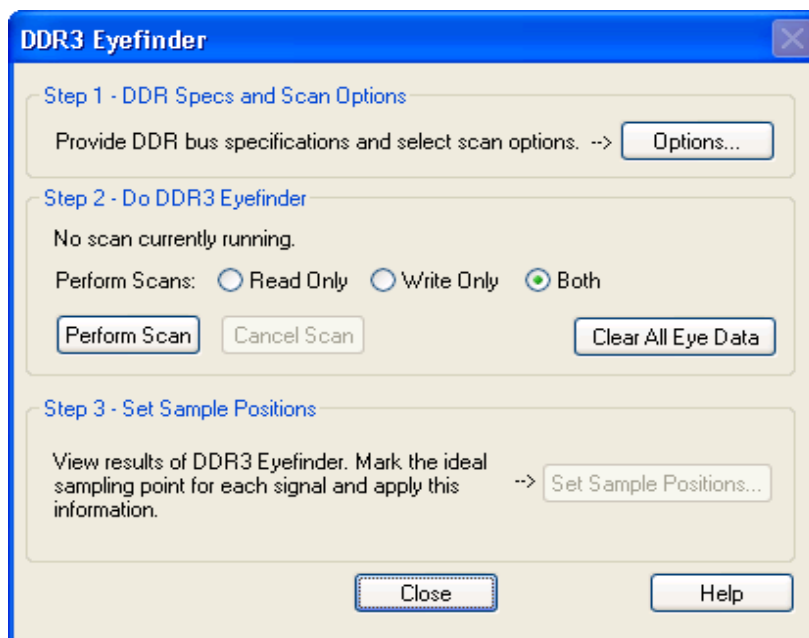
In the DDR Eyefinder Scan Options dialog's Scan Options tab, you can click **Advanced Options...** to change advanced scan options.



Field	Description
Logic Analyzer Trigger and Storage Qualification	<p>Capture and store all memory bursts – this is the default setting.</p> <p>Do not store back-to-back memory bursts – you can use this to eliminate the "double eye" effect in scan results.</p> <p>Use current logic analyzer trigger – this lets you further customize the samples that are used in scans.</p>
Unit Interval Delays	<p>If the eyes in which you want to set the sampling position are outside of the adjustment range, you can use these "coarse delay" adjustments to move the signals left or right (in relation to the zero time) by Unit Interval (clock cycle) amounts.</p> <p>It is unlikely that you will have to change the unit interval delays when using the proper configuration files and Total Read Latency and Total Write Latency settings.</p> <p>After making coarse delay adjustments, you must rescan and set the sampling positions again.</p> <p>Background: There are two ways to move the DDR3 Eyefinder display window and scan the appropriate location for the Read and Write data valid windows:</p> <ol style="list-style-type: none"> 1 By adjusting the Total Read Latency setting for the Read eyes and Total Write Latency for the Write eyes. See "Setting DDR Bus Specifications" on page 97. 2 By adjusting the Unit Interval Delays sliders. In the extreme right position, the delay is zero between the qualified clock edge and the data. Each mark to the left represents a whole clock cycle. The Unit Interval Delays sliders are usually used only for two scenarios: <ul style="list-style-type: none"> • When setting up a new configuration for a new probe or embedded midbus application where delays from the routing require adjustment in the DDR3 Eyefinder display. • When adjusting for significant changes in the data rate compared to the range of the specification for a specific configuration. For instance, most DDR3 probes are set up expecting DDR 3 800-1600. <p>Moving the slider to the left results in the data eyes moving left in the display after rerunning a scan. If the slider is all the way to the right and the data eyes need to move further to the right, reduce the Total Read Latency and Total Write Latency settings in the DDR3 Eyefinder tool. Once you determine the correct Latency settings to capture the data eyes, use the same latency values in the DDR Bus Decoder.</p>
Threshold Scan Range Offsets	<p>Lets you specify a custom vertical range to use for threshold scans. This option lets you either:</p> <ul style="list-style-type: none"> ▪ See a portion of a signal in more detail (and shorten the scan time). ▪ See more of the signal swing (and lengthen the scan time). <p>Note that the default offsets are different depending on the selected Scan Mode.</p>

Performing Scans

When performing DDR3 Eyefinder scans, you can perform read only scans or write only scans, you can cancel scans, and you can clear eye data.



To run scans

- 1 Click **Perform Scan** to start a scan using the currently set options (see ["Setting Scan Options"](#) on page 97).

To select Read Only, Write Only, or Both read and write scans

- If you are only interested in setting the sample positions of data read or data write signals, you can choose **Read Only** or **Write Only**.

To cancel a scan

- 1 Click **Cancel Scan** to stop a currently running scan.

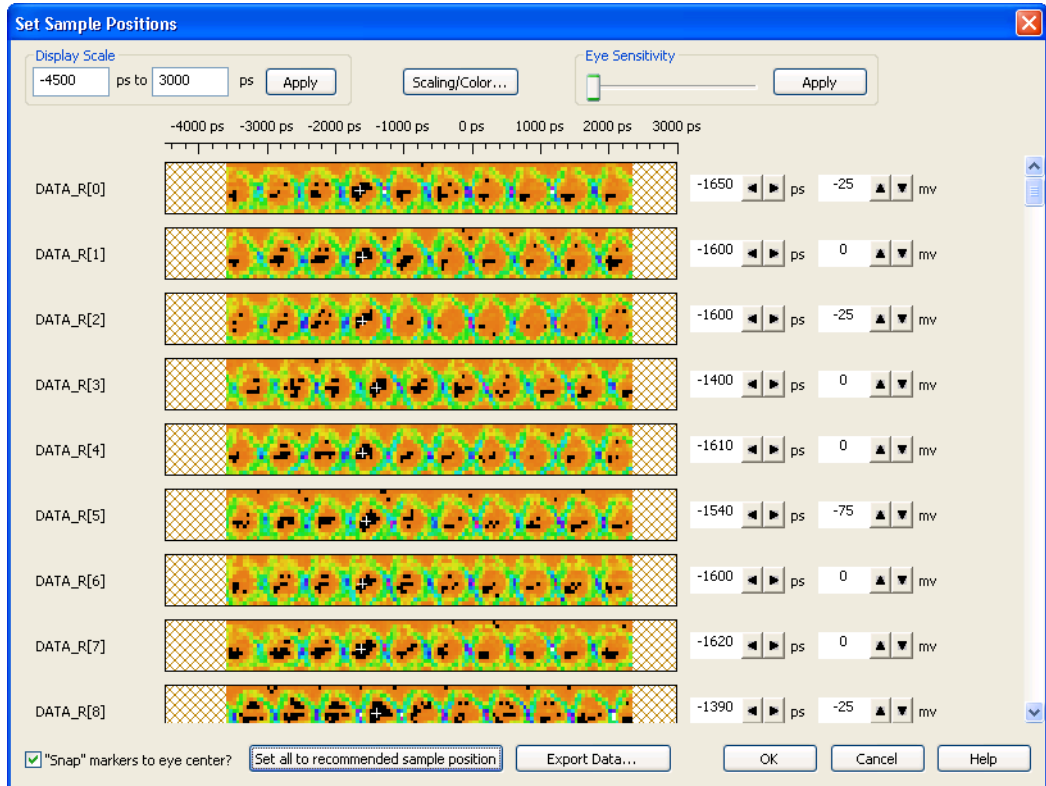
To clear all eye data

- 1 Click **Clear All Eye Data** to clear all DDR3 Eyefinder scan data.

Setting Sample Positions

After performing DDR3 Eyefinder scans, when setting sample positions, you can change the display settings to help identify the proper eye locations, and you can adjust the recommended sample positions.

To do this, click **Set Sample Positions...** in the DDR3 Eyefinder dialog. This opens the Set Sample Positions dialog.



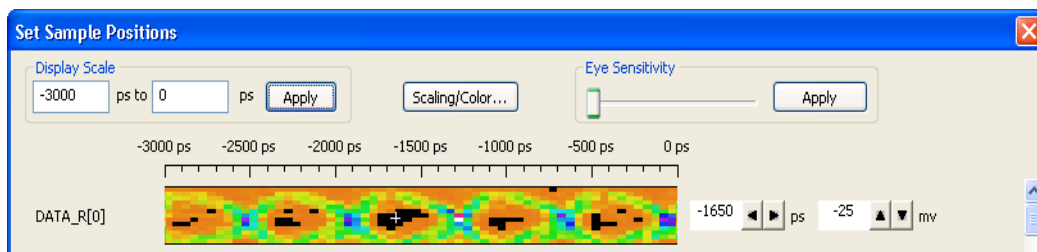
The Set Sample Positions dialog gives you these capabilities:

- [“Adjusting the Display Scale”](#) on page 104
- [“Changing the Time Bucket Scaling and Colors”](#) on page 105
- [“Adjusting the Eye Sensitivity”](#) on page 106
- [“Adjusting Sample Positions”](#) on page 107

The **Export Data...** button lets you export the underlying eye scan data to a CSV format file that can be imported into Microsoft Excel or other data visualization tools. For more information on the format of the exported CSV data, please contact your local Keysight sales representative.

Adjusting the Display Scale

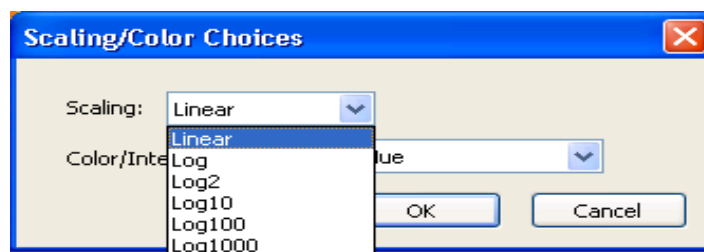
In the upper left corner of the Set Sample Positions dialog, there is a **Display Scale** box for adjusting the scale of the display. This lets you zoom in on a particular eye(s) or zoom out to the full scale of the data that was scanned. After you enter the desired values of the range, click **Apply**.



Changing the Time Bucket Scaling and Colors

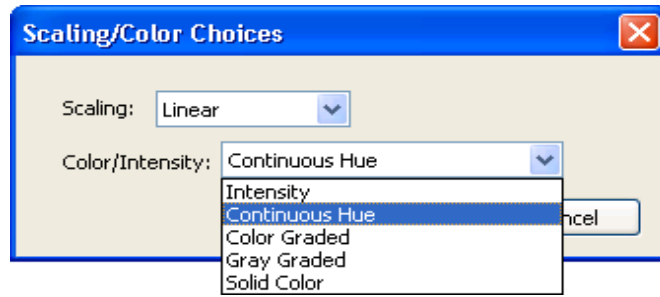
To change the time bucket scaling and color/intensity settings in the Set Sample Positions dialog:

- 1 Click **Scaling/Color...**
- 2 In the Scaling/Color Choices dialog, select the **Scaling** drop-down and choose the desired scaling:



Scaling:	Example	Notes
Linear		(Color graded)
Log		(Color graded)
Log2		(Color graded)
Log10		(Color graded)
Log100		(Color graded)
Log1000		(Color graded)

- 3 In the Scaling/Color Choices dialog, select the **Color/Intensity** drop-down and choose the desired color scheme or intensity:



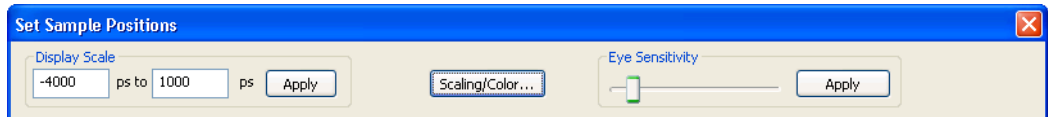
Color/Intensity:	Example	Notes
Intensity		(Linear scaling)
Continuous Hue		(Linear scaling) Continuous hue appears the same for all Log scales.
Color Graded		(Linear scaling)
Gray Graded		(Linear scaling)
Solid Color		(Linear scaling)

4 Click **OK** to make the scaling color change.

Adjusting the Eye Sensitivity

To adjust the eye sensitivity in the Set Sample Positions dialog:

- 1 Drag the **Eye Sensitivity** slider; then, click **Apply**.



Changing the sensitivity does not affect any of the collected data, it just hides lower intensity values so that you can more easily identify the signal eyes.

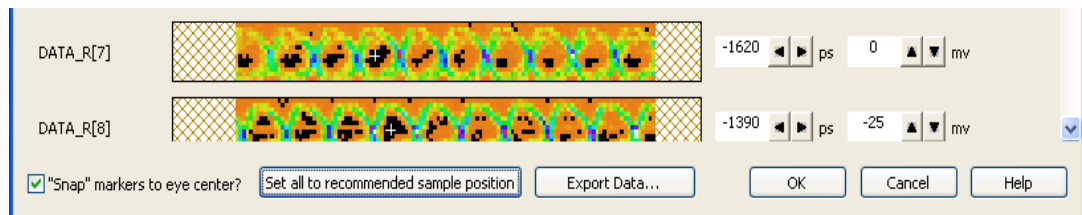
Some examples of decreased sensitivity are shown in the following table.

Color/Intensity:	Example	Notes
Intensity		(Linear scaling, decreased sensitivity)
Continuous Hue		(Linear scaling, decreased sensitivity)
Color Graded		(Linear scaling, decreased sensitivity)
Gray Graded		(Linear scaling, decreased sensitivity)
Solid Color		(Linear scaling, decreased sensitivity)
Color/Intensity:	Example	Notes
Intensity		(Log2 scaling, decreased sensitivity)
Continuous Hue		(Log2 scaling, decreased sensitivity) Continuous hue appears the same for all Log scales.
Color Graded		(Log2 scaling, decreased sensitivity)
Gray Graded		(Log2 scaling, decreased sensitivity)
Solid Color		(Log2 scaling, decreased sensitivity)

Adjusting Sample Positions

In the Set Sample Positions dialog, you can do these things to adjust the sample positions:

- Click **Set all to recommended sample position**.
The white crosshair markers show the recommended sample positions.



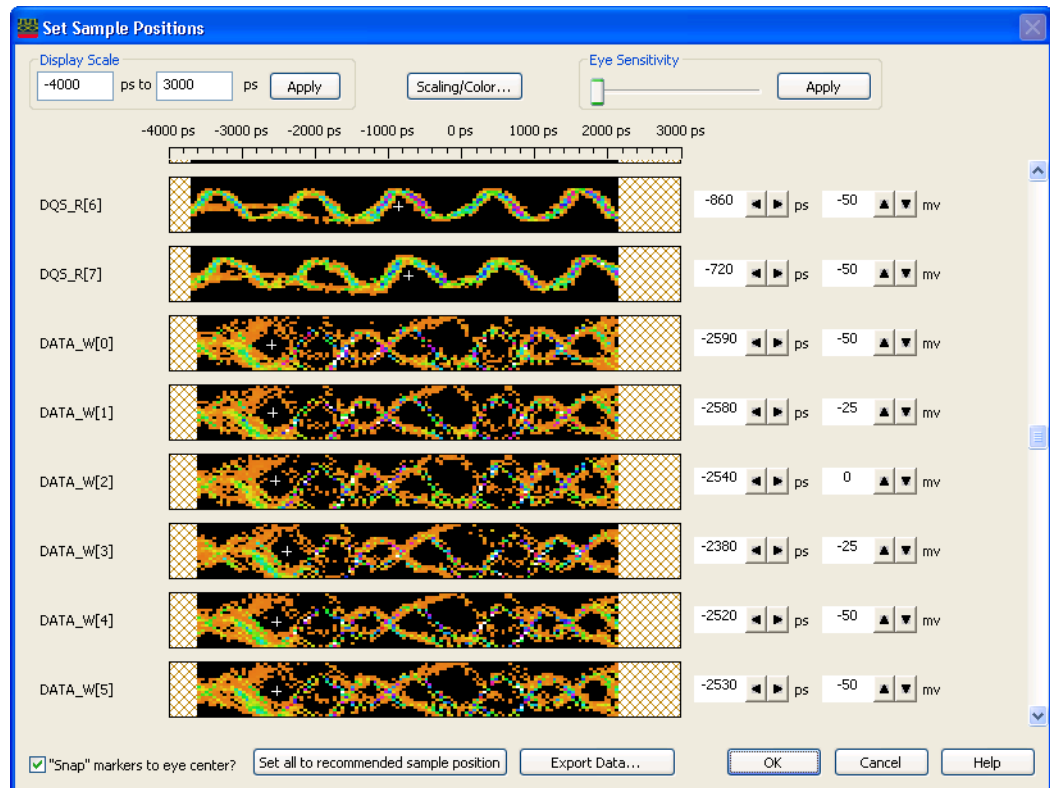
- Single-click to move to the center of suggested eyes.
- Uncheck the **"Snap" markers to eye center** option for greater control over the sample position placement.
- Use the fine controls to the right of the signal pictures.

Viewing Signal Swing vs. Time

If you have selected the Signal Trace Scan Mode (see [“Setting Scan Mode”](#) on page 98) and performed a scan (see [“Performing Scans”](#) on page 103), you can click **Set Sample Positions...** in the DDR3 Eyefinder dialog to view the signal swing vs. time. This view:

- Provides additional qualitative insight into the signal integrity on the DDR system at the logic analyzer probe location.
- Lets you check and modify sample positions although it is generally not recommended.
- Can show how the bits in a complete burst compare to one another.
- Can show how bursts from different byte lanes compare to one another.

For example, the following picture shows signal trace scan results at the beginning of an x8 data burst.



Solving DDR3 Eyefinder Problems

If you run into these problems, see:

- “If scans stick on Runs in DDR3 Eyefinder” on page 110
- “If there are no transitions in DDR3 Eyefinder” on page 110
- “If eyes show tri-stating” on page 110
- “If eyes are closed” on page 111
- “If there are multiple eyes” on page 112
- “If eye scan results are noisy” on page 112

If scans stick on Runs in DDR3 Eyefinder

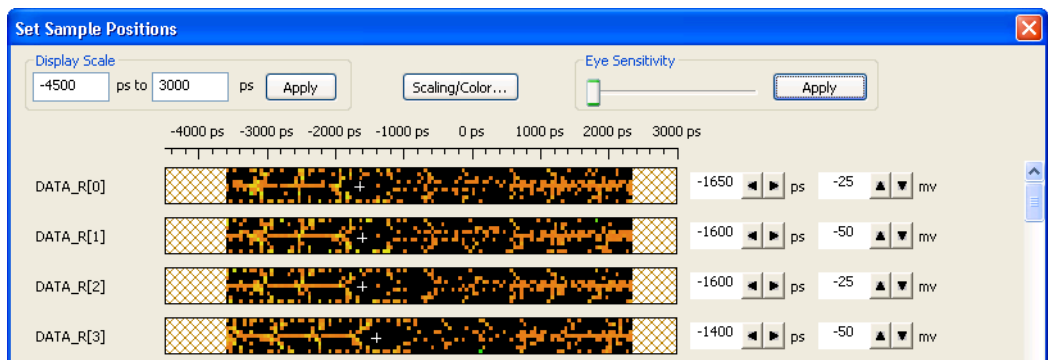
If scans stick on Runs in DDR3 Eyefinder, this means triggers are not happening in the logic analyzer. You can verify this by looking at the status in the *Keysight Logic Analyzer* application. If this is the case, cancel the scan and look for possible solutions.

Possible Solutions:

- Take a trace in the logic analyzer to make sure reads and writes are occurring.
- Make sure there is consistent memory traffic *on the channel you are probing*.

If there are no transitions in DDR3 Eyefinder

The following picture is of an example scan showing no transitions.



Possible Solutions:

Take a trace and observe the data. If the data is not changing during the burst, then DDR3 Eyefinder will not show transitions.

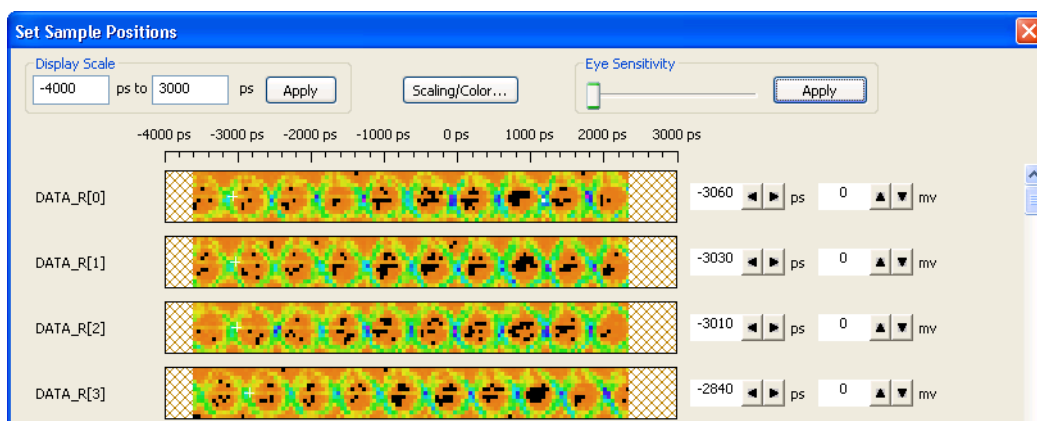
Example:

Entire burst is the same pattern. Resulting in no transitions in DDR3 Eyefinder.



If eyes show tri-stating

Horizontal lines through the middle of eyes show tristating, as in the following picture.

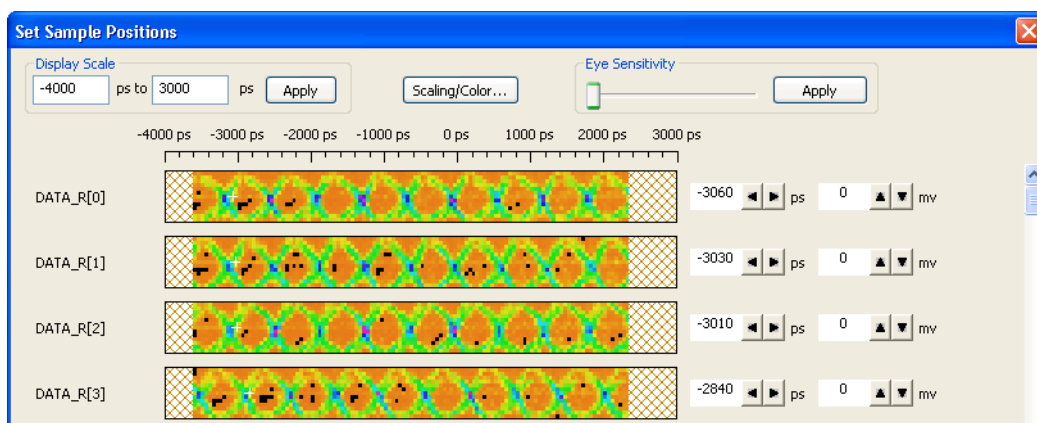


Possible Solutions:

- Check the Total Read Latency and Total Write Latency values in the DDR3 Eyefinder options dialog are correct.
- Adjust the Unit Interval Delays in the DDR3 Eyefinder advanced options dialog and re-run the scan.
- Make sure the clock signal is "clean" with crisp transitions.
- Make sure the Burst Length value in the DDR3 Eyefinder options dialog is not set too high (for example, set at 8 when the real burst length is 4).

If eyes are closed

The following picture is of an example scan showing closed or "noisy" eyes.



Possible Solutions:

- Check the Total Read Latency and Total Write Latency values in the DDR3 Eyefinder options dialog are correct.
- Try adjusting the Eye Sensitivity slightly and click **Apply**. A slight adjustment of the sensitivity may help you identify the proper eye for setting the sample position.

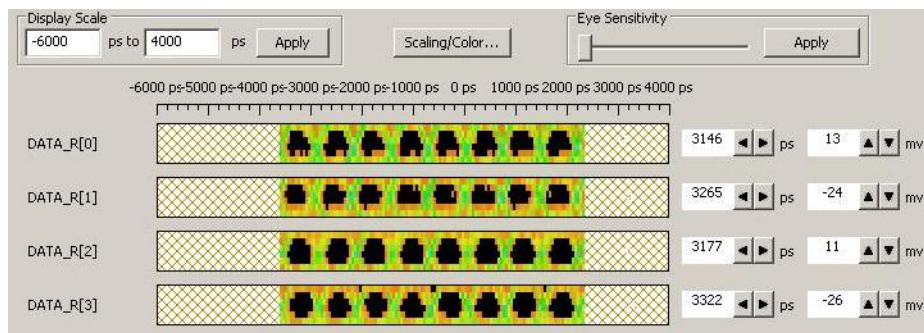
CAUTION

Be sure to reset the Eye Sensitivity after setting the sample position so that you are not hiding scan information for additional signals.

- Try scanning at the next finer setting, but stay within the **Medium** or **Medium-Fine** range. The **Fine** or **Ultra Fine** settings are generally not necessary for setting sample positions and they take much longer to run.
- Make sure the clock signal is "clean" with crisp transitions.
- Check the stimulus.
- Make sure the Burst Length value in the DDR3 Eyefinder options dialog is not set too high (for example, set at 8 when the real burst length is 4).

If there are multiple eyes

The following picture is of an example scan showing multiple eyes. In this case, it is hard to identify the proper eye in which to set the sample position.

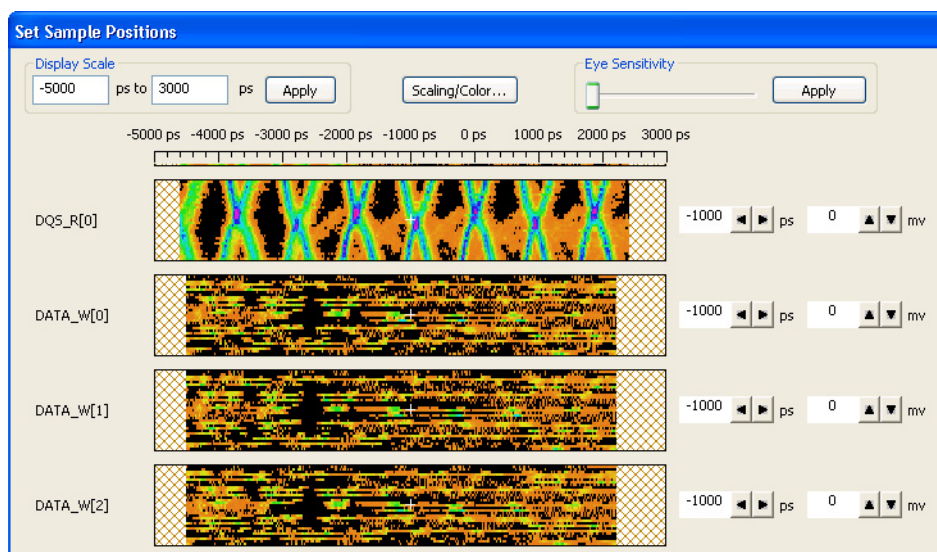


Possible Solutions:

- Make sure the Eye Sensitivity adjustment is not being used.
- Use the "Do not store back-to-back memory bursts" option (see ["Setting Advanced Scan Options"](#) on page 101).
- Try scanning at the next finer setting, but stay within the **Medium** or **Medium-Fine** range. The **Fine** or **Ultra Fine** settings are generally not necessary for setting sample positions and they take much longer to run.
- Specify a greater voltage scan range (Threshold Scan Range Offsets) in the DDR3 Eyefinder advanced options dialog and re-run the scan.
- Make sure the Burst Length value in the DDR3 Eyefinder options dialog is not set too low (for example, set at 4 when the real burst length is 8).
- Note that while byte lane eyes can shift, there are seldom shifts within byte lanes. Also, note that strobe eyes are aligned with the eyes of the signals in the corresponding byte lane.

If eye scan results are noisy

The following picture shows eyescan results that are noisy.



Possible Solutions:

- Make sure there are consistent memory reads and writes (see [“Setting Up Read and Write Traffic in the DUT”](#) on page 36). For example, these sort of results can occur when running multiple memory tests instead of a consistent memory test.
- Make sure the memory being tested is not switching to a different rank for a long periods of time.

6 Using Eyescan (for U4154A/B Logic Analyzer Module)

The Eyescan feature is used to set Thresholds and Sample Positions when using the U4154A/B Logic Analyzer module. Eyescan is used to perform general eyescans as well as to specifically find DDR data signal eyes. You can also use the Eyescan feature to customize DDR eyescans and to modify the scan qualification parameters that you initially set using the DDR Setup Assistant tool.

You can then choose to set the sampling position and threshold voltages suggested in the eye scan run or manually adjust these settings based on the suggested values. You use the Eye Scan - Sample Position and Threshold Settings dialog box to set up and run eye scan measurements for U4154A/B. In this dialog box, first you create an eyescan measurement and customize it to suit your specific requirements and then run this eyescan measurement. This allows U4154A/B logic analyzer to determine and suggest optimal values for sample positions and thresholds.

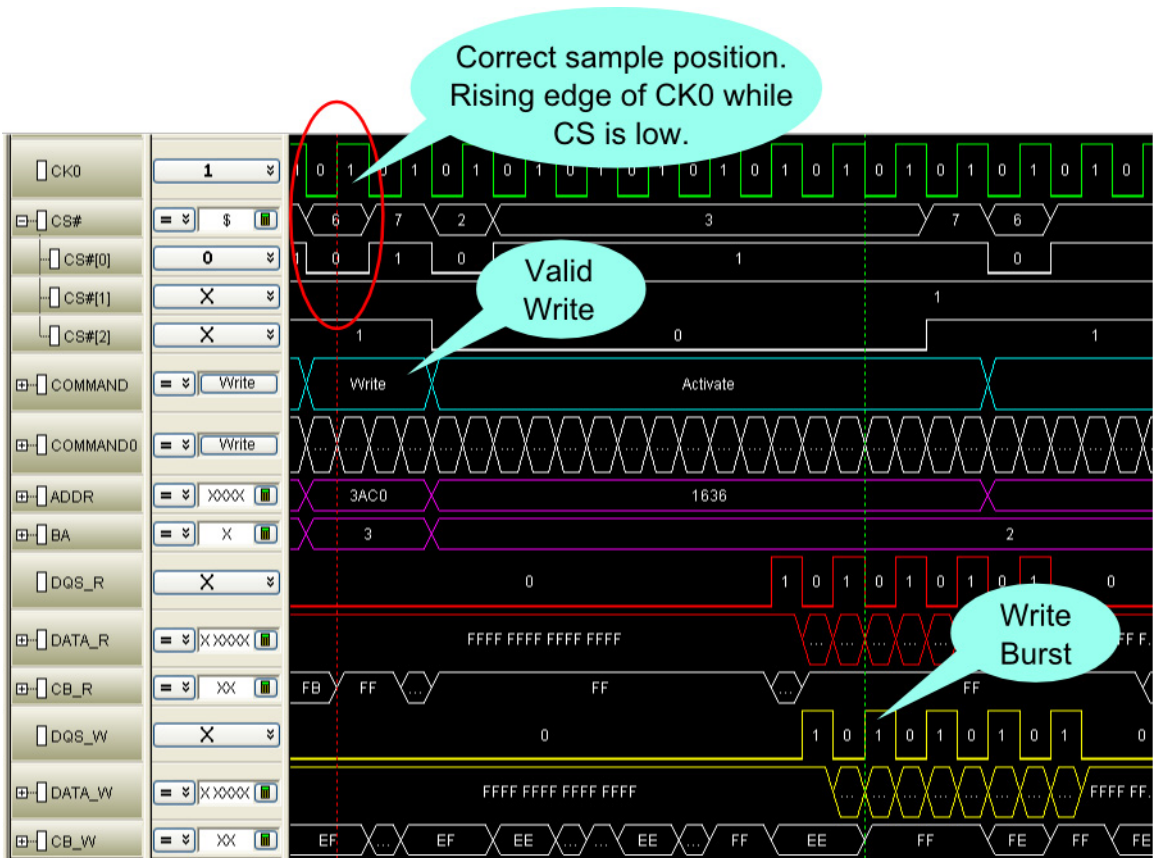
To know about the eyescan feature in detail and how to set up and run an eyescan, refer to the topic *Setting up and Running Eyescans in U4154A/B Logic Analyzer* in the Logic Analyzer online help.

7 Validating the DDR Setup

Validating Data in the Trace / 118

Validating Data in the Trace

After sampling positions have been set up, click the Run button to take a trace. Then, view the results in the Waveform window.



The previous picture shows a valid write and write burst.

8 Capturing Data (Triggering)

Recalling DDR Favorite Triggers / 120
Triggering on Valid Commands / 121
Burst Triggering / 122

Recalling DDR Favorite Triggers

The configuration files provided with the DDR Bus Decoder include these DDR favorite triggers:

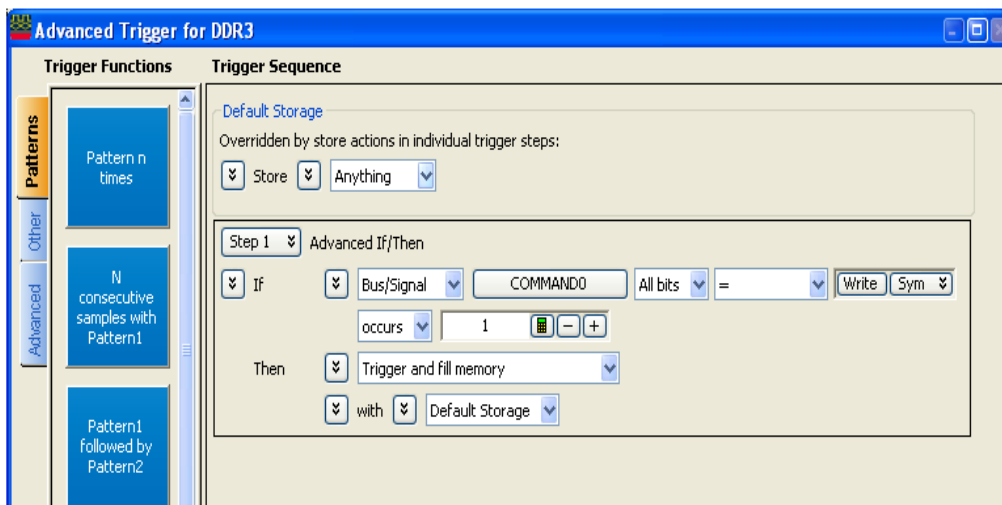
DDR Favorite Trigger	Description
Burst 4 Write Data	Triggers on four write burst data values.
Burst 8 Write Data	Triggers on eight write burst data values.
Mode Register Settings (MRS)	Captures mode register settings as the DDR device under test starts up. This trace will show the Total Read latency, Total Write latency, burst length, and burst type (sequential or interleaved) values of the DDR device under test. See "Taking a Mode Register Settings (MRS) Trace" on page 56.
Basic Trigger	Lets you specify command, CS#, CKE, and CS0 values to trigger on.
Filter NOPs	Uses trigger sequence step storage qualifiers and branched to prevent NOPs from being stored in the trace.

To recall the DDR favorite triggers:

- 1 In the *Keysight Logic Analyzer* application, open the Advanced Trigger Setup dialog.
- 2 Click **Recall...** at the bottom of the dialog.
- 3 In the Recall Trigger dialog, select the favorite trigger; then, click **OK**.

Triggering on Valid Commands

With DDR signals, you can set up the logic analyzer to trigger on valid commands. For example, you can trigger on Command0 and qualify it with CS#0.



Note that you can use pre-defined symbols to easily select commands.

For more information on setting up triggers, see "Specifying Advanced Triggers" (in the online help).

Burst Triggering

With the 16960A and 16962A logic analyzers, you can use the burst triggering feature to capture sequential data capture.

The trigger setup for sequential data triggering looks like:

The screenshot shows the trigger configuration interface with the following settings:

- Default Storage:** Overridden by store actions in individual trigger steps. Store: Anything.
- Step 1:** Advanced If/Then. If: Bus/Signal, COMMAND0, All bits, =, Read, Sym. Occurs: 1. Then: Goto, Next.
- Step 2:** Advanced If/Then. If: Anything. Occurs: 19. Then: Goto, Next.
- Step 3:** Advanced If/Then. If: Burst, 4, DATA_R.

.1:	0000 0020 0000 0010	Hex
.2:	0000 0080 0000 0040	Hex
.3:	0000 0200 0000 0100	Hex
.4:	0000 0800 0000 0400	Hex

 Occurs: 1. Then: Goto, Next.

 Else if not: Burst, 4, DATA_R.

.1:	0000 0020 0000 0010	Hex
.2:	0000 0080 0000 0040	Hex
.3:	0000 0200 0000 0100	Hex
.4:	0000 0800 0000 0400	Hex

 Then: Goto, 1.

NOTE

The trigger will be at the end of the burst pattern specified in the burst trigger.

For more information on burst triggering, see "Specifying Advanced Triggers in the 16960/16962 Logic Analyzers" (in the online help).

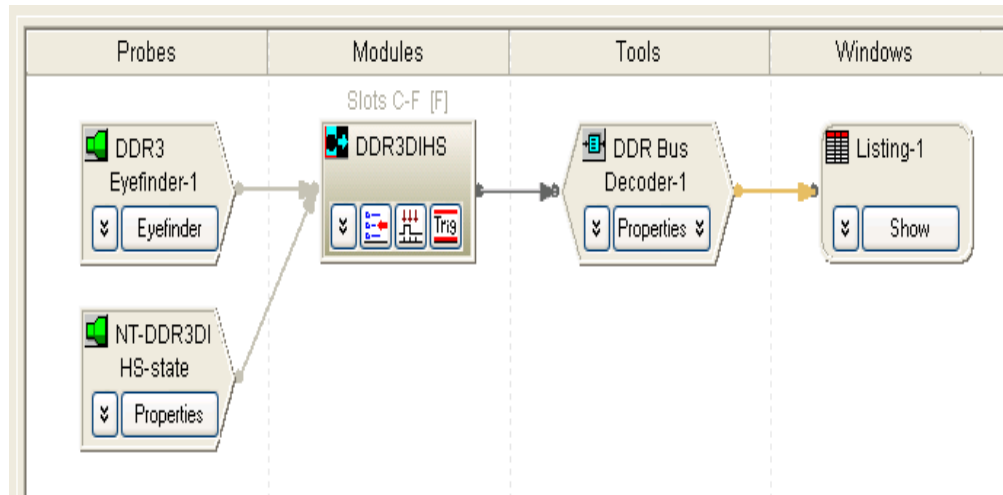
9 Decoding Captured Data

DDR Bus Decoder / 124

The DDR Bus Decoder is used to decode data captured from the DDR device under test. Third party probes may provide their own, similar bus decoder tools.

DDR Bus Decoder

The DDR Bus Decoder appears in the *Keysight Logic Analyzer* application's Overview window, as shown in the following example.



For more information, see "Using the DDR Bus Decoder" (in the online help).

A Setting Data Sample Positions with the 1695x Logic Analyzers

When using 16950A/B or 16951B logic analyzers (to capture DDR2 data), the DDR3 Eyefinder cannot be used to determine the proper sample positions for data signals. Instead, you can use the logic analyzer's *timing zoom* feature as outlined in this appendix.

This procedure uses Timing Zoom to identify the time difference between the CK0 (rising and falling edges) and the center of the read and/or write eyes. If dual sampling is used, there is one set of bus/signal names for reads and another for writes, and the sample position can be set independently for each.

The sample position for each bus/signal is set to the middle of the data valid region for the burst type the bus/signal supports.

- 1 The DDR Bus Decoder requires the proper parameters to be entered in order to decode valid states.

In the *Keysight Logic Analyzer* application's Overview window, select **System Configuration** from the DDR Bus Decoder's Properties drop-down.

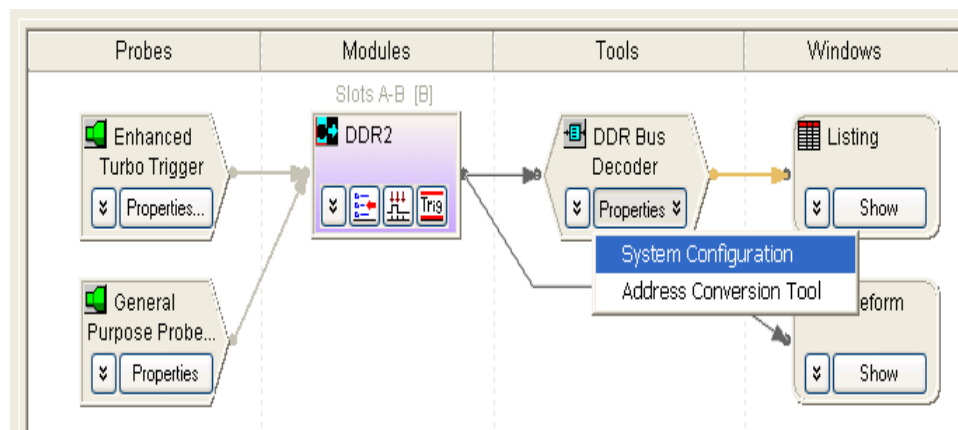


Figure 1 Opening the DDR Bus Decoder System Configuration

The information required is generally available from the specifications sheet of the memory device being used or by querying the BIOS of the device under test.

- Additive Latency – Defined by the chipset.
- Number of Chip Selects – This is either 1 or 2 based on the whether either CS0 is being probed and incorporated into the DDR Bus Decoder or both CS0 and CS1.
- Total Read Latency – The delay from a valid Read command to when the Read data is strobed on the bus.

- Burst Length – Usually fixed at 2, 4, or 8.

The DDR System Configuration dialog for entering this information is shown in the following figure.

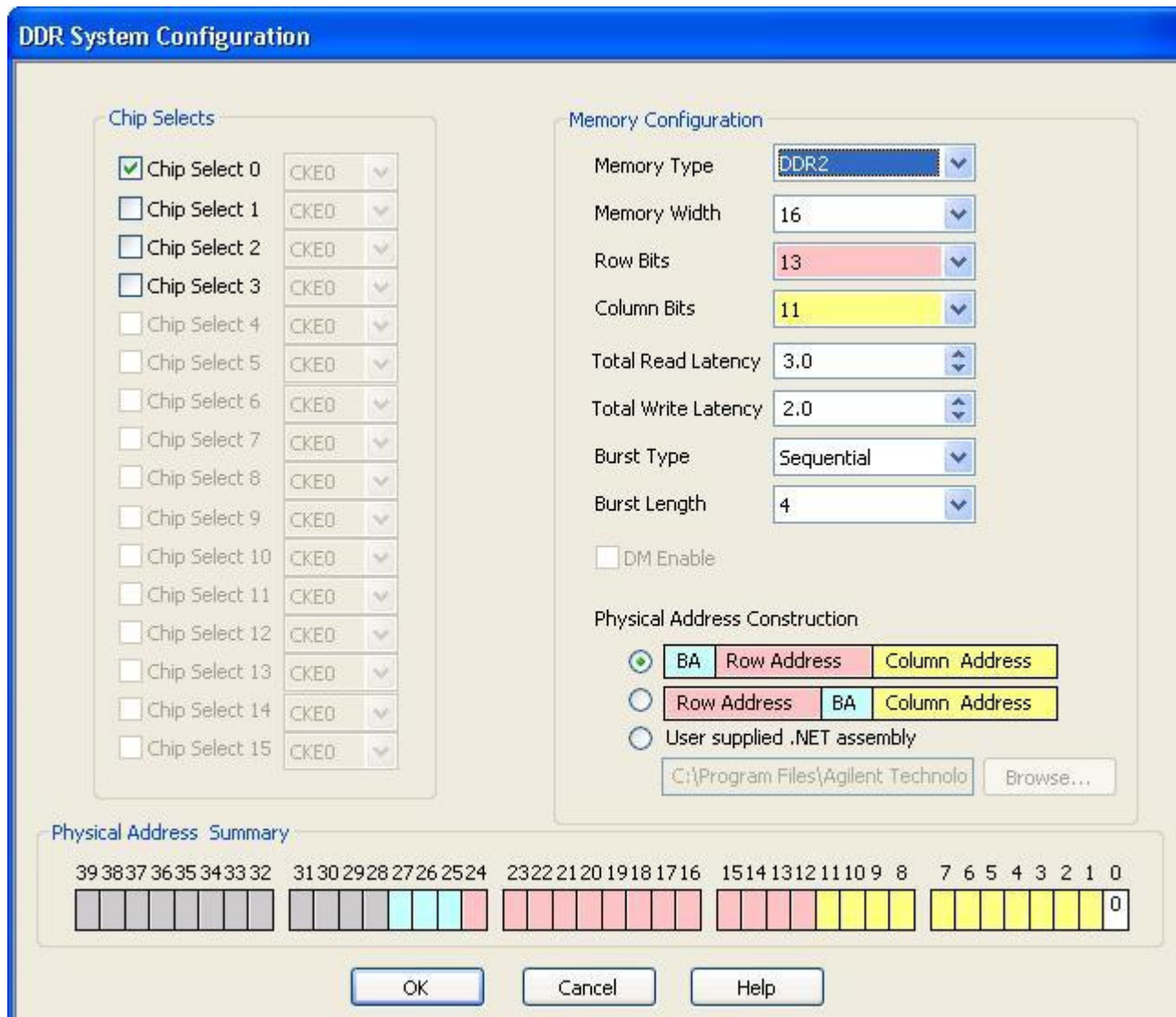


Figure 2 Setting the DDR Bus Decoder System Configuration

- 2 Start a memory test program that creates a good mixture of reads and writes, ideally with bursts of both types close enough together to fit several cycles of each type of burst in a single Timing Zoom trace.
A trigger on a write may be required if the test program does not have a mix or reads and writes in close proximity.
- 3 Trigger the analyzer on a burst. This can be done by using the logic analyzer trigger function "Find pattern n times" as shown in the following figure:

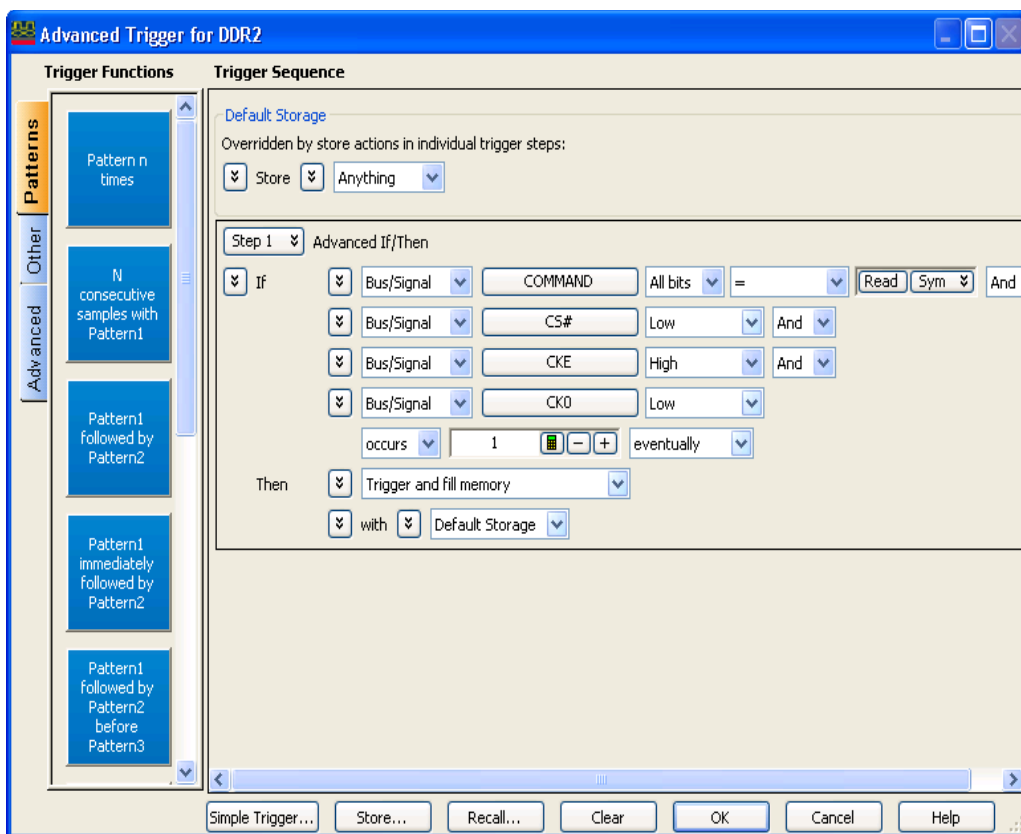


Figure 3 Trigger on a read

Note that in addition to looking for the DDR commands, the CS# signal is used to determine if the command is actually addressing a memory chip, and the CK0 signal is used to make sure the command sampled on the rising edge of the CK0 is used (since that is when the DDR command bus is valid).

This example uses CS# to identify valid commands. Any chip select that addresses an actual rank of memory may be used. If more than one chip select signal is needed (such as when there are several DIMMS on the bus), each of those chip select signals may be OR'ed together in the trigger event.

- 4 Run the logic analyzer to capture a trace.
- 5 Open the Waveform window.

If they are not already added by the supplied configuration file, add the Timing Zoom bus/signal names for:

- command clock, CK0 (TZ)
- chip selects, CS# (TZ)
- DQS, DQS (TZ)
- bus bus/signal names for data reads, DATA_R (TZ)
- bus bus/signal names for data writes, DATA_W (TZ)

Scroll the waveforms to find the start of a read burst. You will see this by finding where the DQS strobe becomes active.

- 6 The following figure shows an example Waveform window being used to locate the start of a read burst.

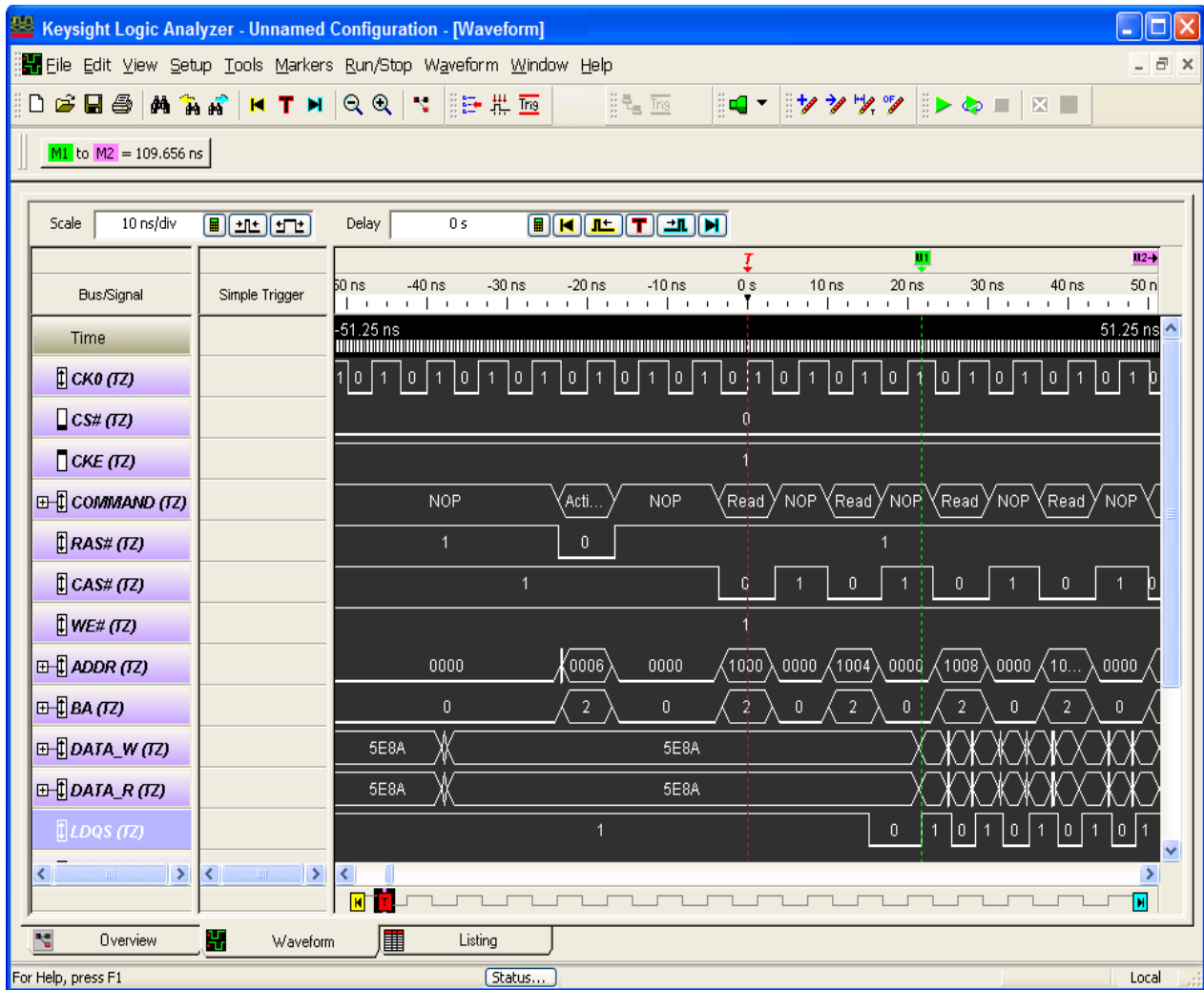


Figure 4 Locating a Read Burst

NOTE

Your display may differ from the previous figure. This is okay. To measure the timing differences you can use just the DATA (TZ) bus/signal names and not the DATA_R (TZ) bus/signal names.

- Now, measure the time delay from the closest edge of CK0 prior to the center of the read data eyes. Place a marker on that edge of the CK0. Place the other marker in the center of the data valid region for the read data bus/signal name. You may find it easier to identify this point by locating the point on one of the DQS signals that is equal distances from the edges. Note the delay between the markers as shown in the following figure.

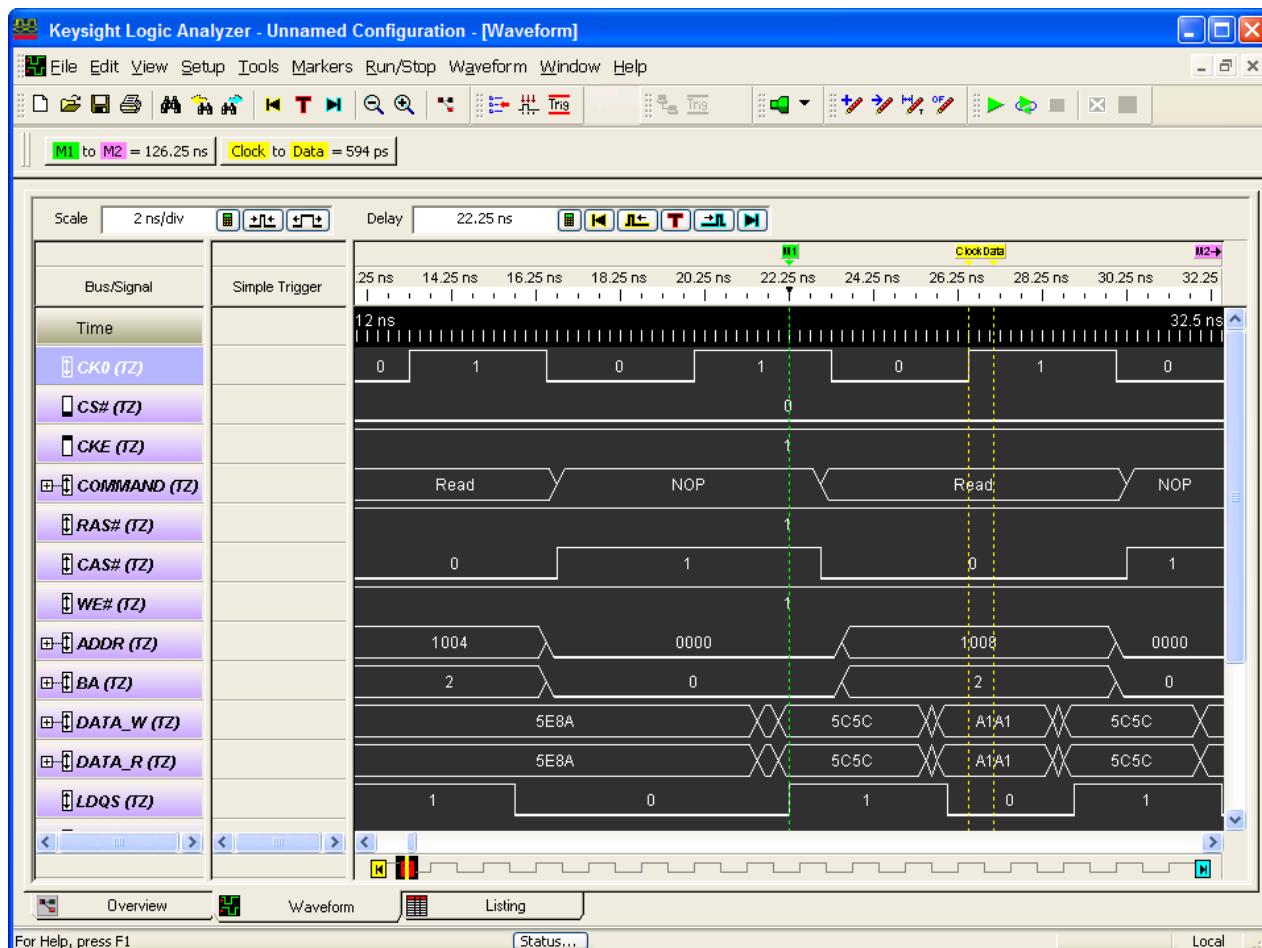


Figure 5 CK0 rise to center of read data eye

- 8 Repeat this procedure using the next edge of CK0 and the corresponding data burst cycle (it will be right next to the burst cycle you just looked at).
- 9 Repeat this procedure for several cycles of the burst. You may do this for other read bursts as well if you wish to cover different types of data burst patterns and account for possible edge jitter sources.

Compute the average of the times for all the burst cycles (combining those for the rise of CK0 and the fall). This will be your sample position delay value, for example 300 ps.

- 10 Now, it is time to use this delay information to set the logic analyzer sample position.

In the logic analyzer's Sampling Setup dialog, click **Thresholds and Sample Position...**

In the Thresholds and Sample Positions dialog, you can set the sample positions for the read and write data bus/signal names.

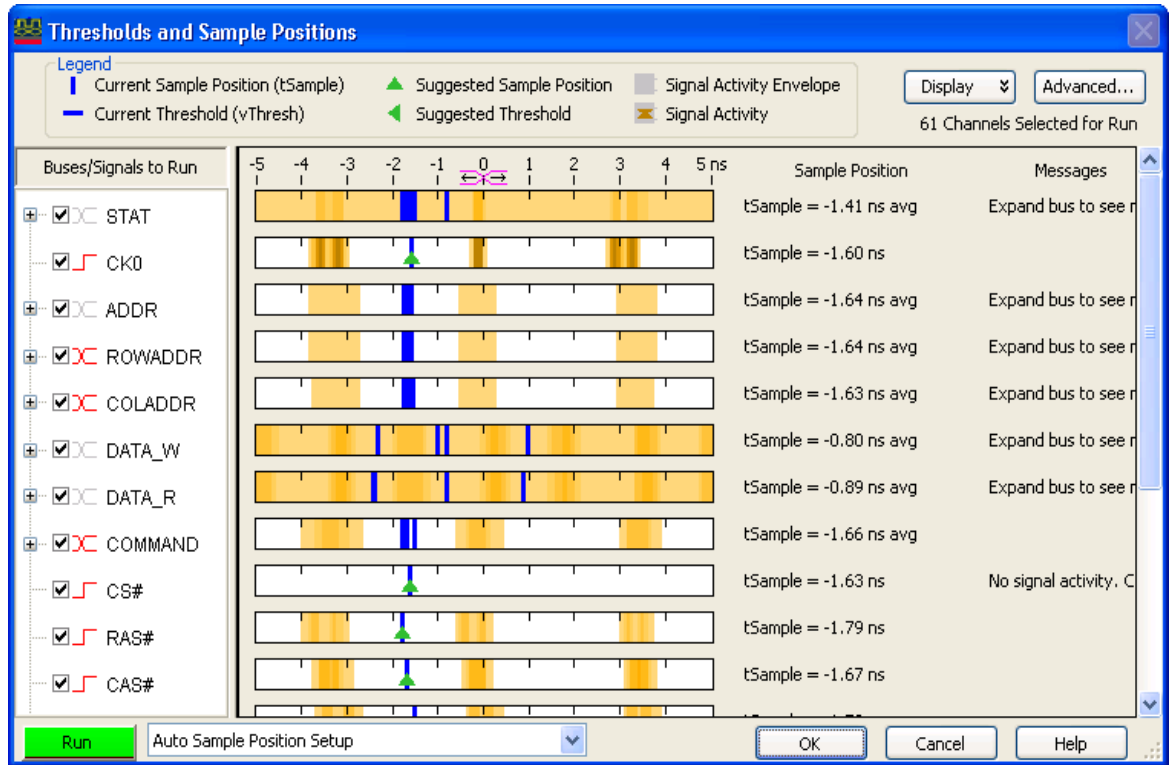


Figure 6 Setting the Sample positions

- 11 Set the sample position to be equal to the average time you computed earlier.

The easiest way to do this is to point to the blue vertical sample position bar with the mouse and press and hold the left mouse button while dragging the blue bars as far to the left side of the display as possible. This will cause all the blue bars for that bus/signal name to be set to the same value. Then, you can drag the blue sample position bar back to the right to place it in the position you measured earlier.

The sample position is indicated on the scale at the top of the display as well as on the side under the "Sample Position" column.

The following figure shows the DATA_R bus/signal name sample position set to +309 ps as an example. This means that if you measured a 309 ps average delay to the center of the data eye for the DATA_R bus after a valid CK0 edge, you would set the logic analyzer sample position for DATA_R to +309 ps (as shown in in the following figure).

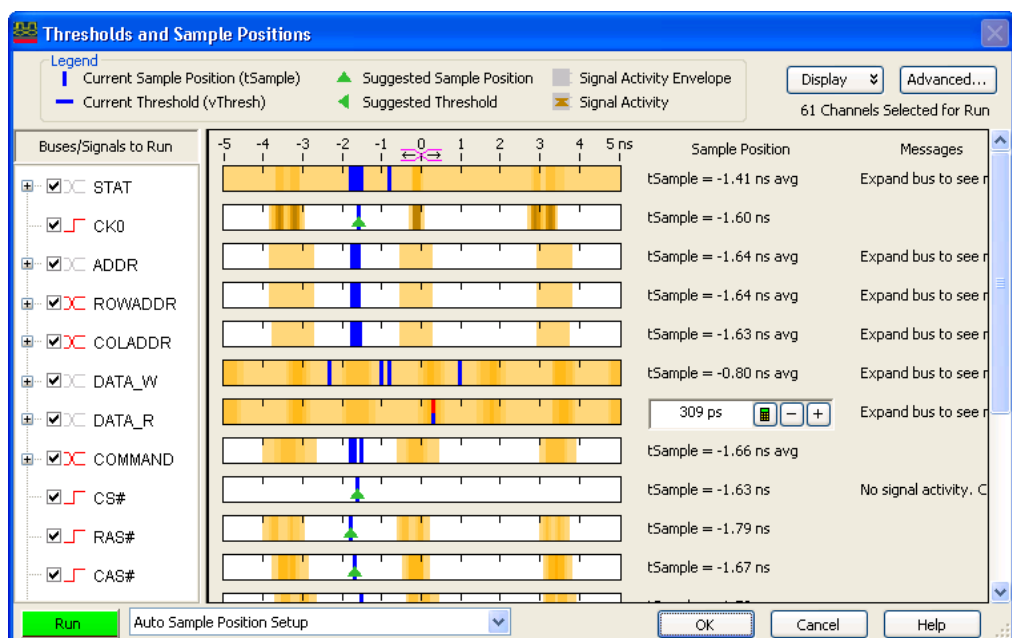


Figure 7 DATA31-0 set to +1.86ns

- 12 Repeat this procedure as well for the ECC bits and the data strobes.
- 13 For the DDR command/address bus you can repeat this procedure also, except that time is measured only from the rising edge of CK0 since those signals are only valid at that time.

This completes the procedure for the read configuration.

Use the same procedure using write bursts and the write data bus/signal names. The only difference is that you can easily find the center of the data valid window by setting the second marker to the EDGE of the DQS signal. (Write data eyes are centered on the edge of the strobes whereas reads straddle the DQS strobes.)

- 14 If you are using the Dual Sample Mode, repeat the calibration procedure for Writes.

You should now be ready to take state traces and be confident you will capture bus traffic correctly.

For more information, see "To manually adjust state sampling positions" (in the online help).

DDR Setup Assistant

User's Guide

DDR Glossary

D

DUT

Device Under Test.

I

interposer

Describes a probing method where the probe is located between a slot and a DIMM.

M

midbus probe

Describes a probing method where Soft Touch footprints are designed into a DUT board between the memory and the memory controller. The N4834A midbus probe is one specific footprint and configuration for midbus probing. Other custom Soft Touch footprints are possible.

Index

Numerics

1695x logic analyzers, DDR data sample positions, [125](#)

A

advanced options, DDR3 Eyefinder, [101](#)

B

back-to-back memory bursts, [102](#)
beginning of data burst, signal trace scan mode, [99](#)
burst length, [61](#), [62](#)
burst triggering, [122](#)
burst type, [61](#)
bus specifications for DDR3 Eyefinder, [97](#)

C

capture and store all memory bursts, [102](#)
chip selects, [62](#)
clock edges too close, [78](#)
closed eyes in DDR3 Eyefinder, [111](#)
coarse delay adjustment, [102](#)
coarse scan resolution, [100](#)
color graded, [106](#)
colors, DDR3 Eyefinder, [105](#)
continuous hue, [106](#)
custom midbus probing, [32](#)

D

data, capturing, [119](#)
data, decoding captured, [123](#)
data, validating in the trace, [118](#)
DD43 BGA probes, [14](#)
DDR Bus Decoder, [7](#), [124](#)
DDR Bus Decoder, latency values, [59](#)
DDR Setup Assistant, before using, [33](#)
DDR Setup Assistant, Ctrl/Addr sample positions, [53](#)
DDR Setup Assistant, Data sample positions, [66](#)
DDR Setup Assistant, find latency values, [55](#)
DDR Setup Assistant, hardware setup, [45](#)

DDR Setup Assistant, input parameters, [39](#)
DDR Setup Assistant, load configuration, [42](#)
DDR Setup Assistant, save setup, [70](#)
DDR Setup Assistant, set initial thresholds, [48](#)
DDR Setup Assistant, setup complete, [71](#)
DDR Setup Assistant, starting, [38](#)
DDR Setup Assistant, using, [37](#)
DDR Setup Assistant, verify software, [40](#)
DDR2 BGA probes, [27](#)
DDR3 BGA probes, [24](#)
DDR3 DIMM interposers, [17](#)
DDR3 Eyefinder, [7](#)
DDR3 Eyefinder, before running, [86](#)
DDR3 Eyefinder, getting started, [86](#)
DDR3 Eyefinder, latency values, [61](#)
DDR3 Eyefinder, performing scans, [103](#)
DDR3 Eyefinder, problems, [110](#)
DDR3 Eyefinder, scan options, [97](#)
DDR3 Eyefinder, setting sample positions, [104](#)
DDR3 Eyefinder, using, [85](#)
DDR3 Eyefinder, your first scan, [86](#)
DDR3 midbus probes, [26](#)
DDR3 SODIMM interposers, [22](#)
decoding captured data, [123](#)
DIMM interposers, handling, [17](#)
DIMM interposers, using, [17](#)
display scale adjustment, DDR3 Eyefinder, [104](#)
DUT (Device Under Test), [133](#)

E

end of data burst, signal trace scan mode, [99](#)
export scan data, [104](#)
eye overlay mode, DDR3 Eyefinder scan mode, [99](#)
eye sensitivity, DDR3 Eyefinder, [106](#)

F

favorite DDR triggers, [120](#)
fine scan resolution, [100](#)
FS2350 DDR3 DIMM interposer, [21](#)
FS2351 DDR3 DIMM interposer, [20](#)
FS2352 1867 DDR3 DIMM probe, [18](#)

FS2354 DDR3 SODIMM interposer, [22](#)

G

general purpose probe tool, [7](#)
glossary, [133](#)
gray graded, [106](#)

I

installing software, [34](#)
intensity, [106](#)
interposer, [133](#)

L

latency values, finding, [55](#)
linear scaling, [105](#)
Listing window, [7](#)
Log scaling, [105](#)
logic analyzer module, [7](#)
logic analyzer trigger, [102](#)
LPDDR BGA probes, [31](#)
LPDDR3 BGA probes, [30](#)
LPDDR4 BGA probes, [29](#)

M

medium scan resolution, [100](#)
medium-fine scan resolution, [100](#)
memory configuration, [62](#)
midbus probe, [133](#)
midbus probing, custom, [32](#)
middle of data burst, signal trace scan mode, [99](#)
Mode Register Settings (MRS) trace, [56](#)
MRS (Mode Register Settings) trace, [56](#)
multiple eyes in DDR3 Eyefinder, [112](#)

N

N4821B DDR3 DIMM interposer, [21](#)
N4834A DDR3 midbus probe, [26](#)
N4835A DDR3 DIMM interposer, [20](#)
Nexus DDR3 DIMM interposer, [19](#)
Nexus DDR3 SODIMM interposer, [23](#)
noisy results in DDR3 Eyefinder, [112](#)

O

optional software, [34](#)

P

probing options, [13](#)

R

range, DDR3 Eyefinder scan, [100](#)
 read offset, [60](#)
 read/write traffic, setting up, [36](#)
 Remote Desktop Connection, [34](#)
 required software, [34](#)
 resolution, DDR3 Eyefinder scan, [100](#)
 runs, scans stuck during, [110](#)

S

sample positions, adjusting, DDR3
 Eyefinder, [107](#)
 scaling, DDR3 Eyefinder, [105](#)
 scan mode, DDR3 Eyefinder, [98](#)
 scan options, DDR3 Eyefinder, [99](#)
 scan type, DDR3 Eyefinder, [100](#)
 signal trace mode, DDR3 Eyefinder
 scan mode, [99](#)
 signal trace scan mode, [109](#)
 Soft Touch custom midbus probing, [32](#)
 software, required and optional, [34](#)
 solid color, [106](#)
 stuck scans, [110](#)

T

threshold scan range offsets, [102](#)
 thresholds and sample positions, [73](#)
 total read latency, [60](#), [62](#)
 total write latency, [60](#), [62](#)
 transitions missing in DDR3
 Eyefinder, [110](#)
 triggering, [119](#)
 tri-state clocks, [79](#)
 tri-stating in DDR3 Eyefinder eyes, [110](#)
 troubleshooting DDR3 Eyefinder
 problems, [110](#)
 tuning DDR DUT for best
 measurements, [35](#)

U

ultra fine scan resolution, [100](#)
 Unit Interval delays, [102](#)

V

valid commands, triggering on, [121](#)
 validating the DDR setup, [117](#)

W

W2631A/B DDR2 BGA x16 probe, [27](#)
 W2632A DDR2 BGA x16 probe, [27](#)
 W2633A/B DDR2 BGA x8 probe, [27](#)
 W2634A DDR2 BGA x8 probe, [27](#)
 W2637A LPDDR BGA x16 probe, [31](#)
 W2638A LPDDR BGA x32 probe, [31](#)
 W3301A, [30](#)
 W3631A DDR3 BGA x16 probe, [25](#)
 W3633A DDR3 BGA x8 probe, [24](#)
 W4631A, [14](#)
 W4633A, [15](#)
 W4636A, [15](#)
 W4641A, [16](#)
 W4643A, [16](#)
 W6601A, [29](#)
 W6602A, [29](#)
 Waveform window, [7](#)
 write offset, [60](#)